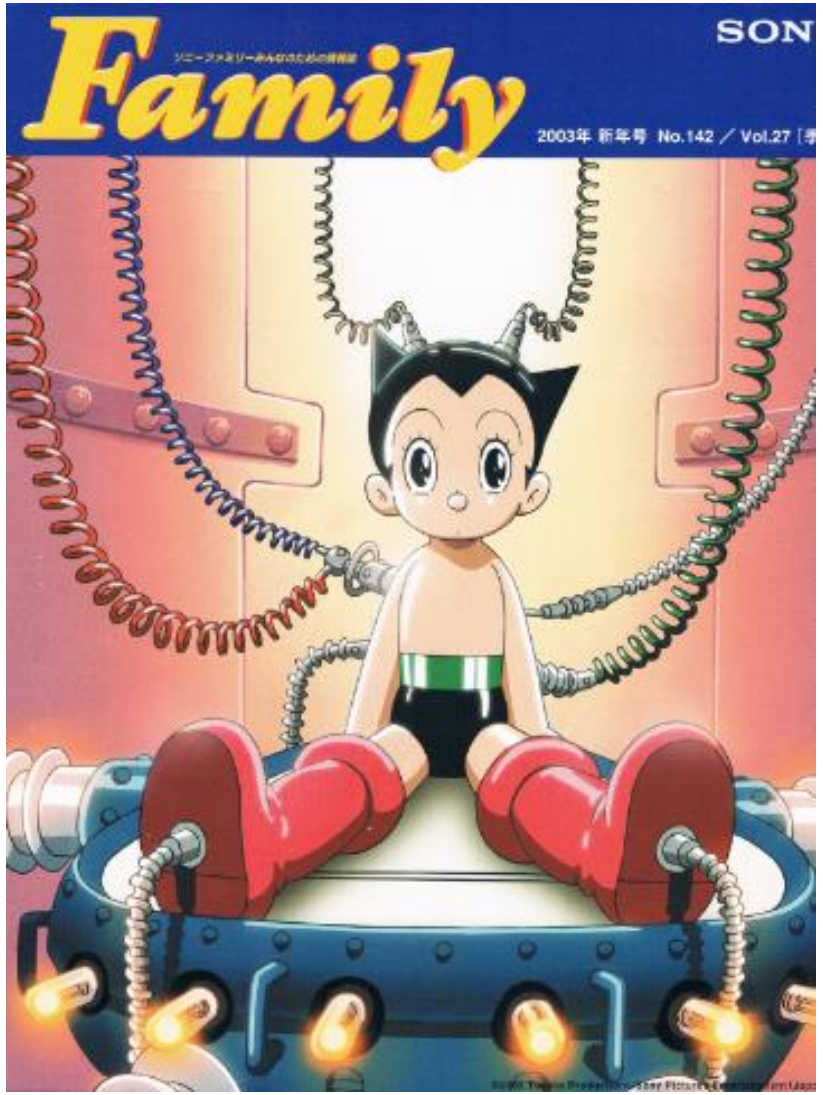
9 Artificial Intelligent Image Sensor

Under Construction

9 Artificial Intelligent Image Sensor

Hagiwara joined Sony in 1975 to work for his dream of building an artificial intelligent (AI) robot system with the smart and real time vision system.

The front page of the Sony Family Journal of January 2003 issue No.142 / Vol 17 shows the Atom Boy.

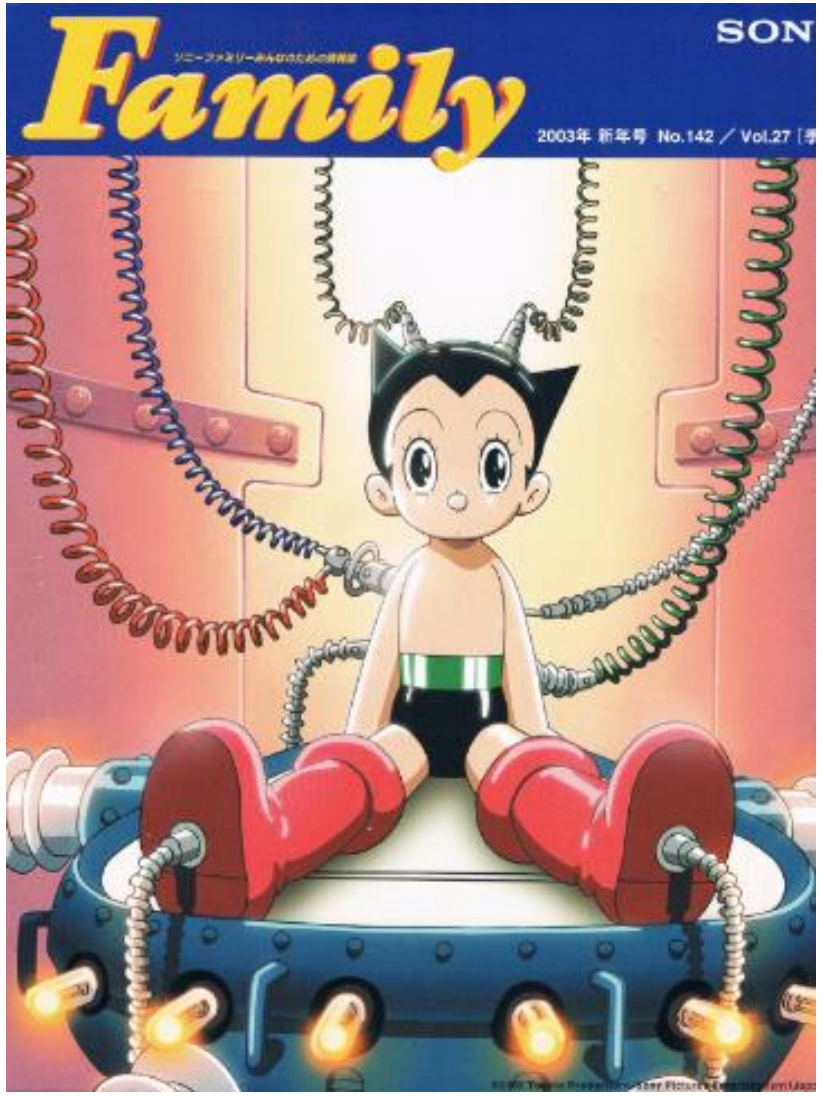


9 Artificial Intelligent Image Sensor

Hagiwara worked on CCD image sensors from 1975 till 1980. Then Hagiwara started building the digital CCD camera system.

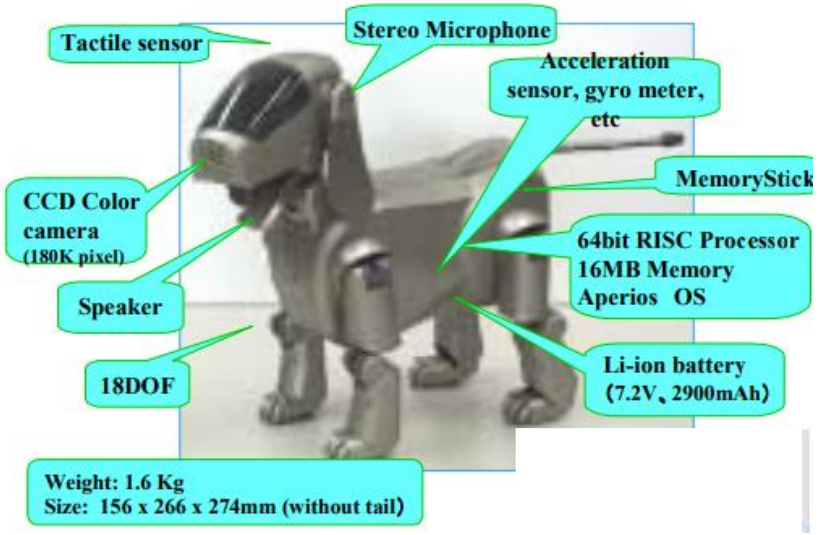
Hagiwara team in Sony in 1989 built the 25 nano sec access time 8 M bit Cache SRAM for fast image data acquisition from CCD image sensor signal output and reported the results at ISSCC1989

Then Hagiwara started working on the micro controller chips, SPC400 and SPC800 series for the Sony consumer products.



9 Artificial Intelligent Image Sensor

In 2001 Hagiwara was invited in the International Conference ESSCIRC2001 in Vilach, Austria to talk about his dream on the entertainment consumer products including the AIBO robot system which was made possible with many important semiconductor components including the intelligent image sensor chip.



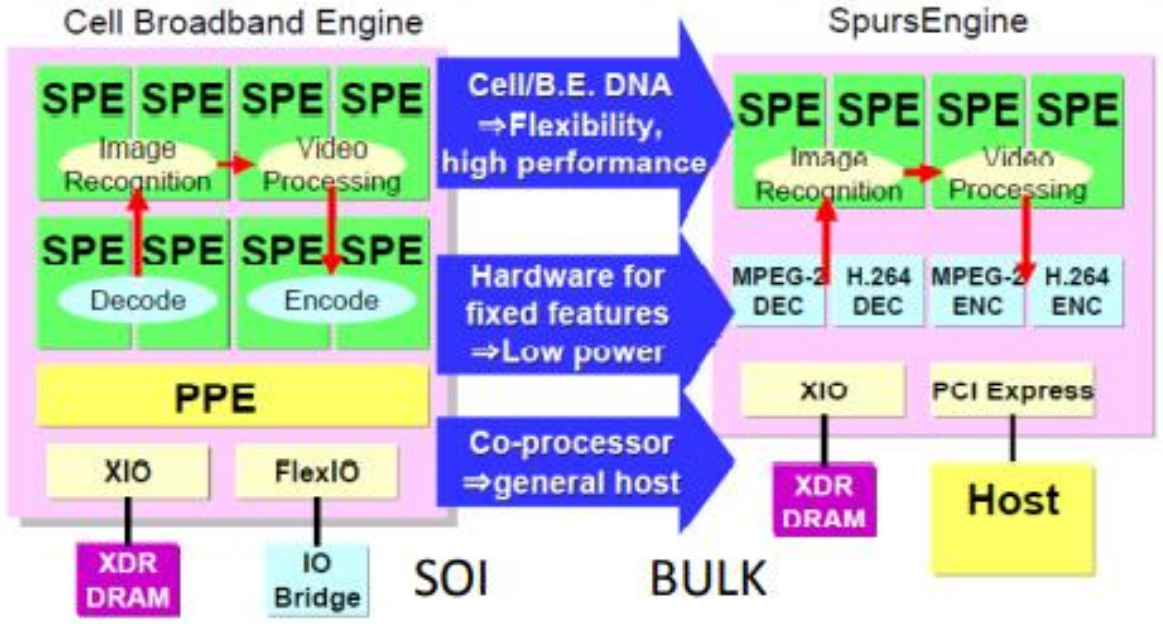
AIBO Model ERS-110

AIBO Model ERS-210

AIBO Model SDR-3

9 Artificial Intelligent Image Sensor

In 2008 Hagiwara was invited in the International Conference ESSCIRC2008 in Edinburgh, Scotland UK , to talk about his dream on the entertainment consumer products including the real time fast dedicated cell processor engines, the Cell / B. E . and Toshiba Spurs, for the PS3 game machine.

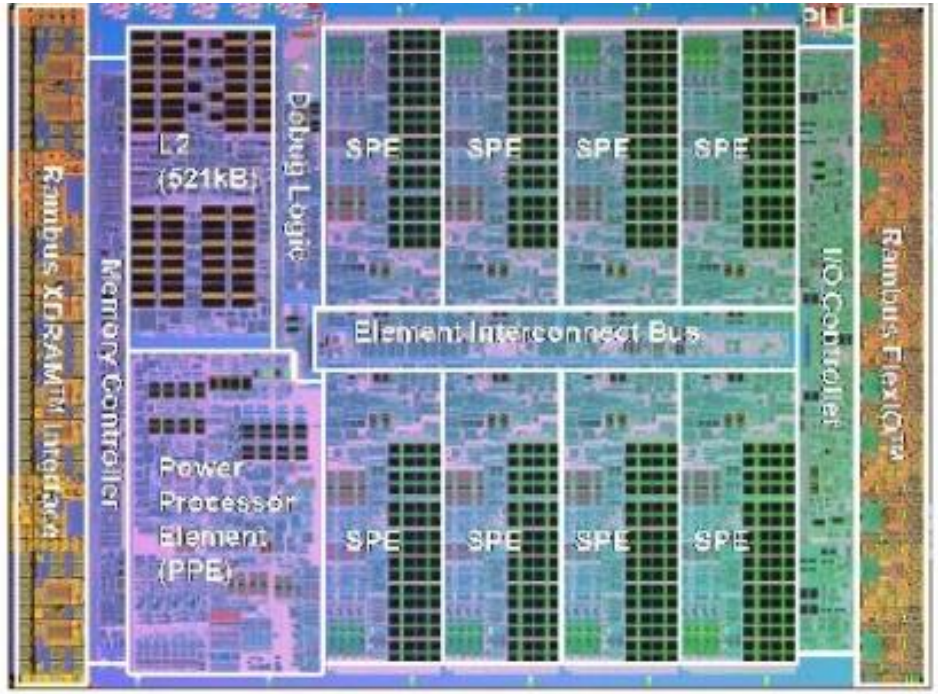


Sony/IBM/Toshiba Cell/B.E. and Toshiba Spurs Engine

Mitsuo Saito at ICD-ARC Panel, May 13, 2008

9 Artificial Intelligent Image Sensor

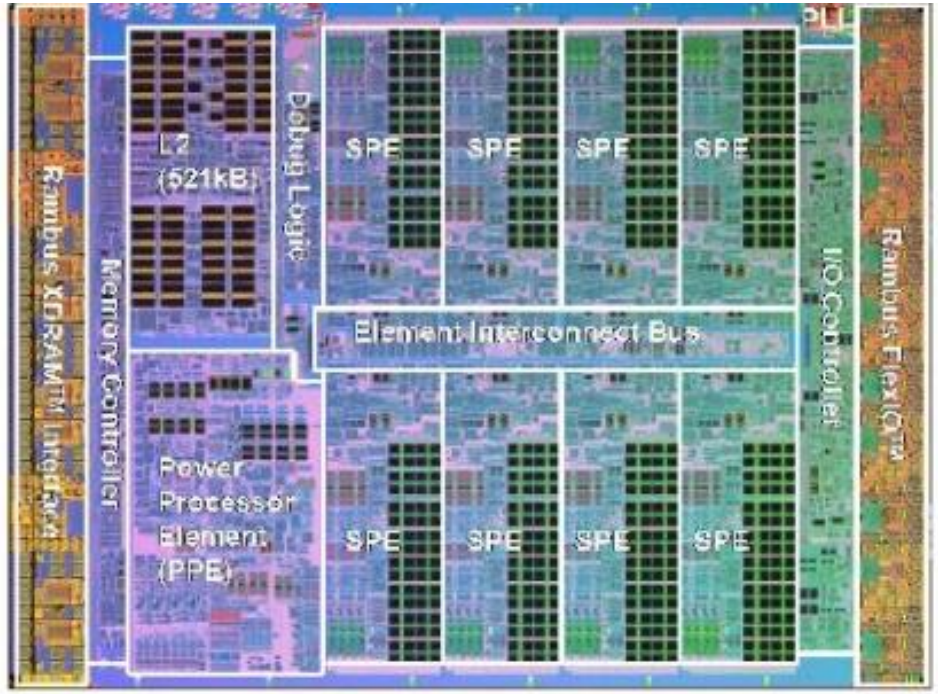
Software approach of Real Time Pattern Recognition is also one of the AISP efforts. However, to utilize real time software approach effectively, we need to design first a powerful hardware real time engine, which is much more powerful than Intel processors and Cell processors.



45 nm Cell/B.E. Die Photo by Osamu Takahashi, ISSCC2006

9 Artificial Intelligent Image Sensor

A powerful hardware real time engine needs first a very fast memory unit and a very powerful ALU unit in parallel architecture.



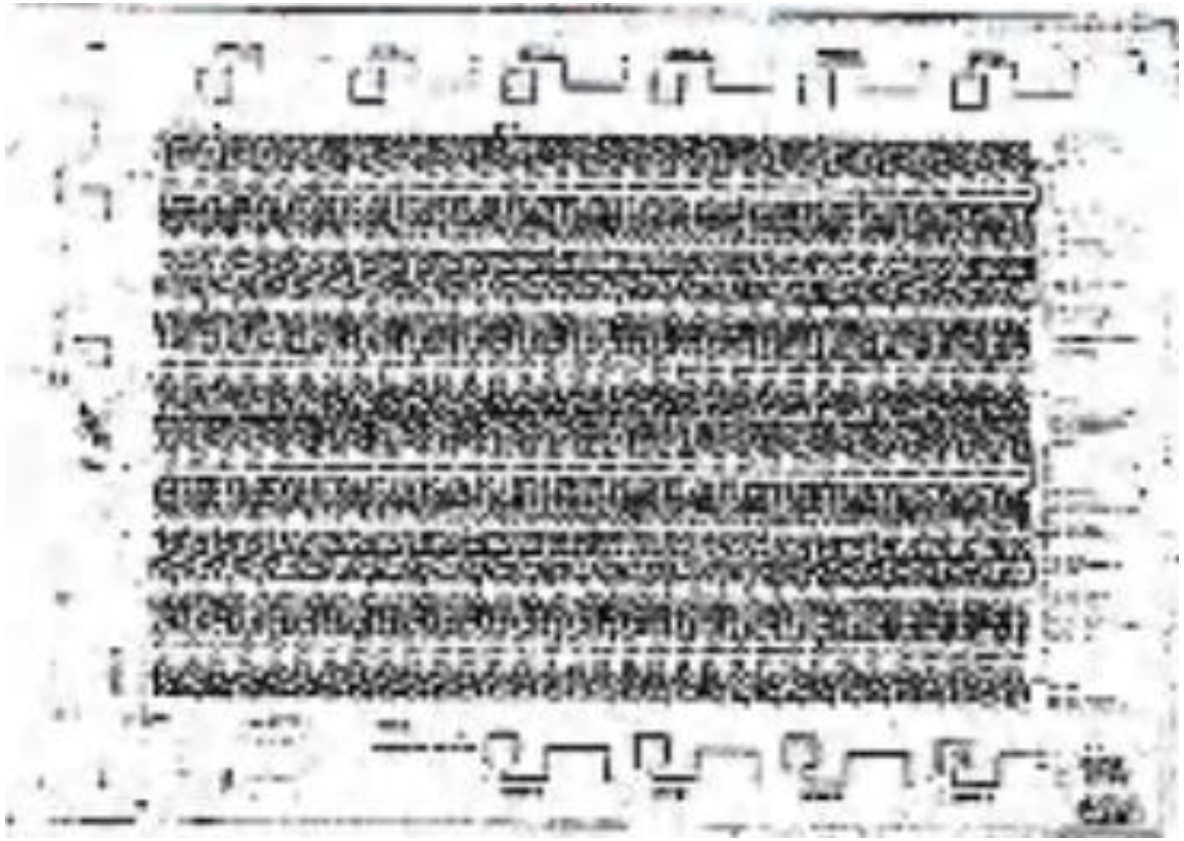
45 nm Cell/B.E. Die Photo by Osamu Takahashi, ISSCC2006

9 Artificial Intelligent Image Sensor

Artificial Intelligent Image Sensor needs a powerful hardware real time engine.

Prof. C. A. Mead and Yoshiaki Daimon Hagiwara
working on the silicon chip design at Caltech in 1972

128-bit Multicomparator chip, designed by Hagiwara
in 1972-1973 and fabricated by Intel PMOS process.

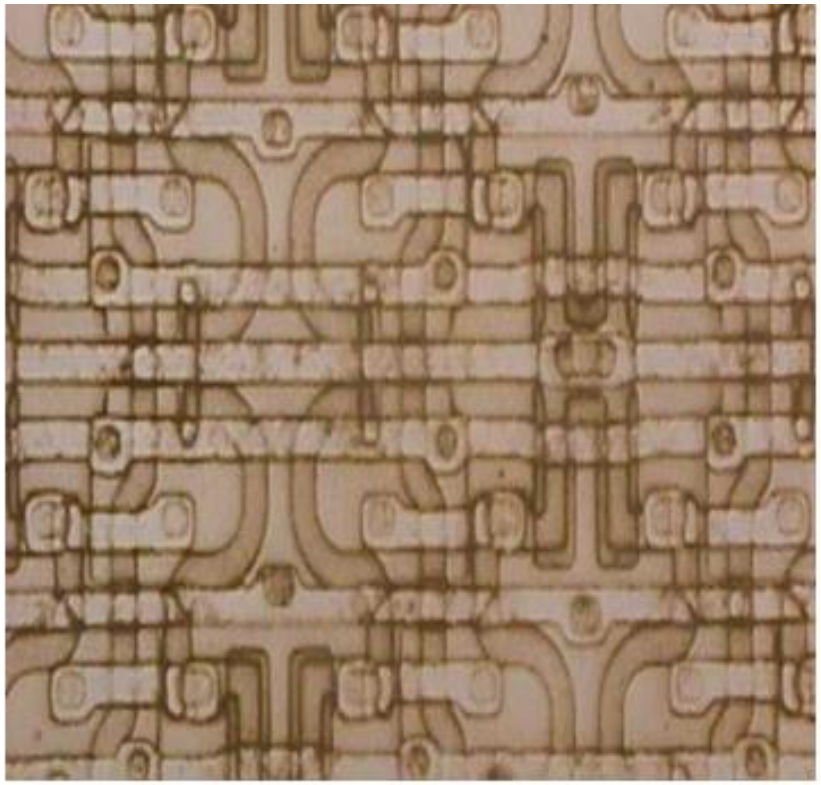


128 bit Multi Comparator Chip

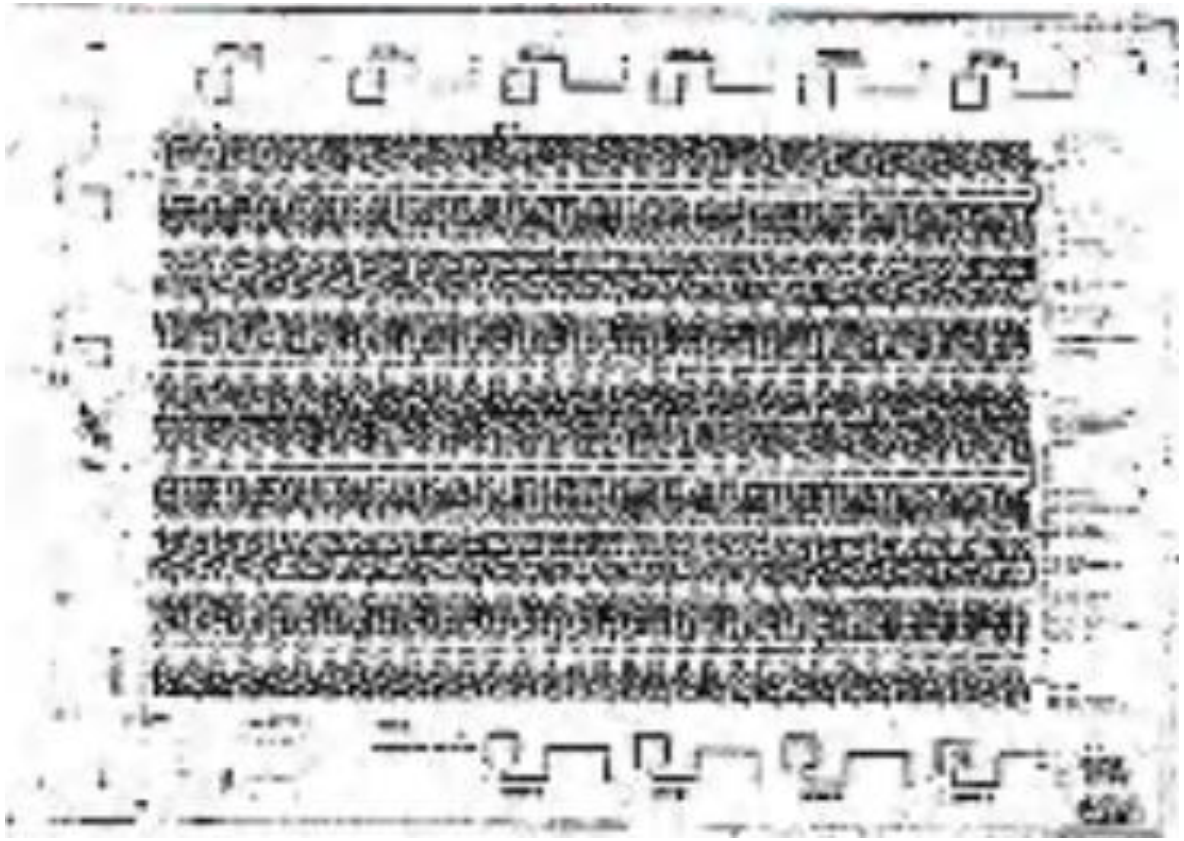
128 bit Multi Comparator Chip designed by Caltech Students and fabricated by Intel Ppocess.
IEEE Journal of Solid State Circuits, VOL.SC11, No.4, October 1976

9 Artificial Intelligent Image Sensor

Artificial Intelligent Image Sensor needs a powerful hardware real time engine.



1971 Intel 1101 256 bit DRAM chip

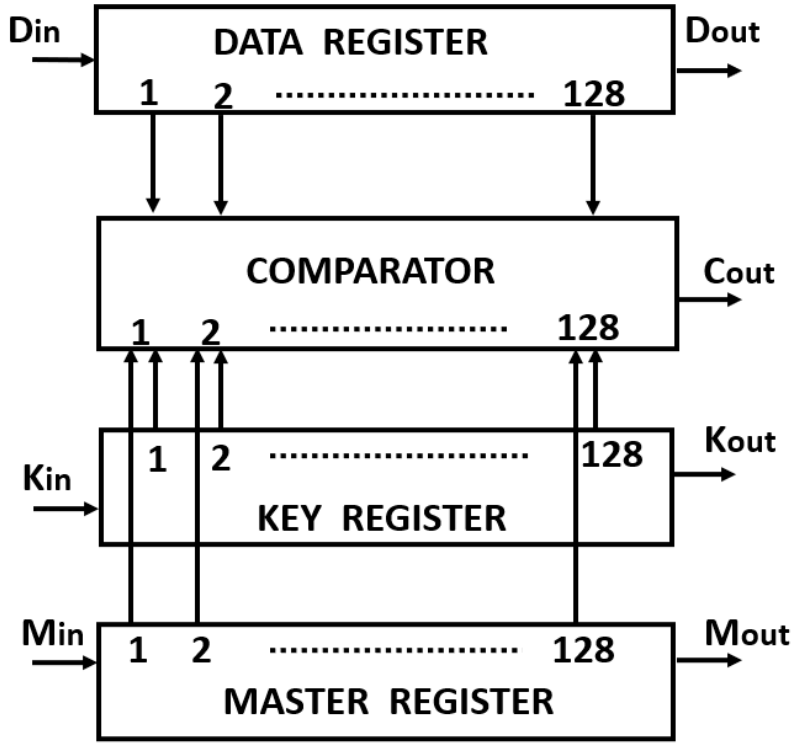


128 bit Multi Comparator Chip

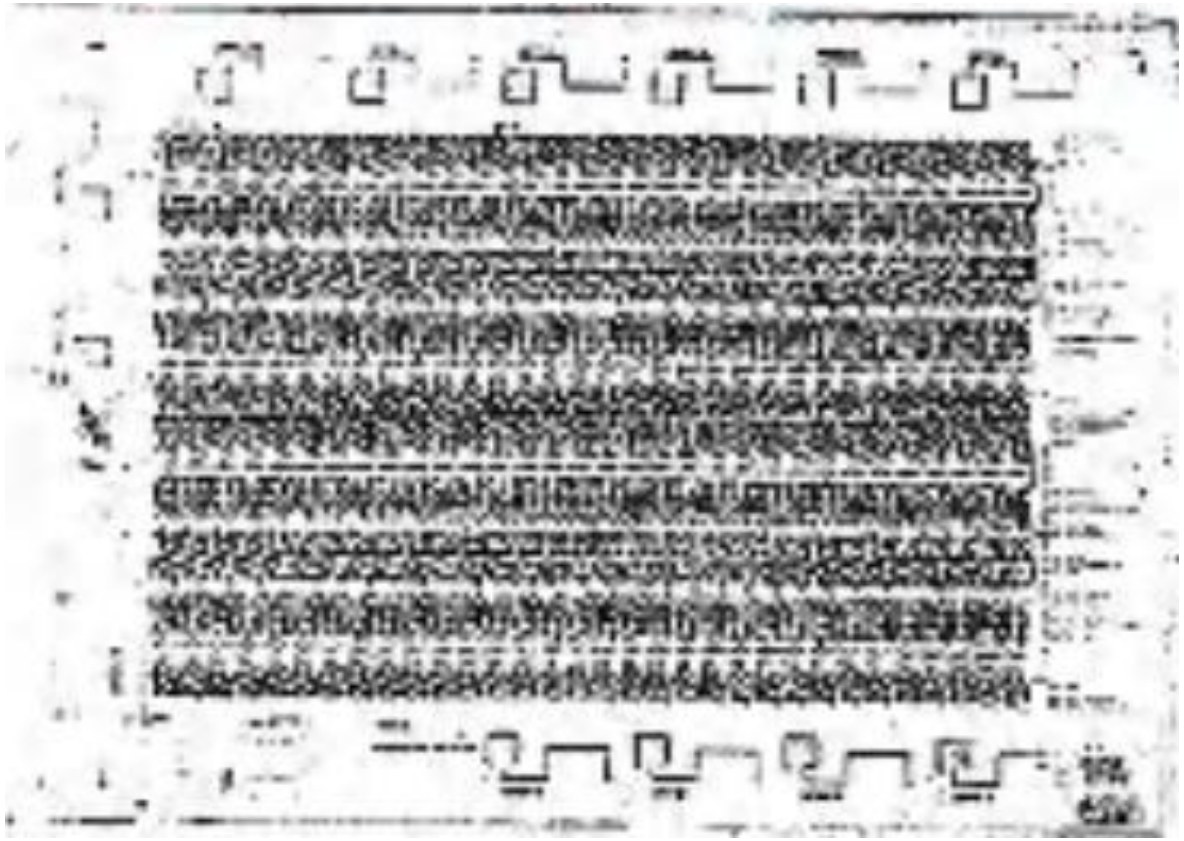
128 bit Multi Comparator Chip designed by Caltech Students and fabricated by Intel DRAM Process.
IEEE Journal of Solid State Circuits, VOL.SC11, No.4, October 1976

9 Artificial Intelligent Image Sensor

Artificial Intelligent Image Sensor needs a powerful hardware real time engine.



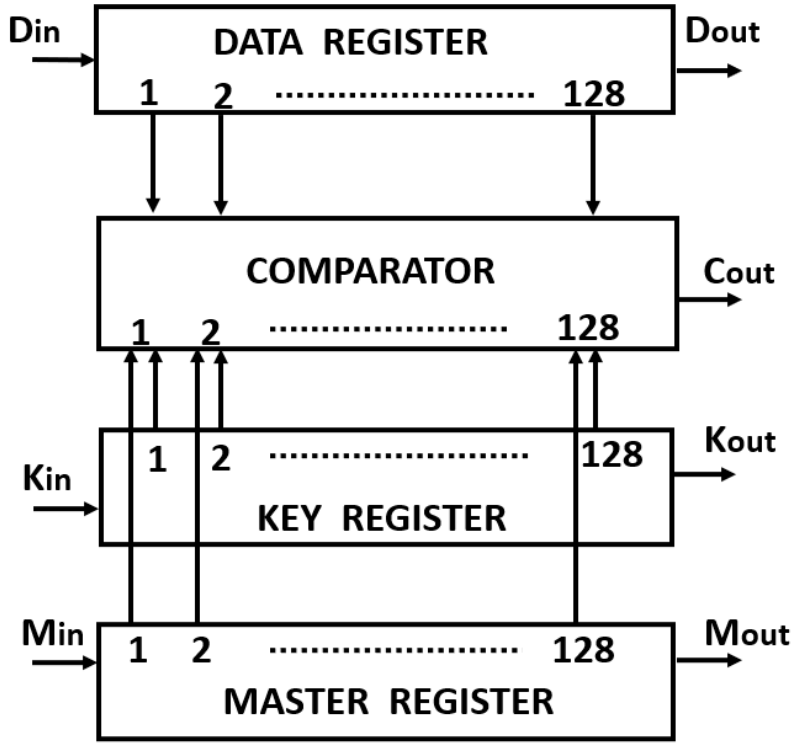
Block Diagram of 128 bit Multi Comparator



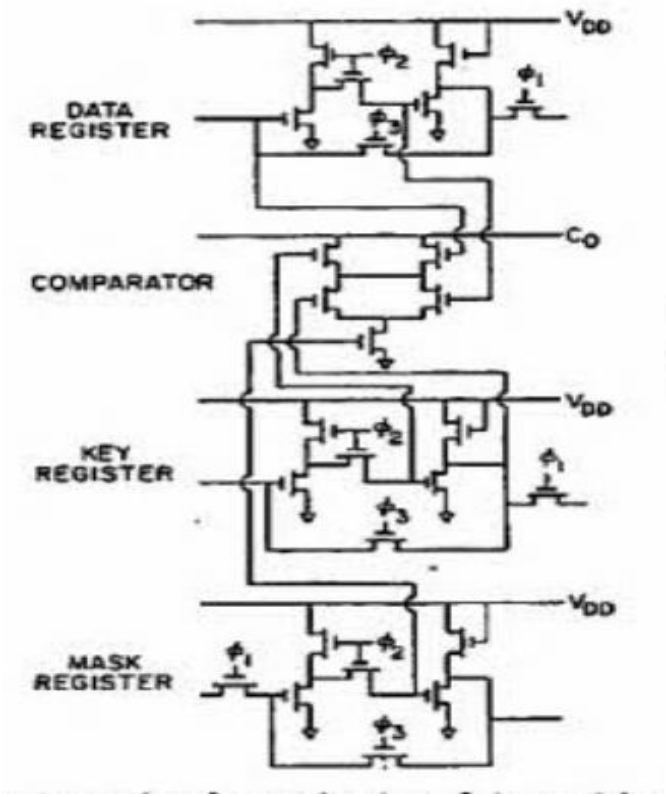
128-Bit Multicomparator Chip designed by Caltech Students and fabricated by Intel.
IEEE Journal of Solid State Circuits, VOL.SC11, No.4, October 1976

9 Artificial Intelligent Image Sensor

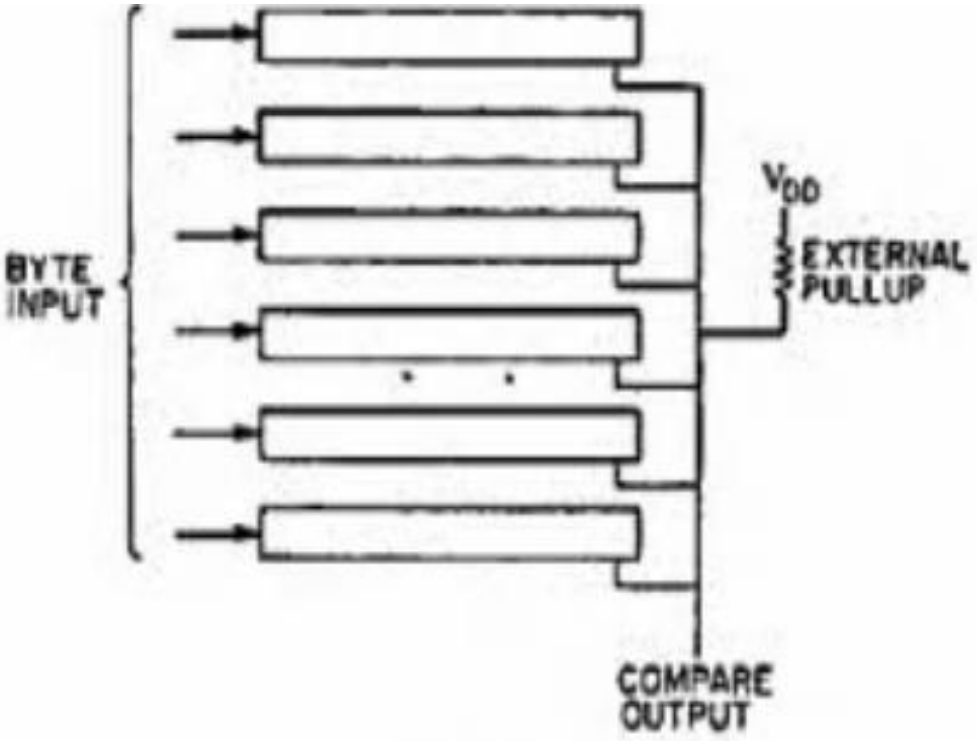
Artificial Intelligent Image Sensor needs a powerful hardware real time engine.



Block Diagram of 128 bit Multi Comparator



Full Schematic of One Bit Slice of the Multi Comparator

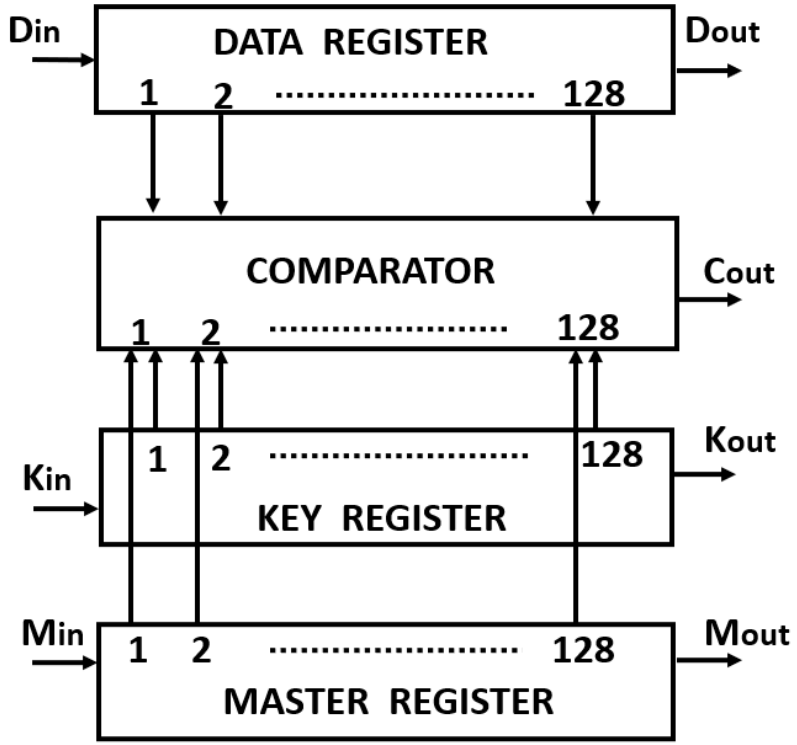


Bit Paralle, Word Serial Organization

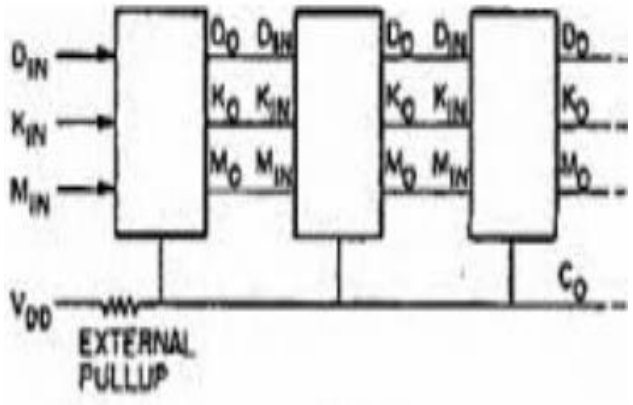
128-Bit Multicomparator Chip designed by Caltech Students and fabricated by Intel.
IEEE Journal of Solid State Circuits, VOL.SC11, No.4, October 1976

9 Artificial Intelligent Image Sensor

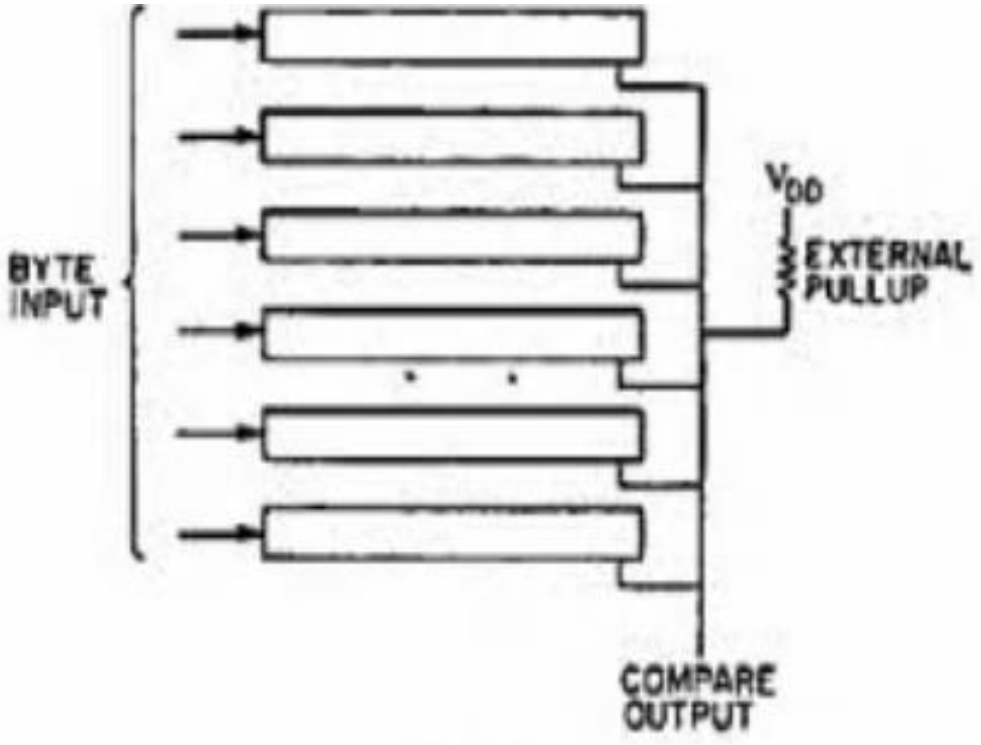
Artificial Intelligent Image Sensor needs a powerful hardware real time engine.



Block Diagram of 128 bit Multi Comparator



Cascaded Organization

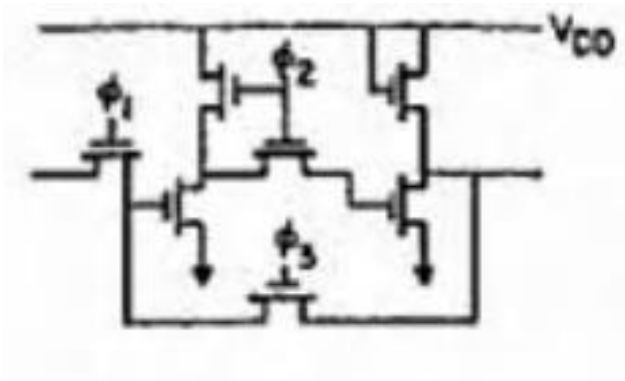


Bit Paralle, Word Serial Organization

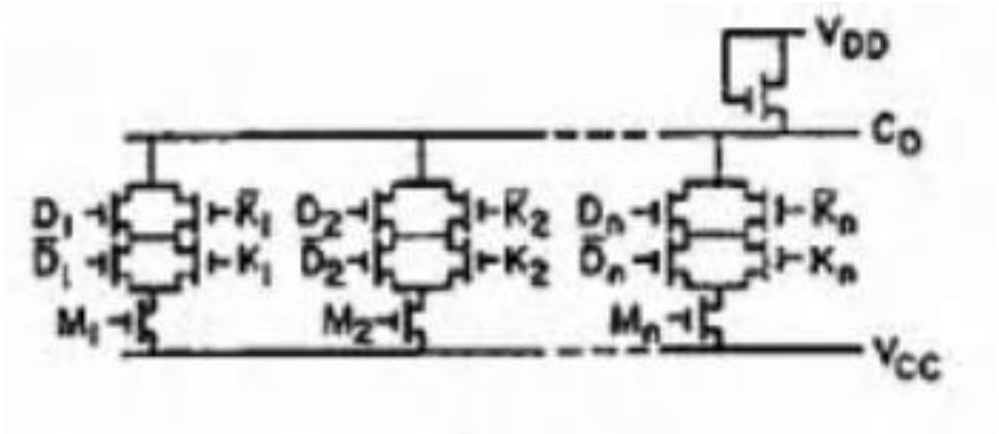
128-Bit Multicomparator Chip designed by Caltech Students and fabricated by Intel.
IEEE Journal of Solid State Circuits, VOL.SC11, No.4, October 1976

9 Artificial Intelligent Image Sensor

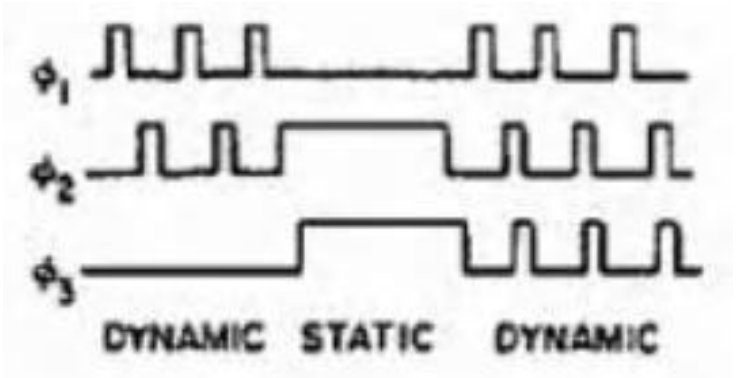
Artificial Intelligent Image Sensor needs a powerful hardware real time engine.



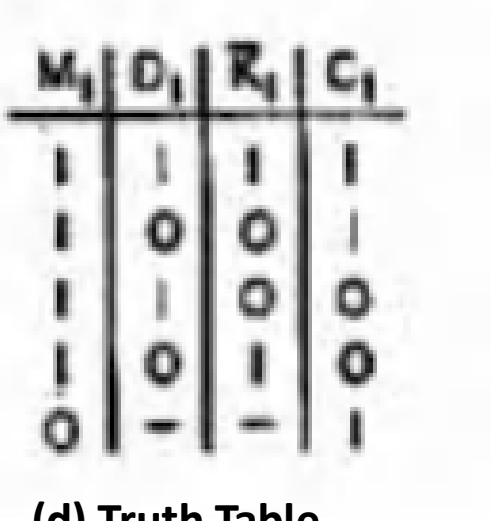
(a) Basic Shift Register



(b) Gated Exclusive Nor Gate

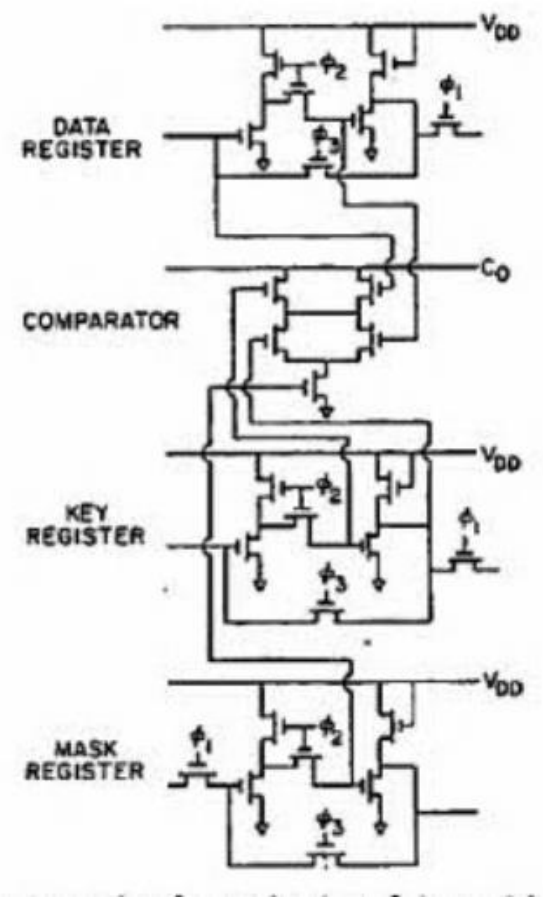


(c) Clock Timing



M_1	D_1	R_1	C_1
1	1	1	1
1	0	0	1
1	1	0	0
1	0	1	0
0	–	–	1

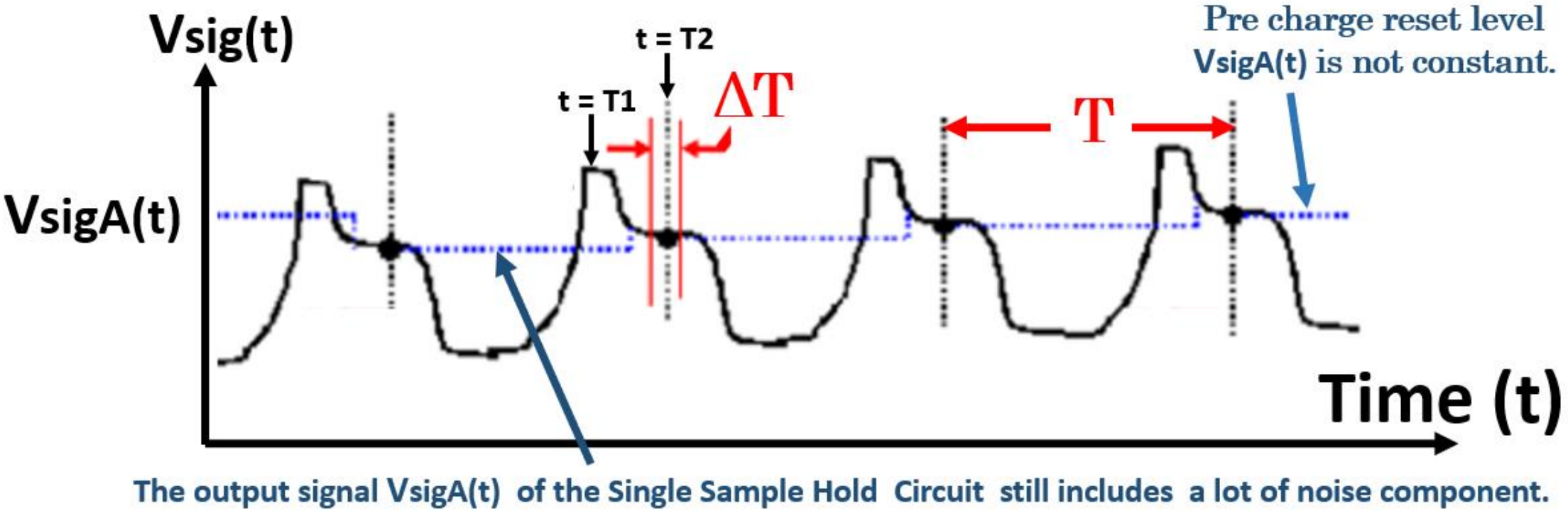
(d) Truth Table



Full Schematic of One Bit Slice of the Multi Comparator

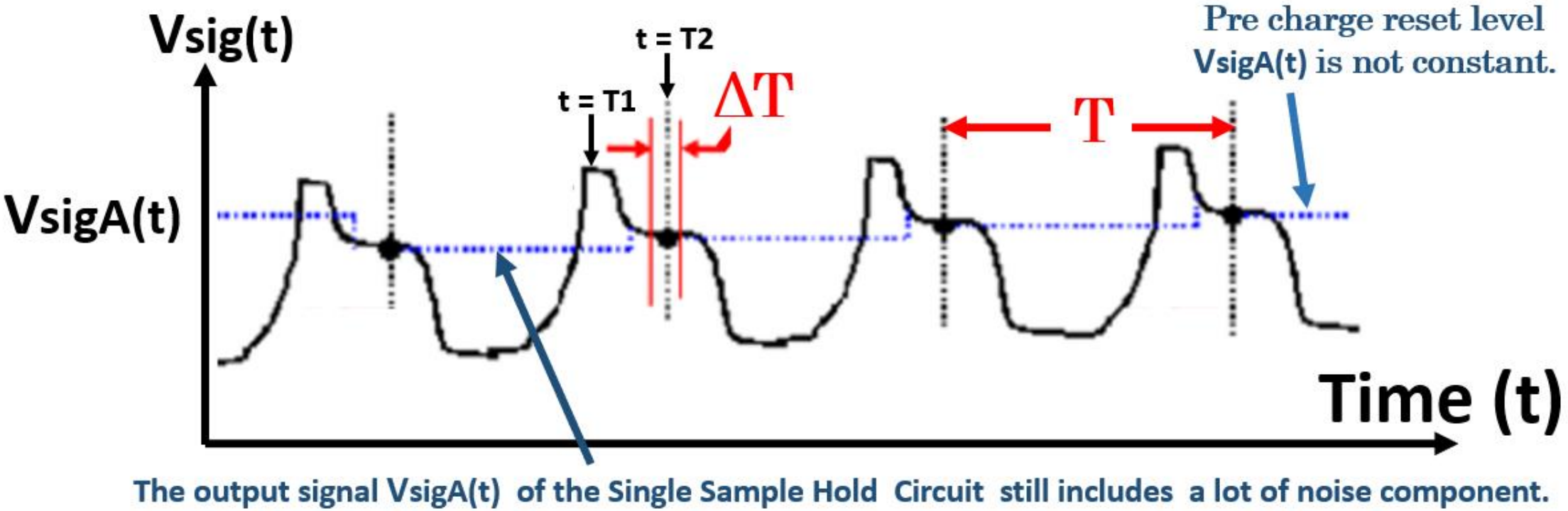
9 Artificial Intelligent Image Sensor

The output signal of an image sensor is buried in many kinds of noises and appears only in a short time slot ΔT during the total cycle time T.



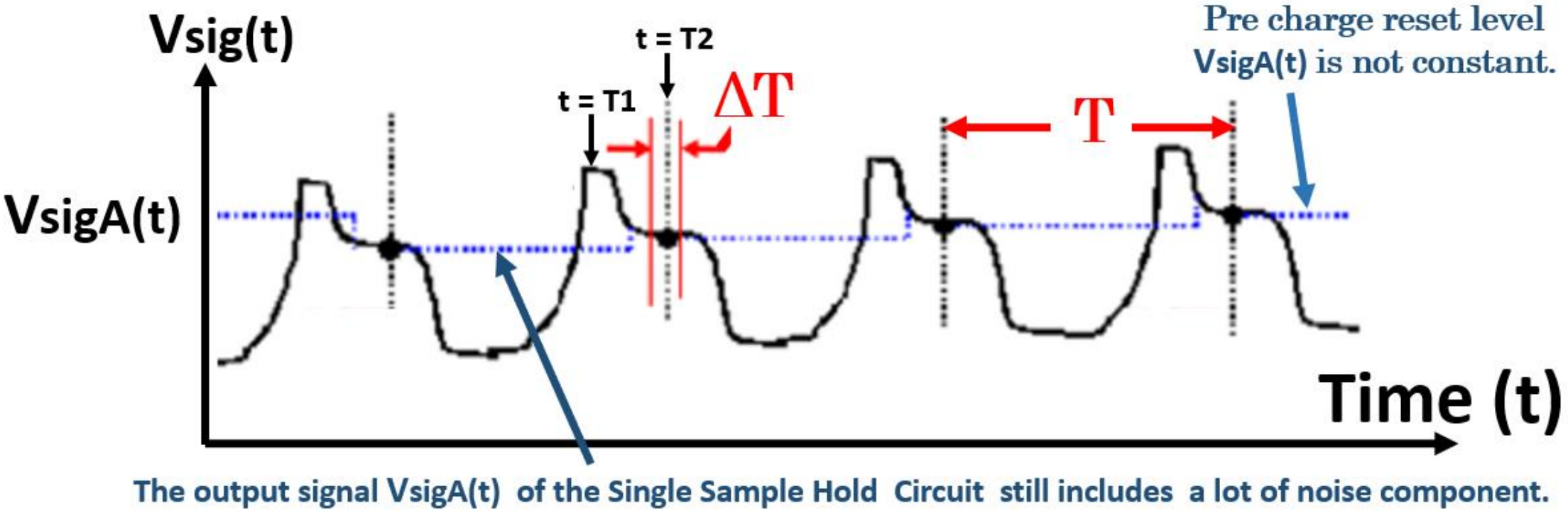
9 Artificial Intelligent Image Sensor

Our task is extracting the important information needed for us from the image sensor output signal which has many kinds of noise.



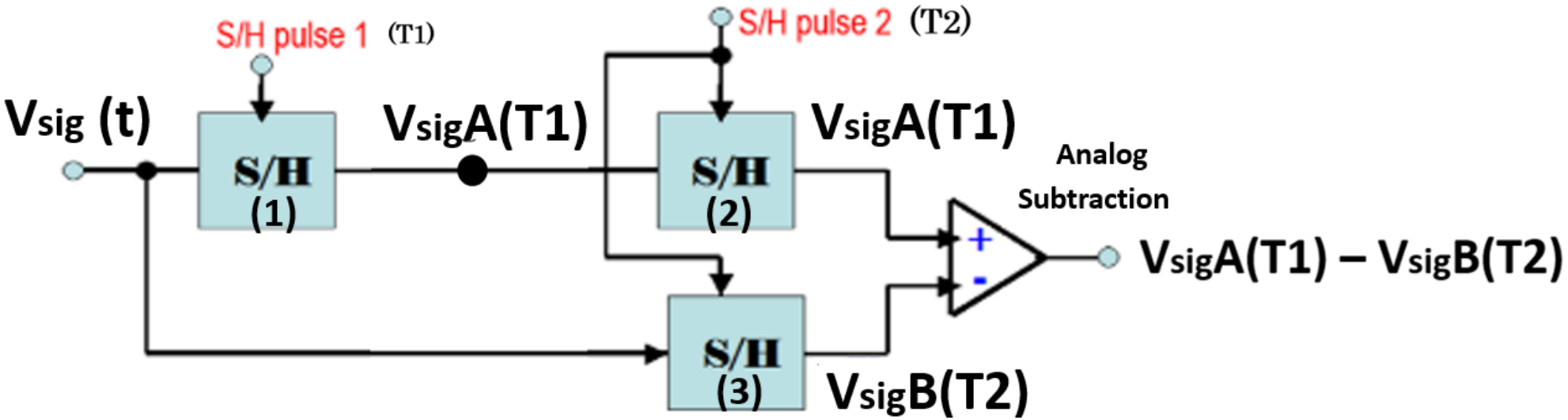
9 Artificial Intelligent Image Sensor

The effort of extracting the important information needed for us is by definition the artificial intelligent signal processing (AISP).



9 Artificial Intelligent Image Sensor

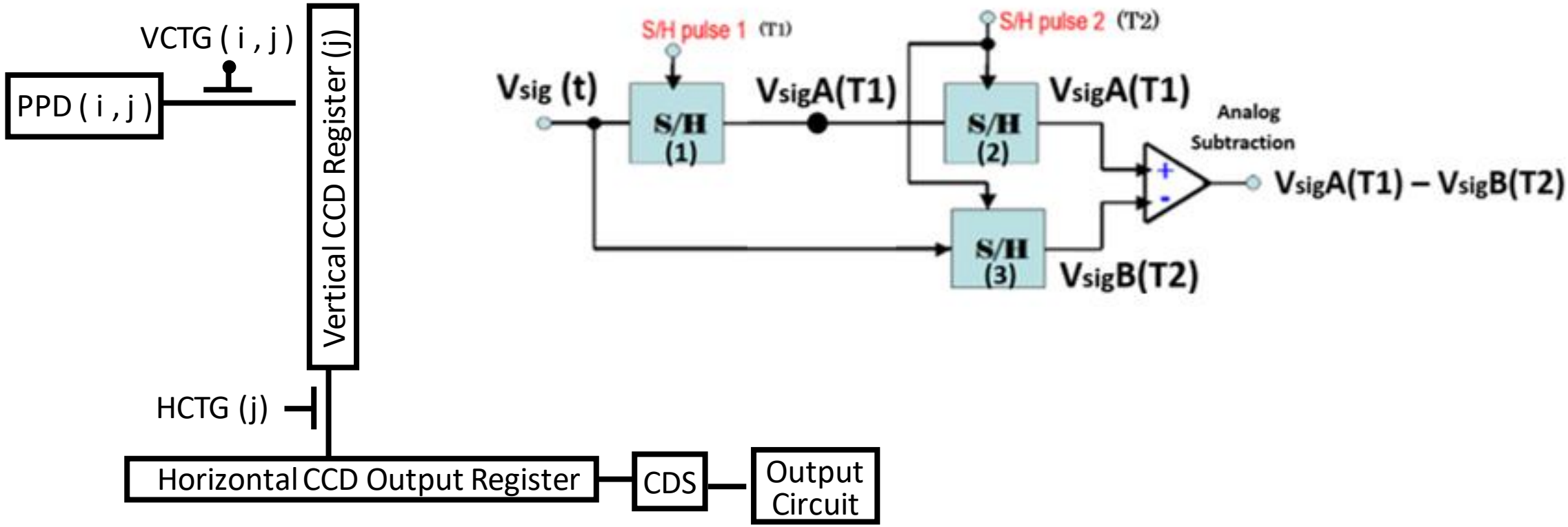
In 1972, M. White proposed Correlated Double Sample (CDS) circuit which has three sample hold circuits and one analog subtraction circuit to delete the undesired noise components of the output signal of CCD image sensors.



M .H. White, D. R. Lanpe, F. C. Blaha and I. A . Mack,
"Characterization of surface Channel CCD Image Arrays at Low Light Level",
IEEE Journal of Solid State Circuits, SC-9, pp.1-13 (1974)

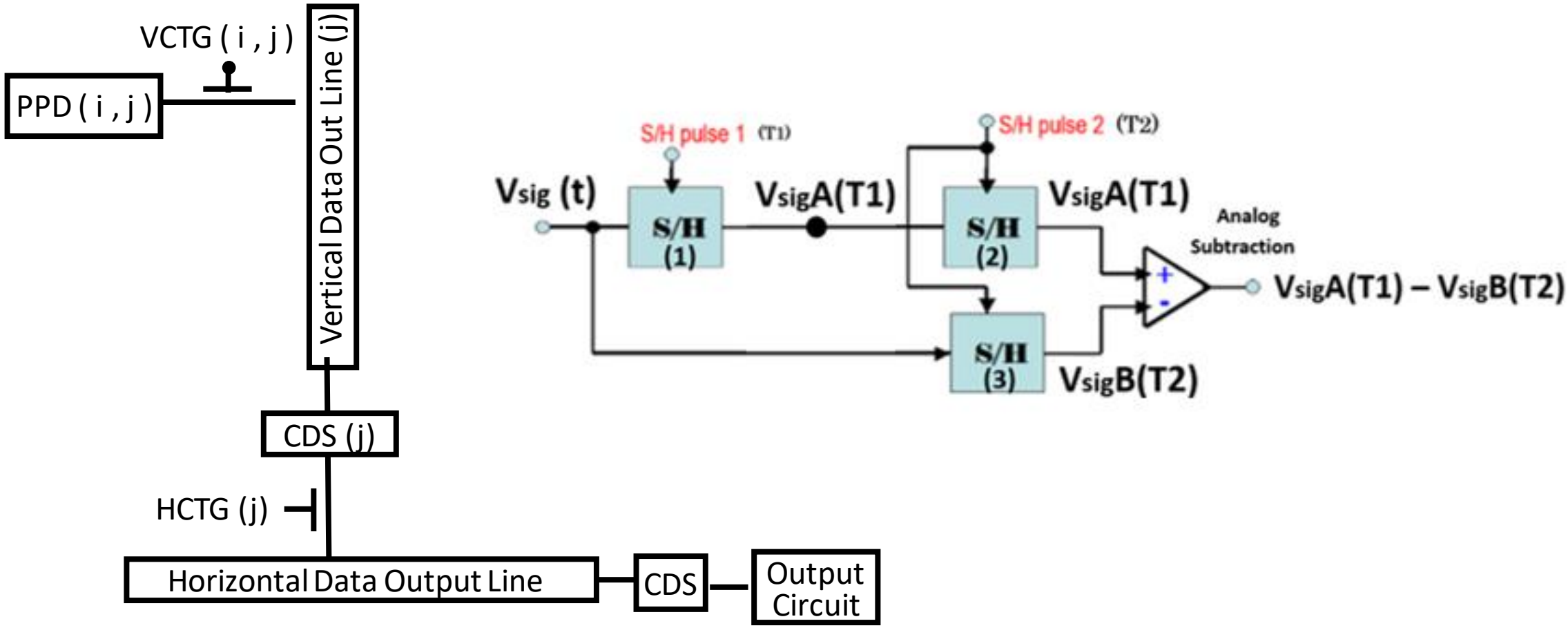
9 Artificial Intelligent Image Sensor

Only one CDS circuit was originally used in classical CCD image sensors.



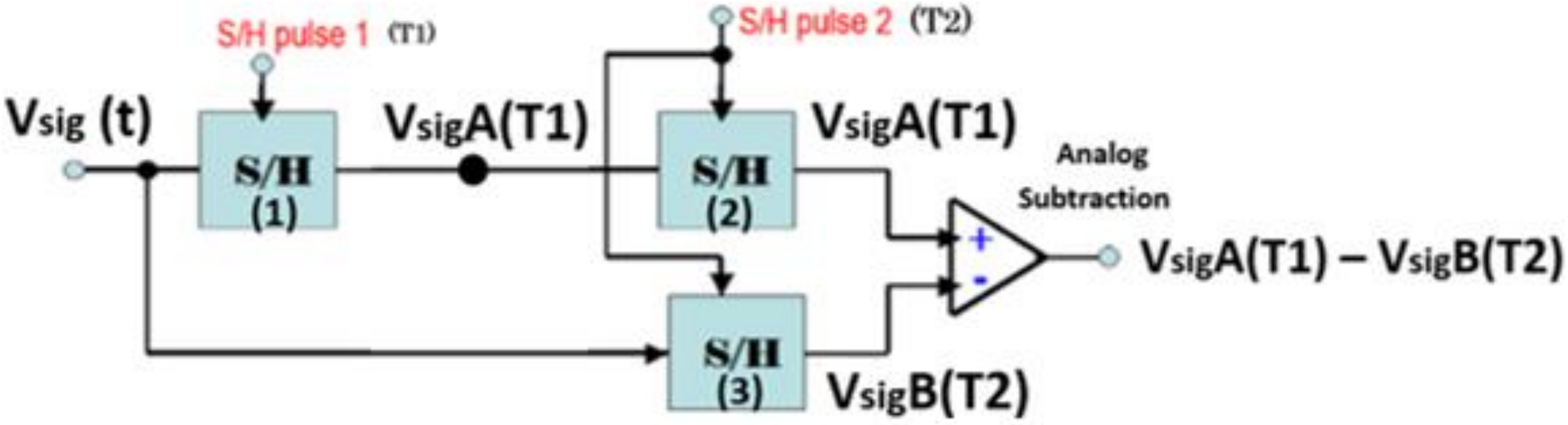
9 Artificial Intelligent Image Sensor

But now one CDS circuits was built in each column line.



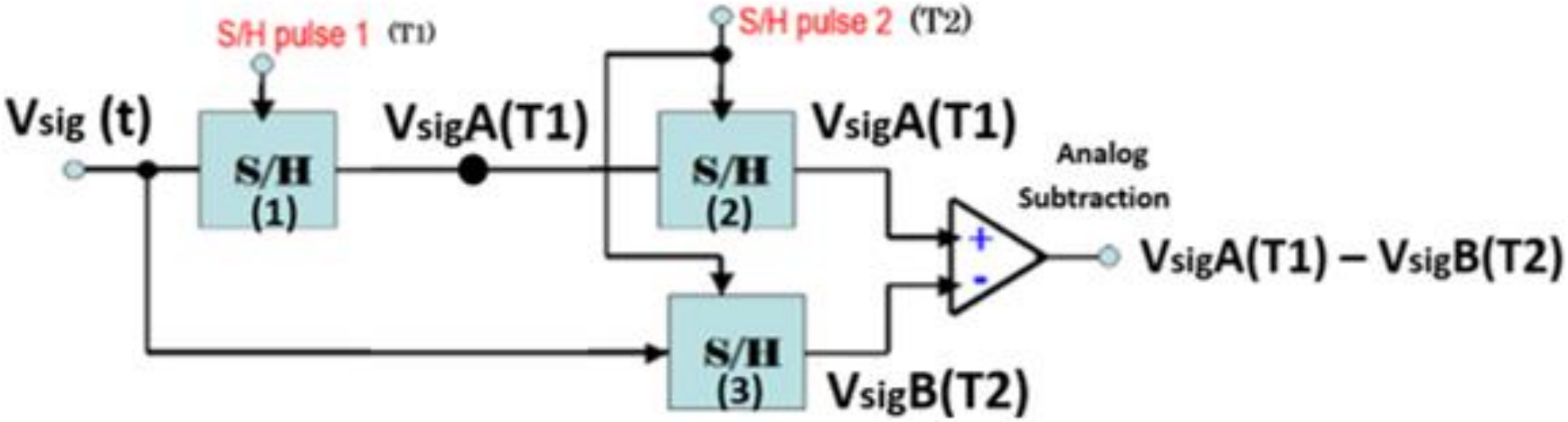
9 Artificial Intelligent Image Sensor

The correlated double sample (CDS) circuit needs a powerful hardware engine to perform analog signal subtraction function which must be implemented by a well balanced and carefully designed differential amplifier circuit built with the CMOS process technology.



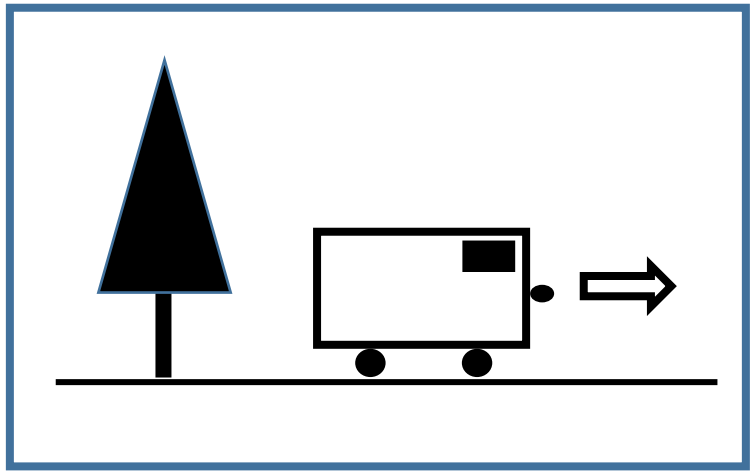
9 Artificial Intelligent Image Sensor

The intelligent circuit design of the correlated double sampling hold (CDS) is also one of the AISP efforts.

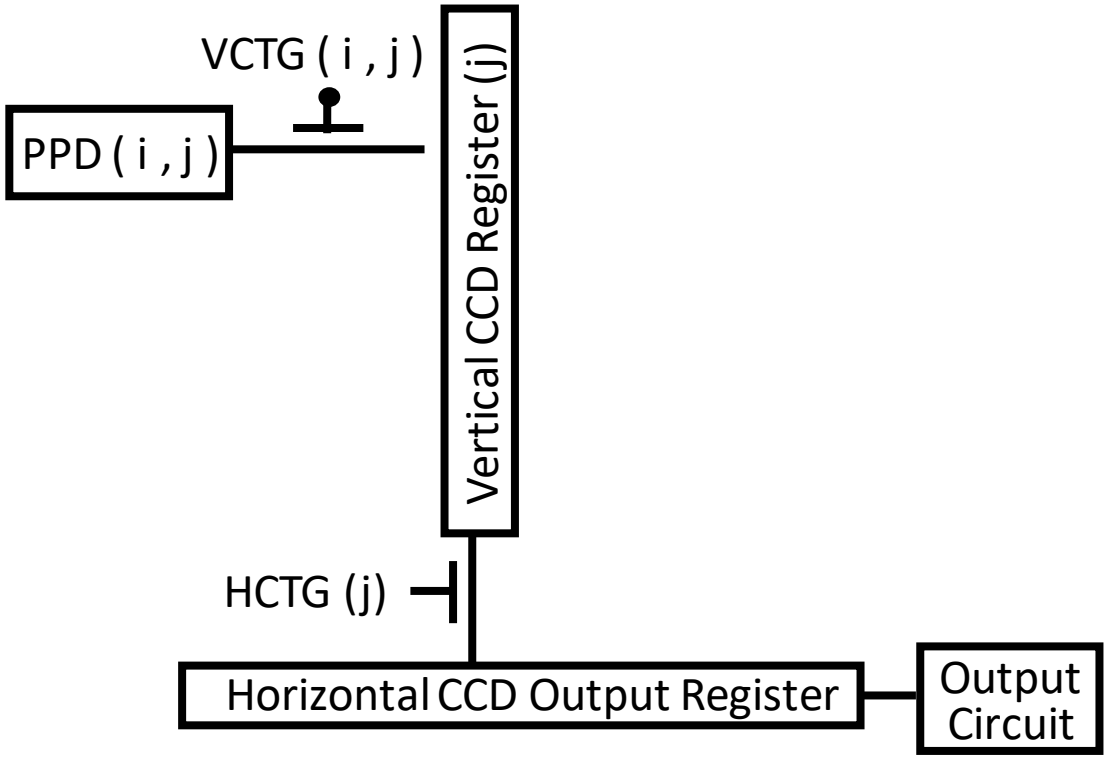


9 Artificial Intelligent Image Sensor

The CCD image sensors with the CCD type CTD was built with the vertical and horizontal CCD type analog shift registers which are made of many CCD/MOS memory capacitors acting also as the in pixel Global Shutter Buffer Memory (GSBM).

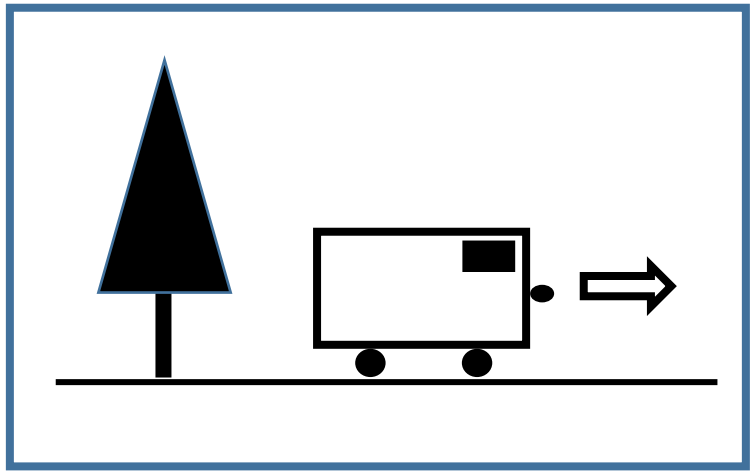


the CCD image sensors with the Built in Global Shutter Function

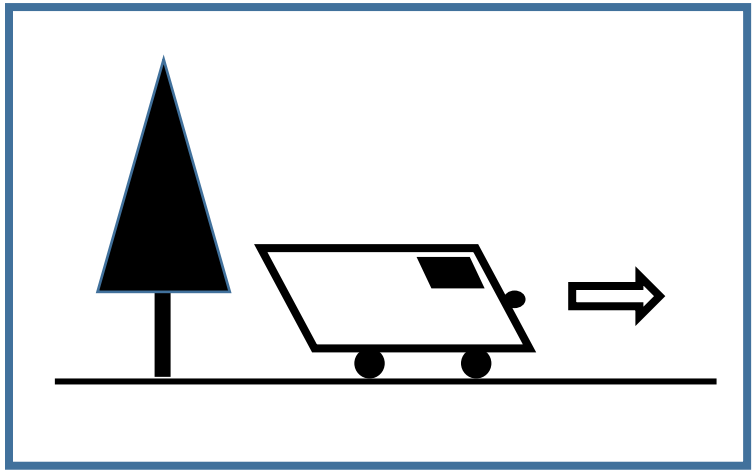


9 Artificial Intelligent Image Sensor

However, the classical CMOS image sensors used the CMOS type charge transfer device (CTD) which had a problem of image distortion in moving objects by the rotary shutter effect.



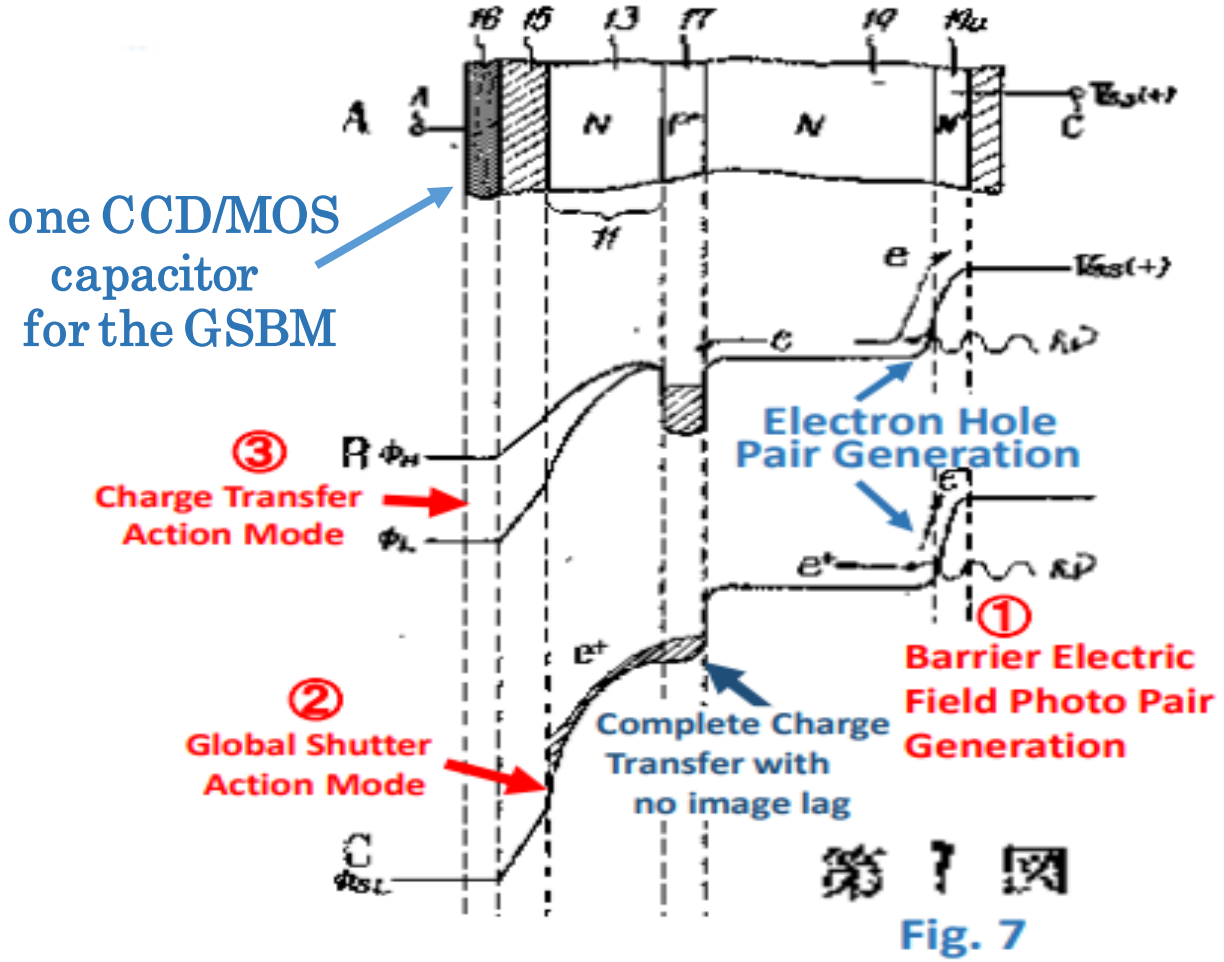
the CCD image sensors with the Built in Global Shutter Function



the classical CMOS image sensors with rotary shutter effect

9 Artificial Intelligent Image Sensor

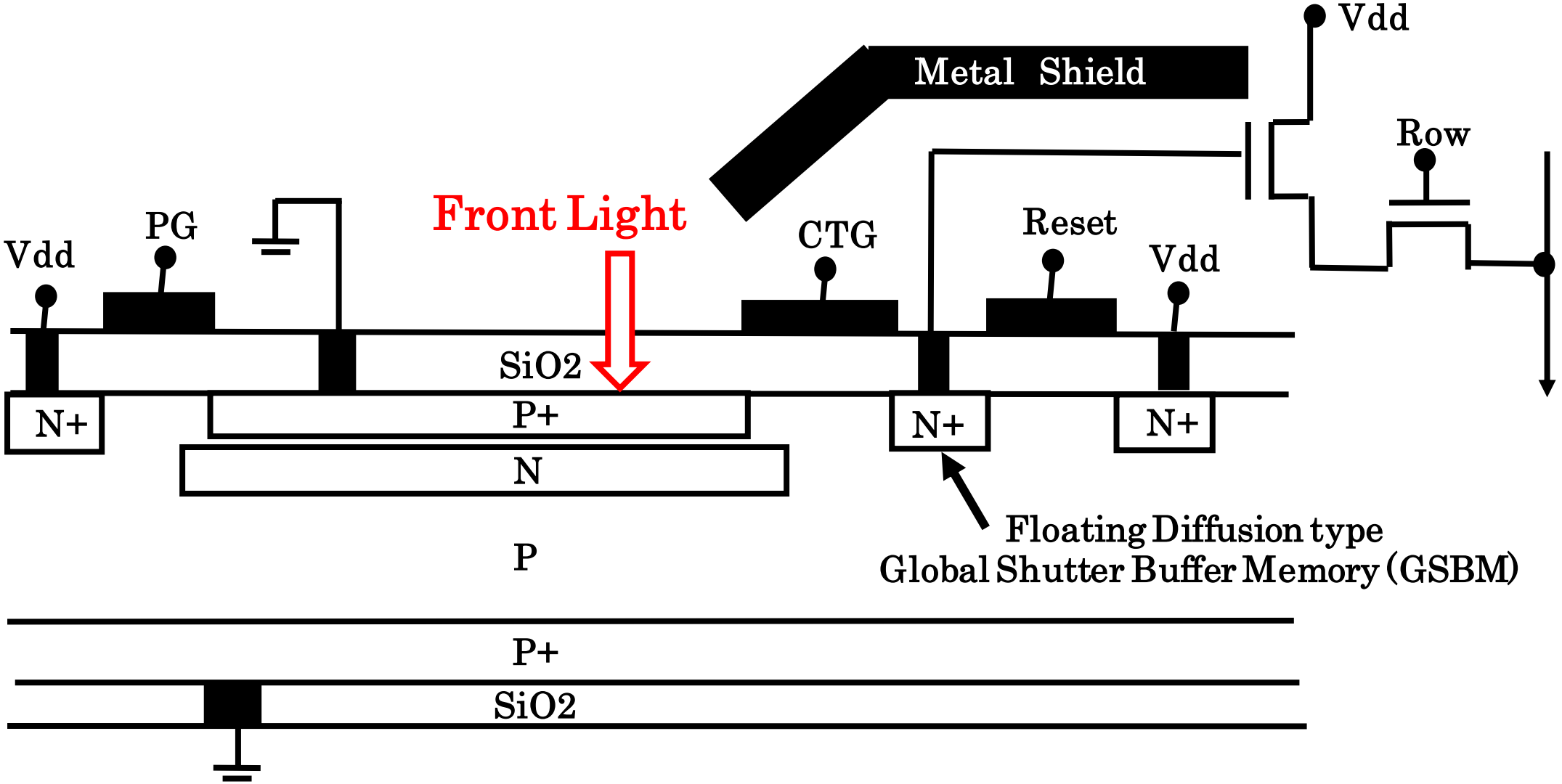
The in pixel Global Shutter Buffer Memory (GSBM) was needed absolutely in CMOS image sensors. Hinted by the CCD type CTD with the built in CCD/MOS capacitor type GSBM, Hagiwara in 1975 proposed to add one CCD/MOS capacitor type GSBM in each pixel with the three voltage level CTG operation scheme.



Yoshiaki. Hagiwara, Japanese Patent Applications JPA 1975-127647, JPA 1975-127647 and JPA 1975-134985.

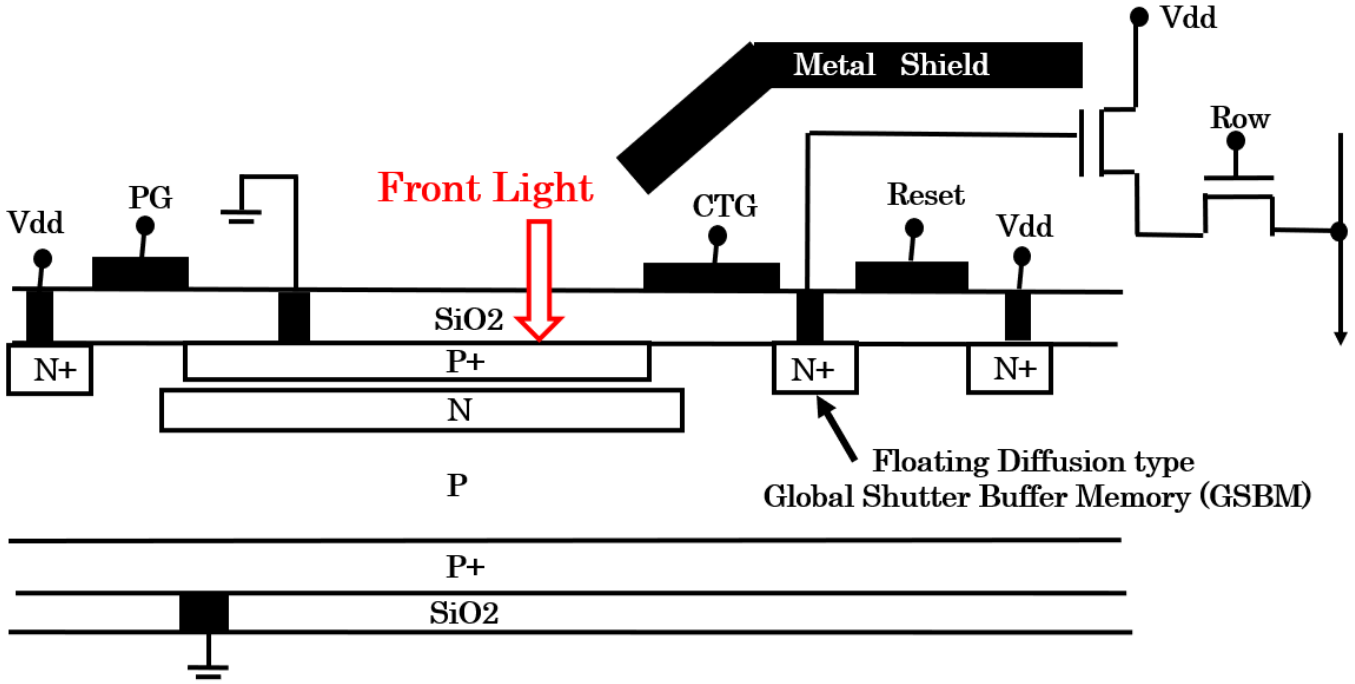
9 Artificial Intelligent Image Sensor

1T1C DRAM has the N+ floating source diffusion as the memory capacitor.



9 Artificial Intelligent Image Sensor

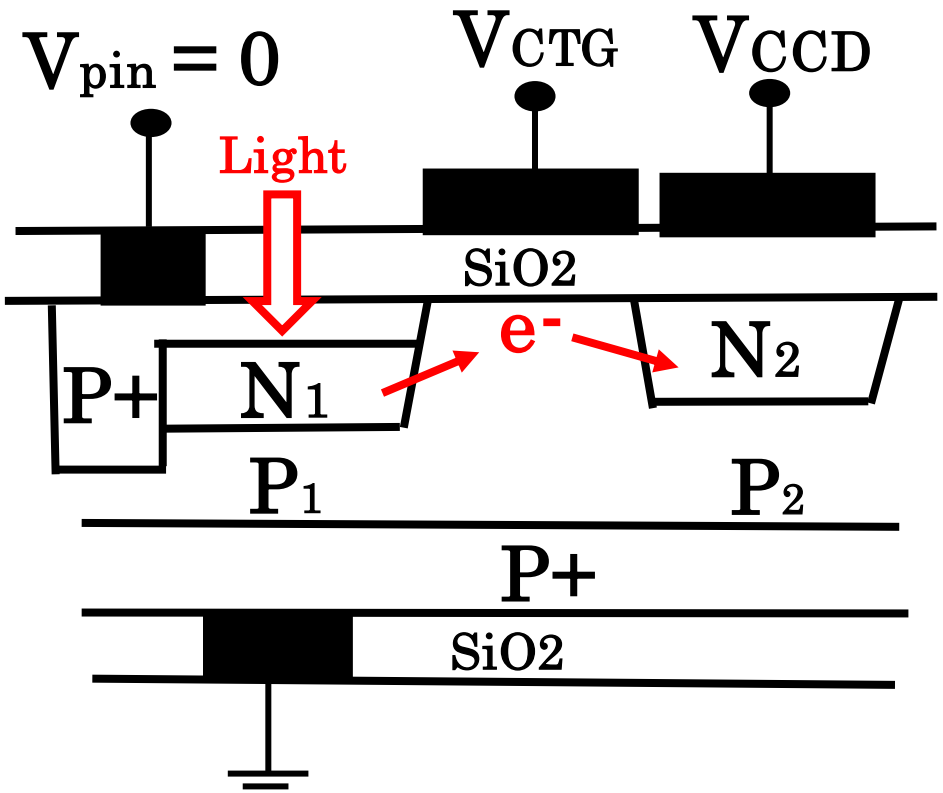
It is a natural choice to use also the floating diffusion for the GSBM for CMOS type CTD image sensors.



Guang Yang, Orly Yadid-Pecht, Chris Wrigley, and Bedabrata Pain,
"A Snap-Shot CMOS Active Pixel Imager for Low-Noise, High-speed Imaging",
Technical Journal of IEDM1998, 98-45, Dec 1998.

9 Artificial Intelligent Image Sensor

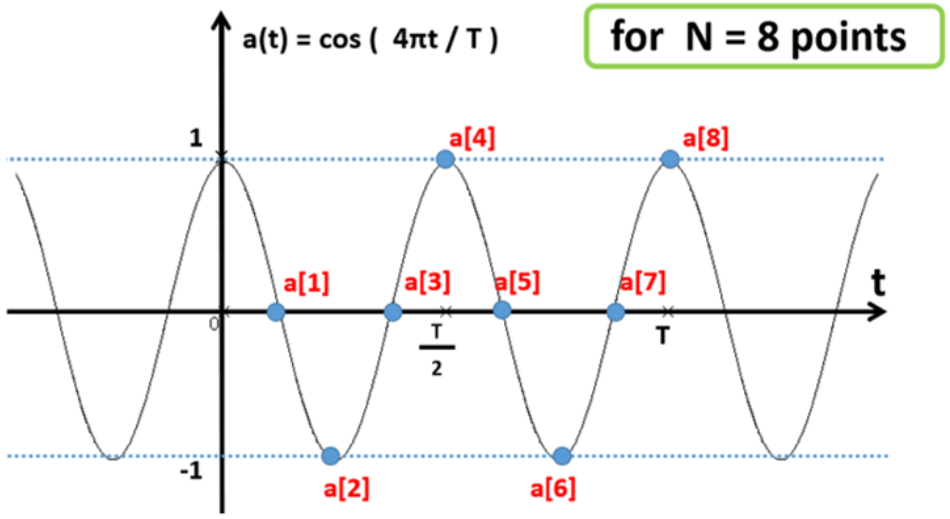
The intelligent device design of the Pinned Photodiode (PPD) with low noise and very excellent light sensitivity is one of the AISP efforts.



9 Artificial Intelligent Image Sensor

Artificial Intelligent Image Sensor needs many kinds of powerful hardware real time engines. Discrete Fourier Transformation (DFT) Engine is one of them which is essential for voice and picture recognition.

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme



Sampling Points are at t[k] = kT/8 for k=1 to 8 ;

a[ ] ={ a[1], a[2], ····· , a[8] }

A[ ] ={A[1], A[2], ····· , A[8] }

$$DFT[m][n] = \exp(-2\,m\,n\,\pi\,i / N)$$

for m = 1, 2, ····· N and n = 1, 2, ····· N.

$$i^2 = -1$$

$$A[\,] = DFT[\,][\,]a[\,]$$

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

Design and Performance Estimation of DFT Processing Circuits

Japanese Patent Application JPA 2014-135497

filed on July 1, 2014 by Yoshiaki Hagiwara.

"The digital circuit engine design to convert the time domain information to the frequency domain information"

Related published paper on July 4, 2014, Izumo city , Japan

Weikun Liang, Yuji Yoshida, Kishi Fukakusa, Yoshiaki Hagiwara,

"Design and Performance Estimation of DFT Processing Circuits"

Institute of Electrical Engineers of Japan (IEEJ),
Techinical Journel of IEEJ ICD ECT－14－060,
July 4, 2012, Izumo-city, Japan

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

Weikun Liang, Yuji Yoshida, Kishi Fukakusa, Yoshiaki Hagiwara,

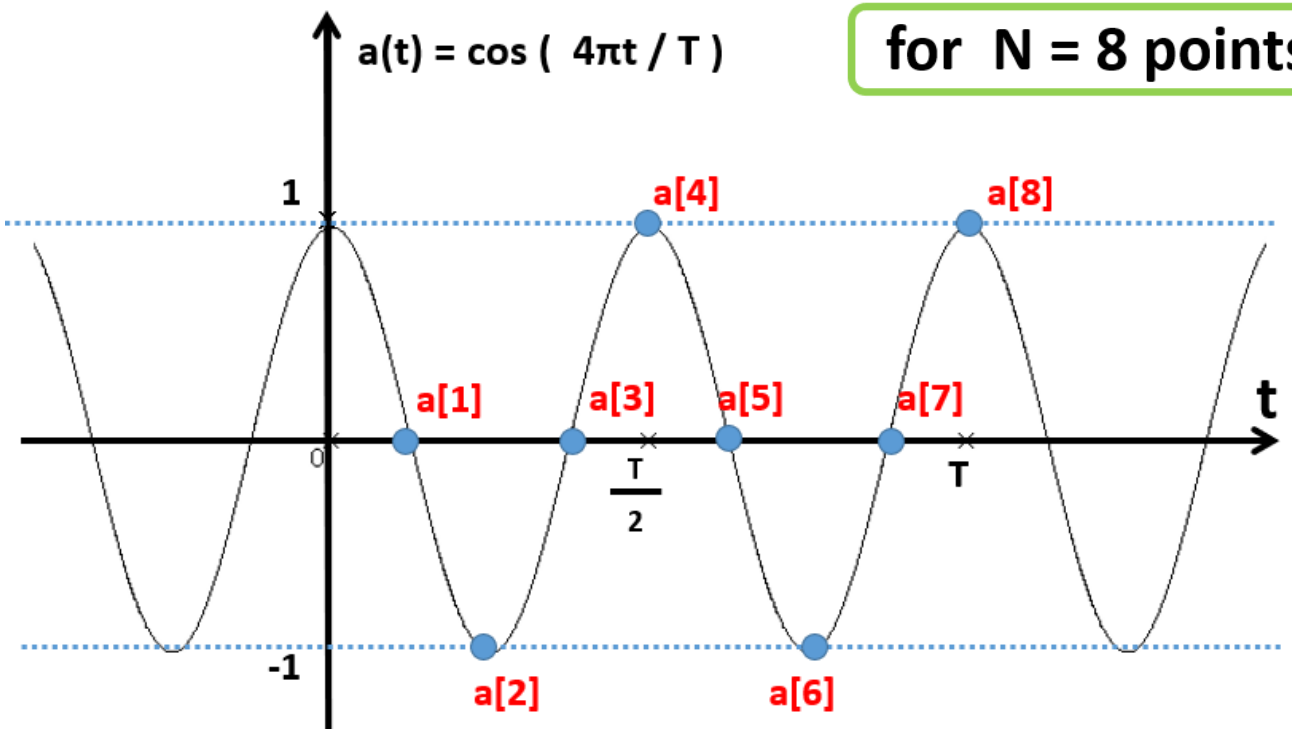
"Design and Performance Estimation of DFT Processing Circuits"

Institute of Electrical Engineers of Japan (IEEJ),
Techinical Journel of IEEJ ICD ECT－14－060,
July 4, 2012, Izumo-city, Japan

DFT is essential for voice and picture recognition. Normally DFT is processed by software,and the processing time is not negligible. This paper reports a challenge to design a DFT hardware engine circuit and estimate its performance by use of a recursive design procedure.

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

Normally DFT is processed by software. However, the processing time is not negligible . To build a powerful AI image sensor system, a DFT digital circuit real time hardware engine is strongly desired.



Sampling Points are at t[k] = kT/8 for k=1 to 8 ;

a[ ] ={ a[1], a[2], ····· , a[8] }

A[ ] ={A[1], A[2], ····· , A[8] }

$$DFT[m][n] = \exp(-2\,m\,n\,\pi\,i / N)$$

for m = 1, 2, ····· N and n = 1, 2,····· N.

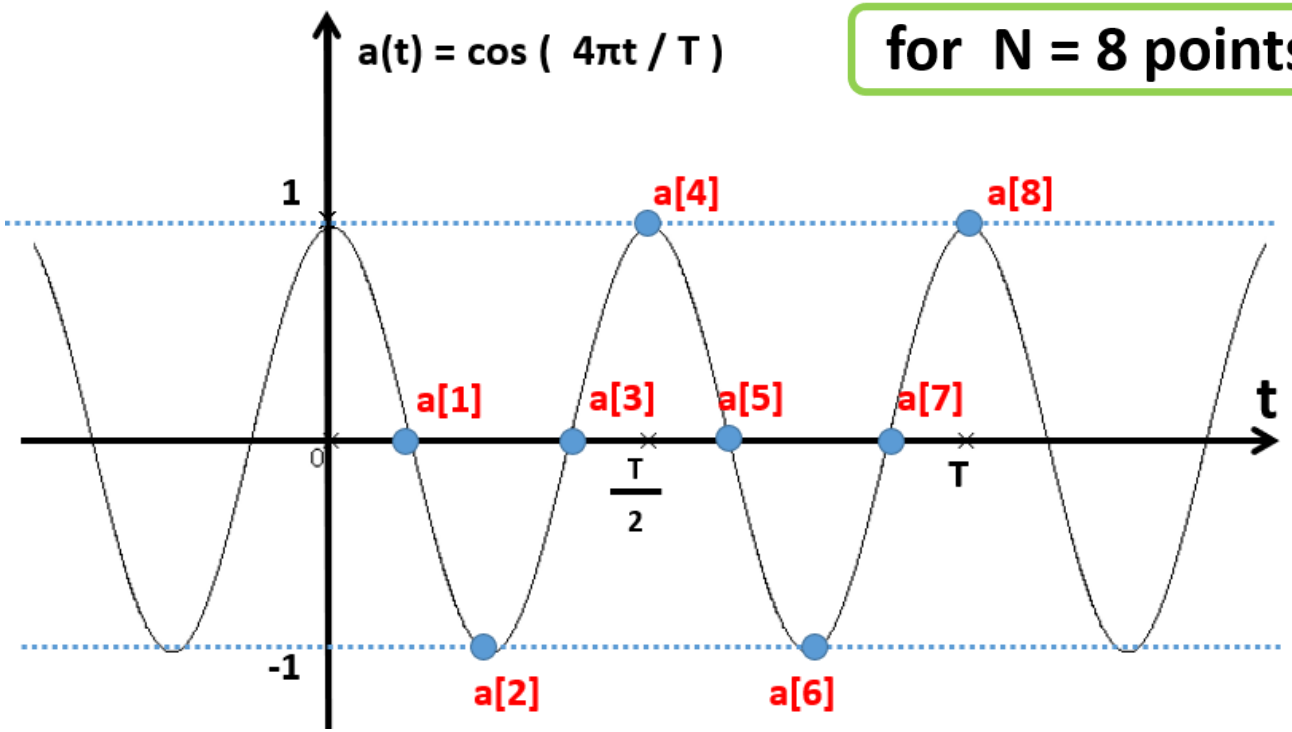
$$i^2 = -1$$

$$A[\,] = DFT[\,][\,]a[\,]$$

A simple case of the input signal $a(t) = \cos(4\pi t / T)$ and the N = 8 sampling points

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

The frequency component vector A[ ] can be obtained by multiplying the input signal vector a[ ] by the DFT matrix DFT8[][ ] .



Sampling Points are at t[k] = kT/8 for k=1 to 8 ;

a[ ] ={ a[1], a[2], ····· , a[8] }

A[ ] ={A[1], A[2], ····· , A[8] }

DFT [m][n] = exp (– 2 m n π i / N)

for m = 1, 2, ····· N and n = 1, 2,····· N.

$i^2 = -1$

A[ ] = DFT[ ][ ]a[ ]

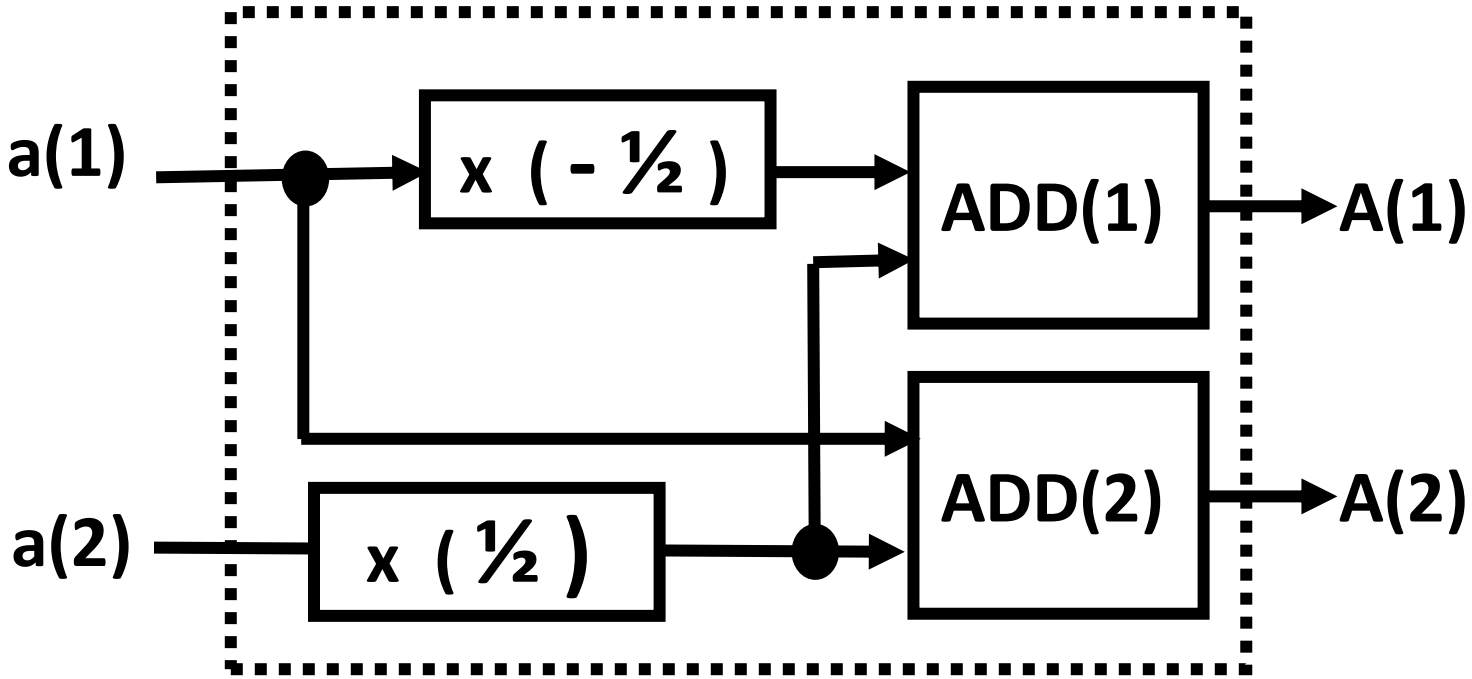
A simple case of the input signal **a(t) = cos (4πt / T)** and the N = 8 sampling points

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

for N = 2 points

DFT2( ) circuit block diagram

ADD( ) is a full adder function (circuit) and
the multiplier function x(½) has the M value of (½).



DFT2( ) circuit function matrix

$$A[\,] = DFT2[\,][\,]\,a[\,]$$

$$a[\,] = \{ a[1], a[2] \}$$

$$A[\,] = \{A[1], A[2] \}$$

$$j^2 = -1$$

$$DFT2\,[m][n] = \frac{1}{2} \exp\left(- \frac{2\,\pi\, m\, n\, j}{2} \right)$$

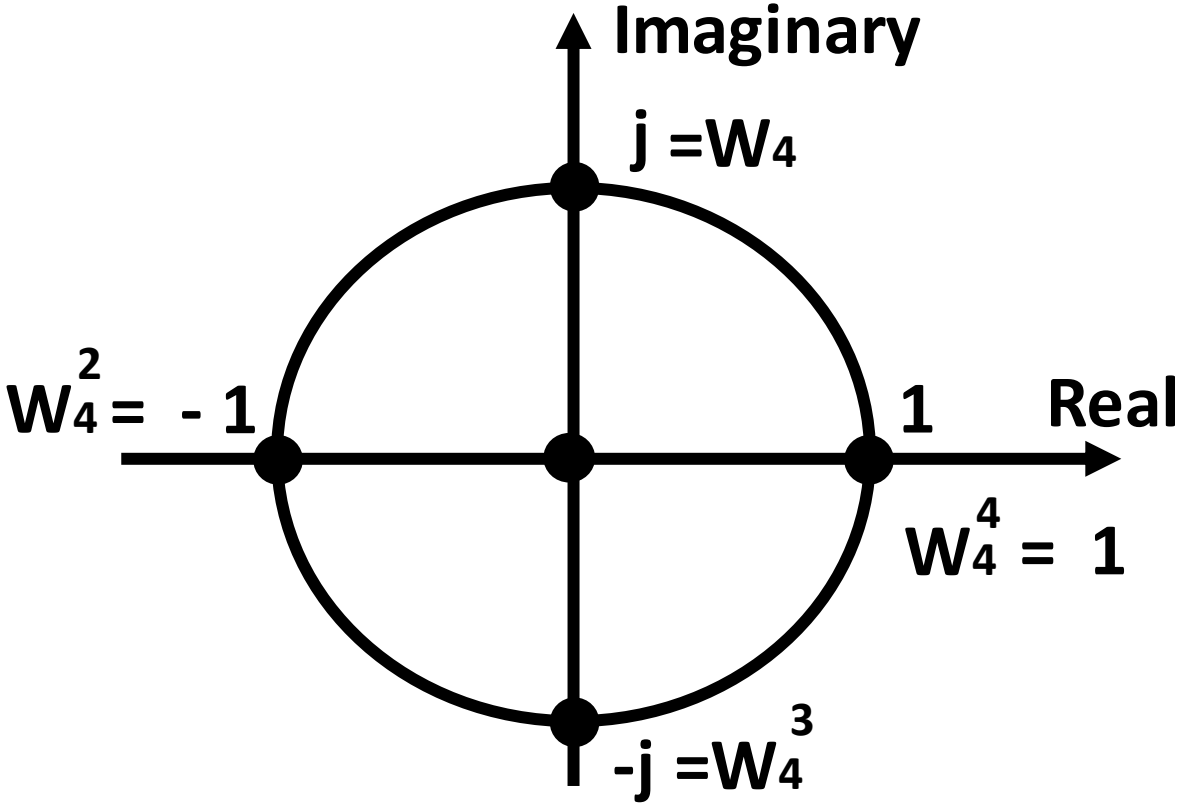
for m = 1, 2 and n = 1,2 .

DFT2( ) Matrix

$$\begin{bmatrix} A(1) \\ A(2) \end{bmatrix} = \frac{1}{2} \begin{bmatrix} -1 & 1 \\ 1 & 1 \end{bmatrix} \begin{bmatrix} a(1) \\ a(2) \end{bmatrix}$$

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

for N = 4 points



$$DFT4[m][n] = \frac{1}{4}\exp\left(-\frac{2\pi m n j}{4}\right)$$

for m = 1, 2 ,3,4 and n = 1,2,3,4 .

DFT4( ) circuit function matrix

$$A[\,] = DFT4[\,][\,]\,a[\,]$$

a[ ] ={ a[1], a[2],a[3].a[4] }

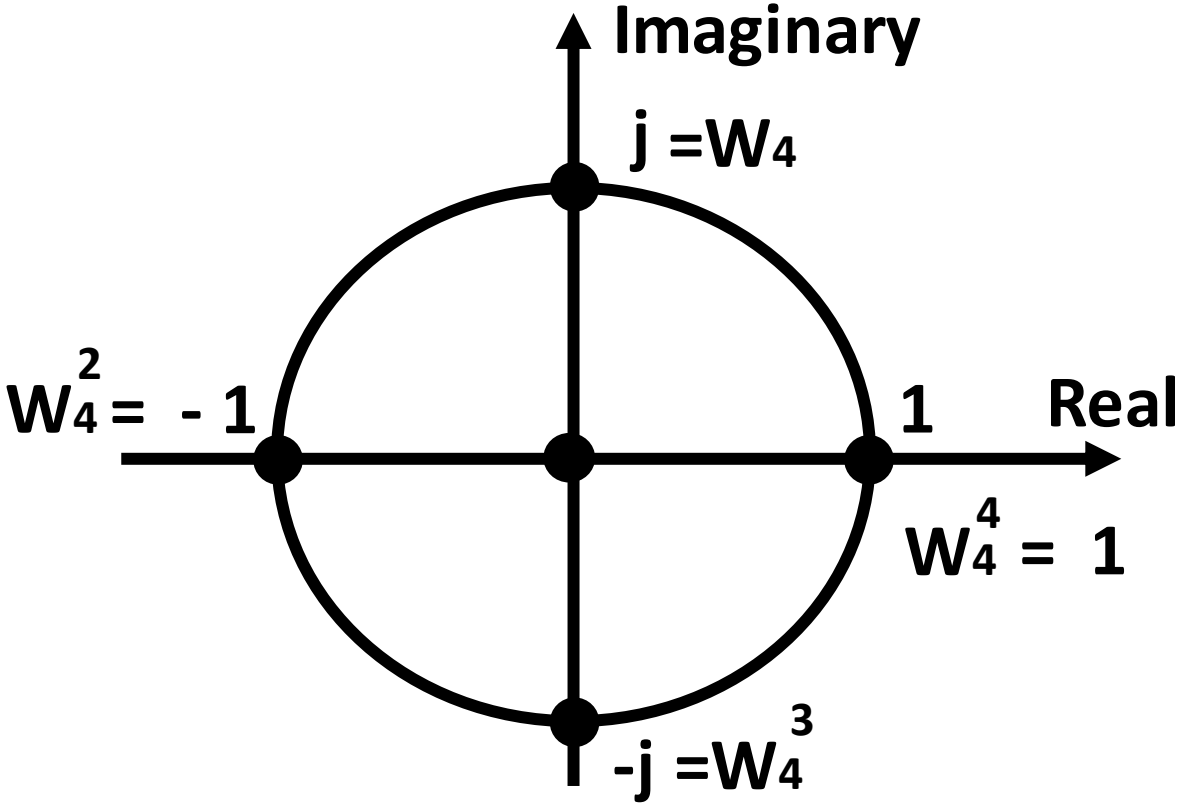
A[ ] ={A[1], A[2].A[3],A[4] }

$$\begin{vmatrix} A(1) \\ A(2) \\ A(3) \\ A(4) \end{vmatrix} = \frac{1}{4} \begin{vmatrix} -j & -1 & j & 1 \\ -1 & 1 & -1 & 1 \\ j & -1 & -j & 1 \\ 1 & 1 & 1 & 1 \end{vmatrix} \begin{vmatrix} a(1) \\ a(2) \\ a(3) \\ a(4) \end{vmatrix}$$

DFT4( ) Matrix

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

for N = 4 points



$$DFT4[m][n] = \frac{1}{4}\exp\left(-\frac{2\pi m n j}{4}\right)$$

for m = 1, 2 ,3,4 and n = 1,2,3,4 .

DFT4( ) Matrix

$$\begin{bmatrix} A(2) \\ A(4) \end{bmatrix} = \underbrace{\frac{1}{4}\begin{bmatrix} -1 & 1 \\ 1 & 1 \end{bmatrix}\begin{bmatrix} a(1) \\ a(2) \end{bmatrix}}_{DFT2(1)} + \underbrace{\frac{1}{4}\begin{bmatrix} -1 & 1 \\ 1 & 1 \end{bmatrix}\begin{bmatrix} a(3) \\ a(4) \end{bmatrix}}_{DFT2(2)}$$

$$\begin{bmatrix} A(1) \\ A(3) \end{bmatrix} = \underbrace{\frac{1}{4}\begin{bmatrix} -1 & 1 \\ 1 & 1 \end{bmatrix}\begin{bmatrix} -j\ \{ -a(1) + a(3) \} \\ \{ -a(2) + a(4) \} \end{bmatrix}}_{DFT2(3)}$$

$$\begin{vmatrix} A(1) \\ A(2) \\ A(3) \\ A(4) \end{vmatrix} = \frac{1}{4}\begin{array}{|c|c|c|c|} \hline -j & -1 & j & 1 \\ \hline -1 & 1 & -1 & 1 \\ \hline j & -1 & -j & 1 \\ \hline 1 & 1 & 1 & 1 \\ \hline \end{array} \begin{vmatrix} a(1) \\ a(2) \\ a(3) \\ a(4) \end{vmatrix}$$

DFT4( ) Matrix

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

for N = 4 points

DFT4( ) Matrix

$$\begin{vmatrix} A(1) \\ A(2) \\ A(3) \\ A(4) \end{vmatrix} = \frac{1}{4} \begin{array}{|c|c|c|c|} \hline -j & -1 & j & 1 \\ \hline -1 & 1 & -1 & 1 \\ \hline j & -1 & -j & 1 \\ \hline 1 & 1 & 1 & 1 \\ \hline \end{array} \begin{vmatrix} a(1) \\ a(2) \\ a(3) \\ a(4) \end{vmatrix}$$

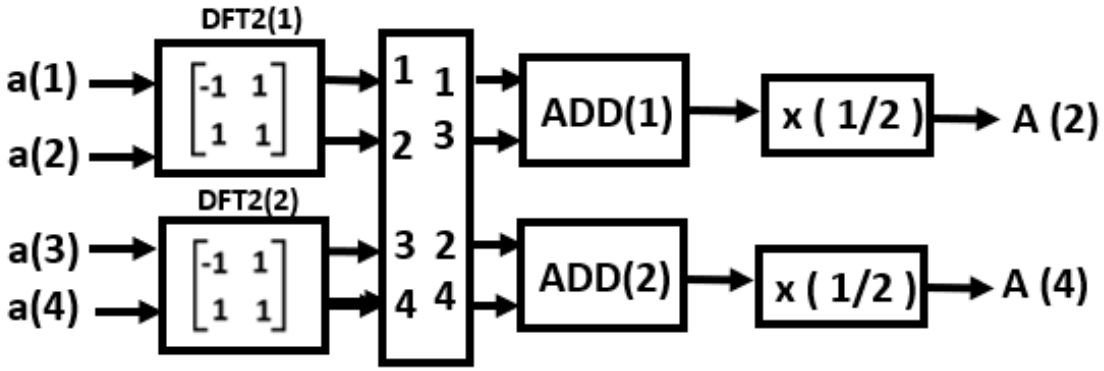
DFT4( ) circuit block diagram

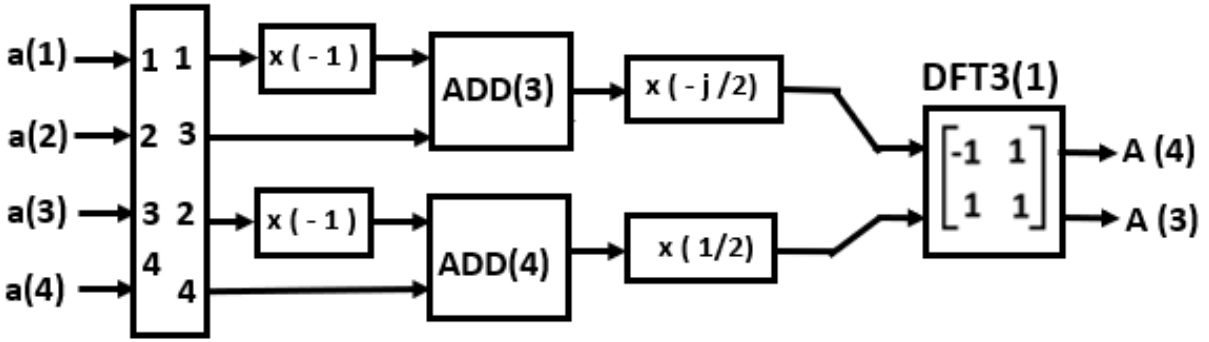
DFT2(1) DFT2(2)

$$\begin{bmatrix} A(2) \\ A(4) \end{bmatrix} = \frac{1}{4} \begin{bmatrix} -1 & 1 \\ 1 & 1 \end{bmatrix} \begin{bmatrix} a(1) \\ a(2) \end{bmatrix} + \frac{1}{4} \begin{bmatrix} -1 & 1 \\ 1 & 1 \end{bmatrix} \begin{bmatrix} a(3) \\ a(4) \end{bmatrix}$$

DFT2(3)

$$\begin{bmatrix} A(1) \\ A(3) \end{bmatrix} = \frac{1}{4} \begin{bmatrix} -1 & 1 \\ 1 & 1 \end{bmatrix} \begin{bmatrix} -j & \{ -a(1) + a(3) \} \\ & \{ -a(2) + a(4) \} \end{bmatrix}$$





DFT2( ) is a 2 bit DFT circuit and x(-j)( ) and x(¼)( ) are multipliers with the M values of (-j) and (¼) respectively.

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

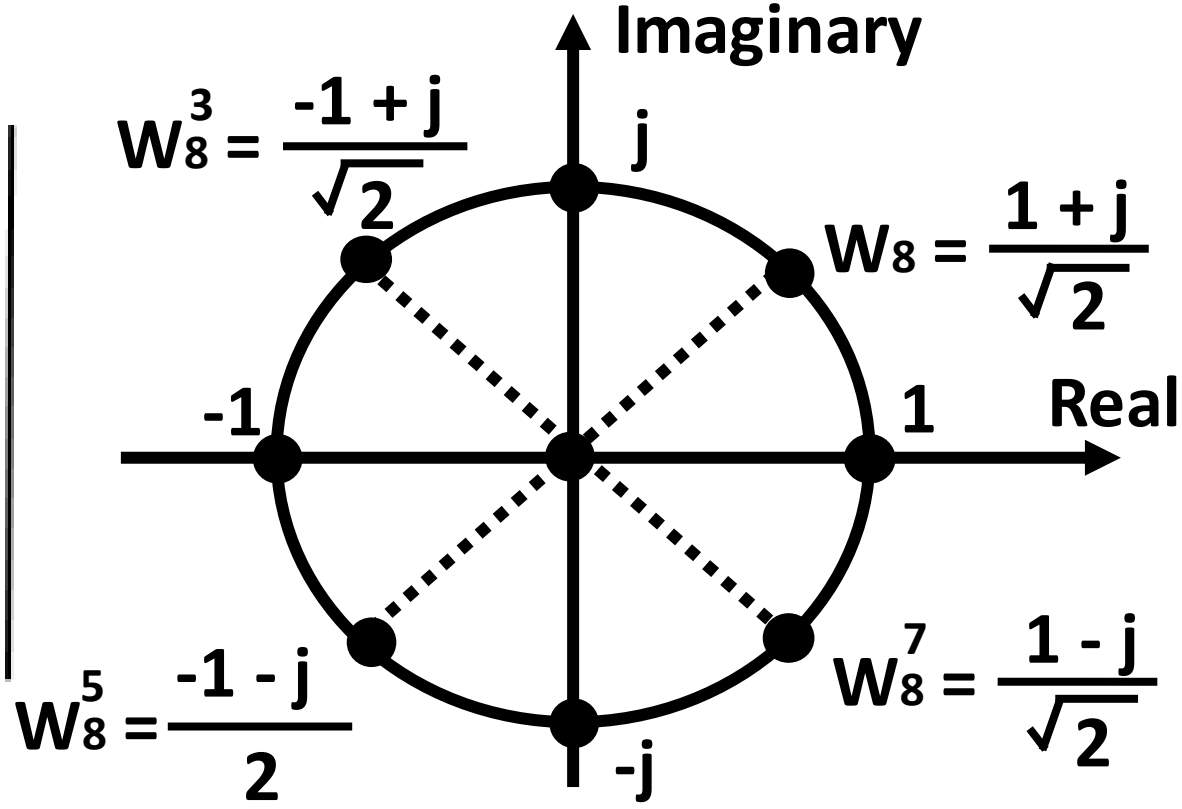
DFT8( ) circuit block diagram

for N = 8 points

$$A[\,] = DFT8[\,][\,]\,a[\,]$$

A[ ] = DFT8[ ][ ] a[ ] matrix for N = 8

$$\begin{vmatrix} A(1) \\ A(2) \\ A(3) \\ A(4) \\ A(5) \\ A(6) \\ A(7) \\ A(8) \end{vmatrix} = \frac{1}{8} \begin{vmatrix} W_8^7 & -j & W_8^5 & -1 & W_8^3 & j & W_8 & 1 \\ -j & -1 & j & 1 & -j & -1 & j & 1 \\ W_8^5 & j & W_8^7 & -1 & W_8 & -j & W_8^3 & 1 \\ -1 & 1 & -1 & 1 & -1 & 1 & -1 & 1 \\ W_8^3 & -j & W_8 & -1 & W_8^7 & j & W_8^5 & 1 \\ j & -1 & -j & 1 & j & -1 & -j & 1 \\ W_8 & j & W_8^3 & -1 & W_8^5 & -j & W_8^7 & 1 \\ 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 \end{vmatrix} \begin{vmatrix} a(1) \\ a(2) \\ a(3) \\ a(4) \\ a(5) \\ a(6) \\ a(7) \\ a(8) \end{vmatrix}$$



a[ ] ={ a[1], a[2],a[3].a[4], a[5], a[6],a[7].a[8] }

A[ ] ={A[1], A[2].A[3],A[4], A[5], A[6].A[7],A[8]}

$$DFT[m][n] = \frac{1}{8} \exp\left(-\frac{2\pi m n j}{8}\right)$$

for m = 1, 2,3,4 ,,,, 8 and n = 1,2,3,4, ,,,,,8

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

DFT8( ) circuit block diagram

for N = 8 points

$$A[\,] = DFT8[\,][\,]\,a[\,]$$

$$\begin{vmatrix} A(1) \\ A(3) \\ A(5) \\ A(7) \end{vmatrix} = \frac{1}{8} \begin{matrix} (W_8) \times \\ (W_8^5) \times \\ (W_8^3) \times \\ (W_8^7) \times \end{matrix} \begin{array}{|c|c|c|c|} \hline -j & j & -1 & 1 \\ \hline -j & j & -1 & 1 \\ \hline j & -j & -1 & 1 \\ \hline j & -j & -1 & 1 \\ \hline \end{array} \begin{vmatrix} a(1) \\ a(3) \\ a(5) \\ a(7) \end{vmatrix} + \frac{1}{8} \begin{array}{|c|c|c|c|} \hline -j & j & -1 & 1 \\ \hline -j & j & -1 & 1 \\ \hline j & -j & -1 & 1 \\ \hline j & -j & -1 & 1 \\ \hline \end{array} \begin{vmatrix} a(2) \\ a(4) \\ a(6) \\ a(8) \end{vmatrix}$$

DFT4( ) Matrix

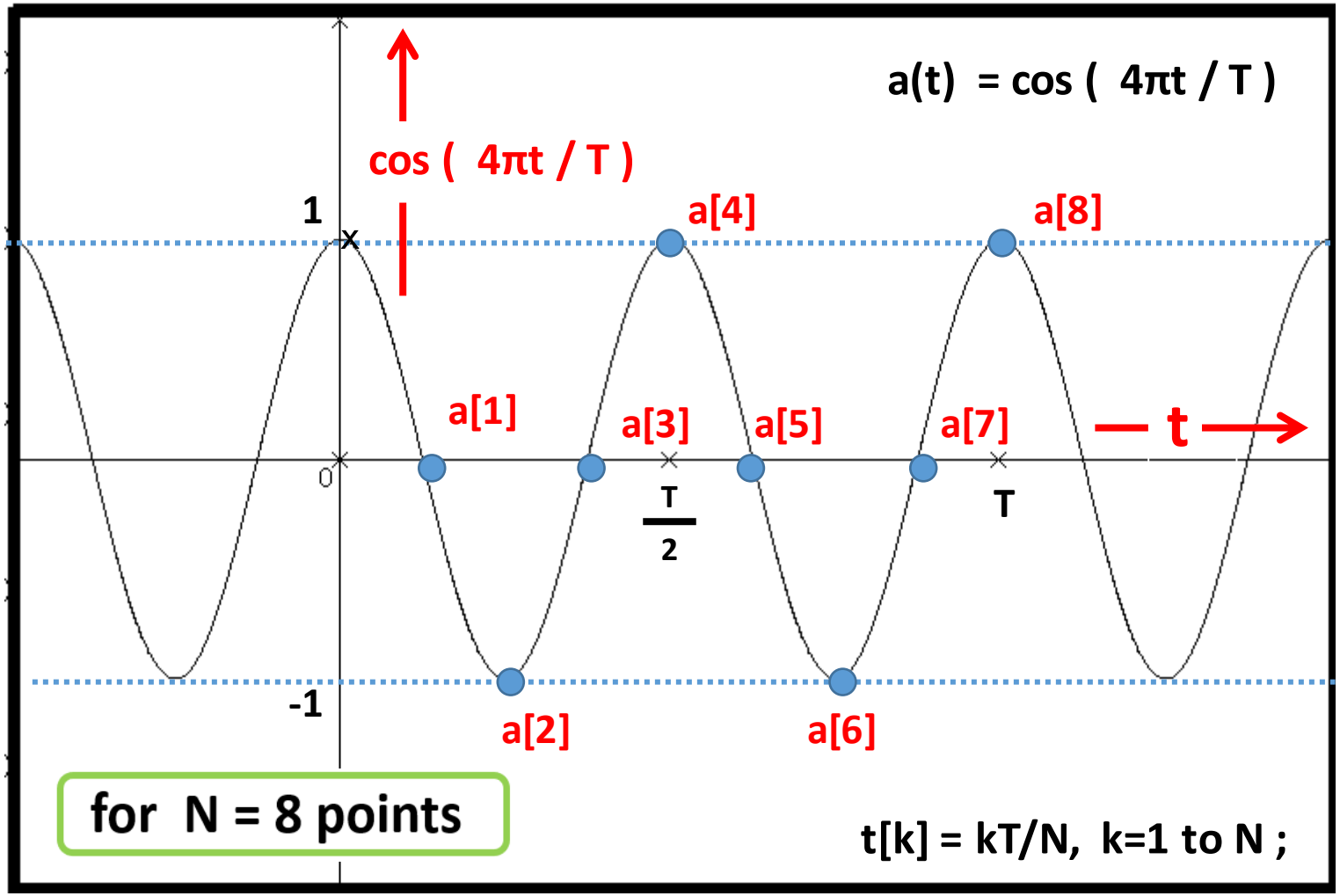
DFT4( ) Matrix

$$\begin{vmatrix} A(2) \\ A(4) \\ A(6) \\ A(8) \end{vmatrix} = \frac{1}{8} \begin{array}{|c|c|c|c|} \hline -j & -1 & j & 1 \\ \hline -1 & 1 & -1 & 1 \\ \hline j & -1 & -j & 1 \\ \hline 1 & 1 & 1 & 1 \\ \hline \end{array} \begin{vmatrix} a(1) \\ a(2) \\ a(3) \\ a(4) \end{vmatrix} + \frac{1}{8} \begin{array}{|c|c|c|c|} \hline -j & -1 & j & 1 \\ \hline -1 & 1 & -1 & 1 \\ \hline j & -1 & -j & 1 \\ \hline 1 & 1 & 1 & 1 \\ \hline \end{array} \begin{vmatrix} a(4) \\ a(5) \\ a(6) \\ a(7) \end{vmatrix}$$

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme

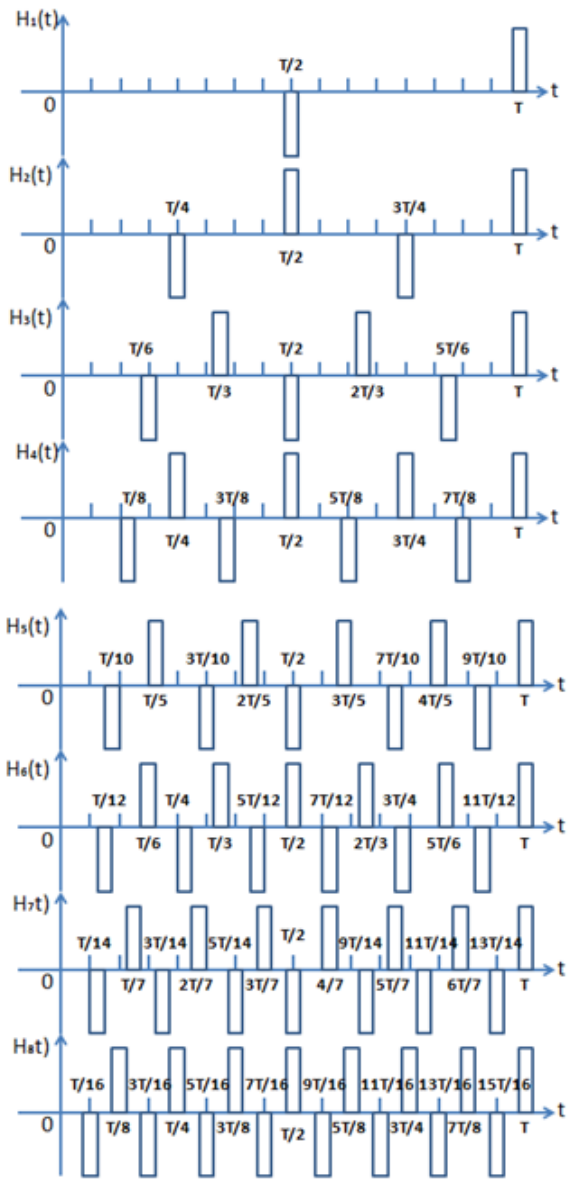
a[1]= 0
a[2]= -1
a[3]= 0
a[4]= 1
a[5]= 0
a[6]= -1
a[7]= 0
a[8]= 1

Ar[1]= 0
Ar[2]= 0.5
Ar[3]= 0
Ar[4]= 0
Ar[5]= 0
Ar[6]= 0
Ar[7]= 0.5
Ar[8]= 0



$$a(t) = \sum_{h=1}^{8} A[h] \exp(2h\pi tj) ; \qquad A[m] = \sum_{k=1}^{8} (1/8)\, DFT8\,[m][k]\, a[k] ;$$

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme



Conventional DFT Case

$$a(t) = \sum_{m=1}^{N} h_m(t)\, A[m]$$

From k=1 to N, t[n]= kT/N and

$$a[k] = a(kT/N) = \sum_{m=1}^{N} h_m(kT/N)\, A[m]$$

$$H[n][m] = h_m(nT/N)$$

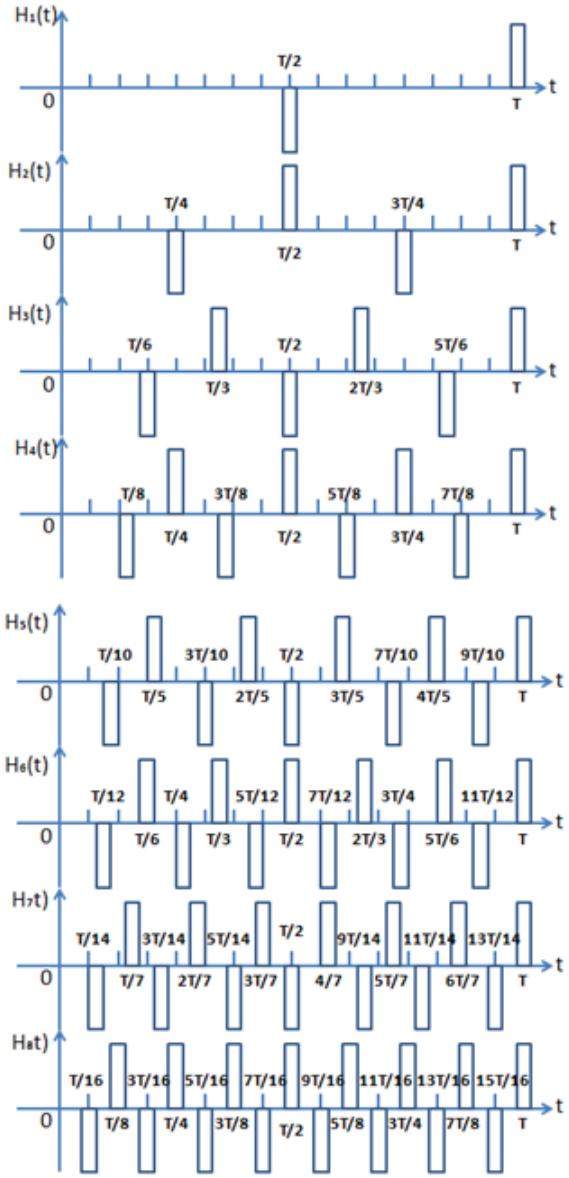
Matrix H[ ][ ] with each element value H[n][m],

$$a[n] = \sum_{m=1}^{N} H[n][m]\, A[m] \quad ; \qquad a(t) = \sum_{m=1}^{N} h_m(t)\, A[m] \quad ;$$

a[ ] = H[ ] [ ] A[ ]

for N = 8 points

Conventional Uniform Interval Δ(T/N) DFT ( ) Sampling Scheme



Conventional DFT Matrix → m

$$DFT8[\,][\,] = \begin{vmatrix} 0 & 0 & 0 & -1 & 0 & 0 & 0 & 1 \\ 0 & -1 & 0 & 1 & 0 & -1 & 0 & 1 \\ 0 & 0 & 0 & -1 & 0 & 0 & 0 & 1 \\ -1 & 1 & -1 & 1 & -1 & 1 & -1 & 1 \\ 0 & 0 & 0 & -1 & 0 & 0 & 0 & 1 \\ 0 & -1 & 0 & 1 & 0 & -1 & 0 & 1 \\ 0 & 0 & 0 & -1 & 0 & 0 & 0 & 1 \\ 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 \end{vmatrix}$$

(n ↓)

$H[n][m] = h_m\ (\ nT/N\ )$

Matrix H[ ][ ] has each element H[n][m].

$$a[n] = \sum_{m=1}^{N} H[n][m]\, f[\,m\,] \quad ; \quad a(\,t\,) = \sum_{m=1}^{N} h_m(\,t\,)\, f[\,m\,]$$

for N = 8 points

$a[\ ] = H[\ ][\ ]\, A[\ ]$

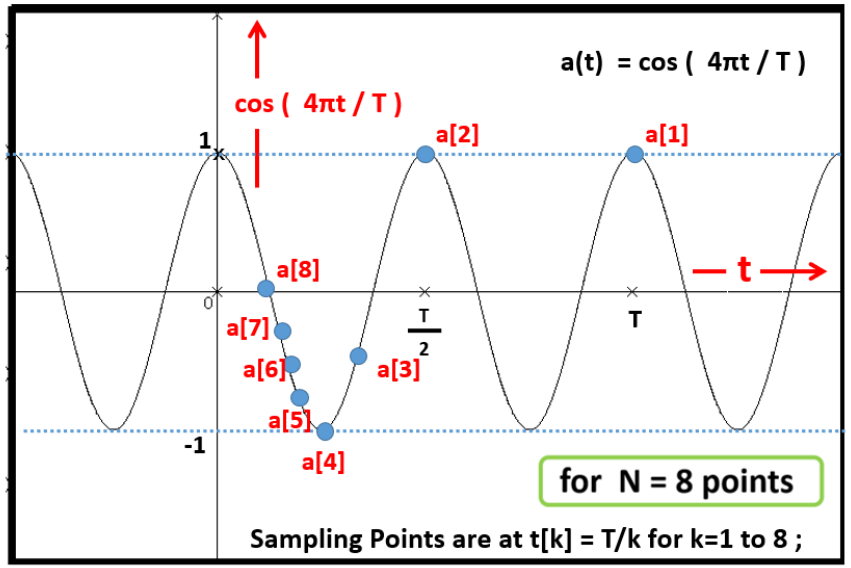
9 Artificial Intelligent Image Sensor

Artificial Intelligent Image Sensor needs many kinds of powerful hardware real time engines. Nonuniform T/k Sampling Scheme with the Fast H [ ][ ] Transformation Matrix is also one of them.

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

a[1]= 1
a[2]= 1
a[3]= - 0.5
a[4]= - 1
a[5]= - 0.809
a[6]= - 0.5
a[7]= - 0.223
a[8]= 0

A[1]= 1.032
A[2]= 1.5
A[3]= 0
A[4]= 0
A[5]= - 0.809
A[6]= - 0.5
A[7]= - 0.223
A[8]= 0



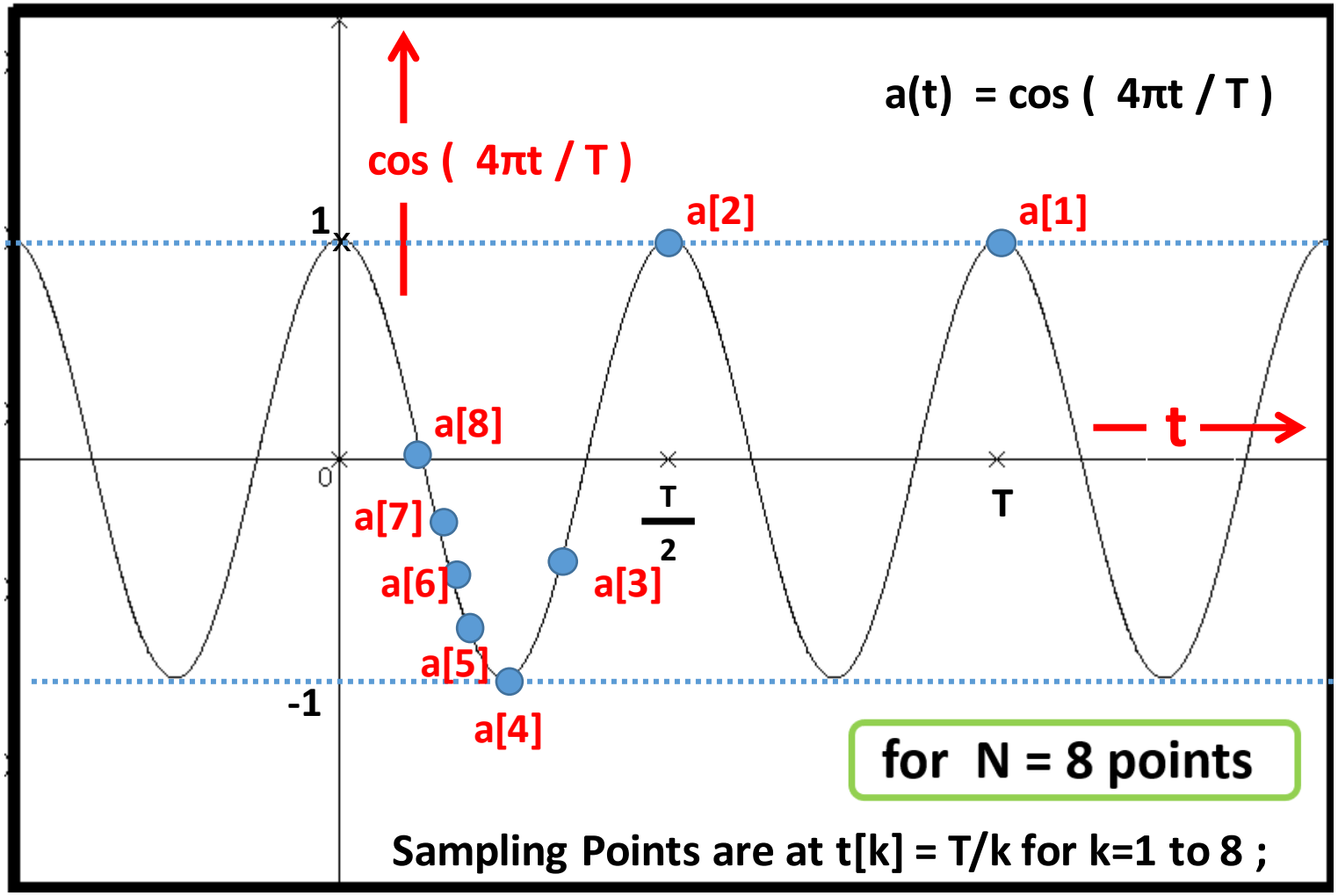
Compute $A[m] = \sum_{k=1}^{8} (1/8)\, H[m][k]\, a[k]$; Then we have $a(t) = \sum_{m=1}^{8} A[m]\, H_m(t)$;

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Step(1) Define $H_m(t)$ functions
Step(2) Define H[m][k]
Step(3) Obtain a[m]
Step(4) Obtain A[m]

a[1]= 1
a[2]= 1
a[3]= - 0.5
a[4]= - 1
a[5]= - 0.809
a[6]= - 0.5
a[7]= - 0.223
a[8]= 0

A[1]= 1.032
A[2]= 1.5
A[3]= 0
A[4]= 0
A[5]= - 0.809
A[6]= - 0.5
A[7]= - 0.223
A[8]= 0



Compute $A[m] = \sum_{k=1}^{8} (1/8)\, H[m][k]\, a[k]$; Then we have $a(t) = \sum_{m=1}^{8} A[m]\, H_m(t)$;

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Design and Performance Estimation of DFT Processing Circuits

Japanese Patent Application JPA 2014-135497

filed on July 1, 2014 by Yoshiaki Hagiwara.

"The digital circuit engine design to convert the time domain information to the frequency domain information"

Related published paper on

Masaru TANAKA, Weikun LIANG, and Yoshiaki HAGIWARA,

"Digital Frequency Transformation Circuit for Time-wise Unequally Sampled Data"

THE INSTITUTE OF ELECTRONICS,
INFORMATION AND COMMUNICATION ENGINEERS,
IEICE Technical Report,
August 25, 2015, Kumamoto-city, Japan

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Masaru TANAKA, Weikun LIANG, and Yoshiaki HAGIWARA,

"Digital Frequency Transformation Circuit
for Time-wise Unequally Sampled Data"

THE INSTITUTE OF ELECTRONICS,
INFORMATION AND COMMUNICATION ENGINEERS,
IEICE Technical Report,
August 25, 2015, Kumamoto-city, Japan

DFT is essential for voice and picture recognition. Normally DFT is processed for Time-wise Equally Sampled Data. This paper reports a challenge to design a DFT circuit for Time-wise Unequally Sampled Data.

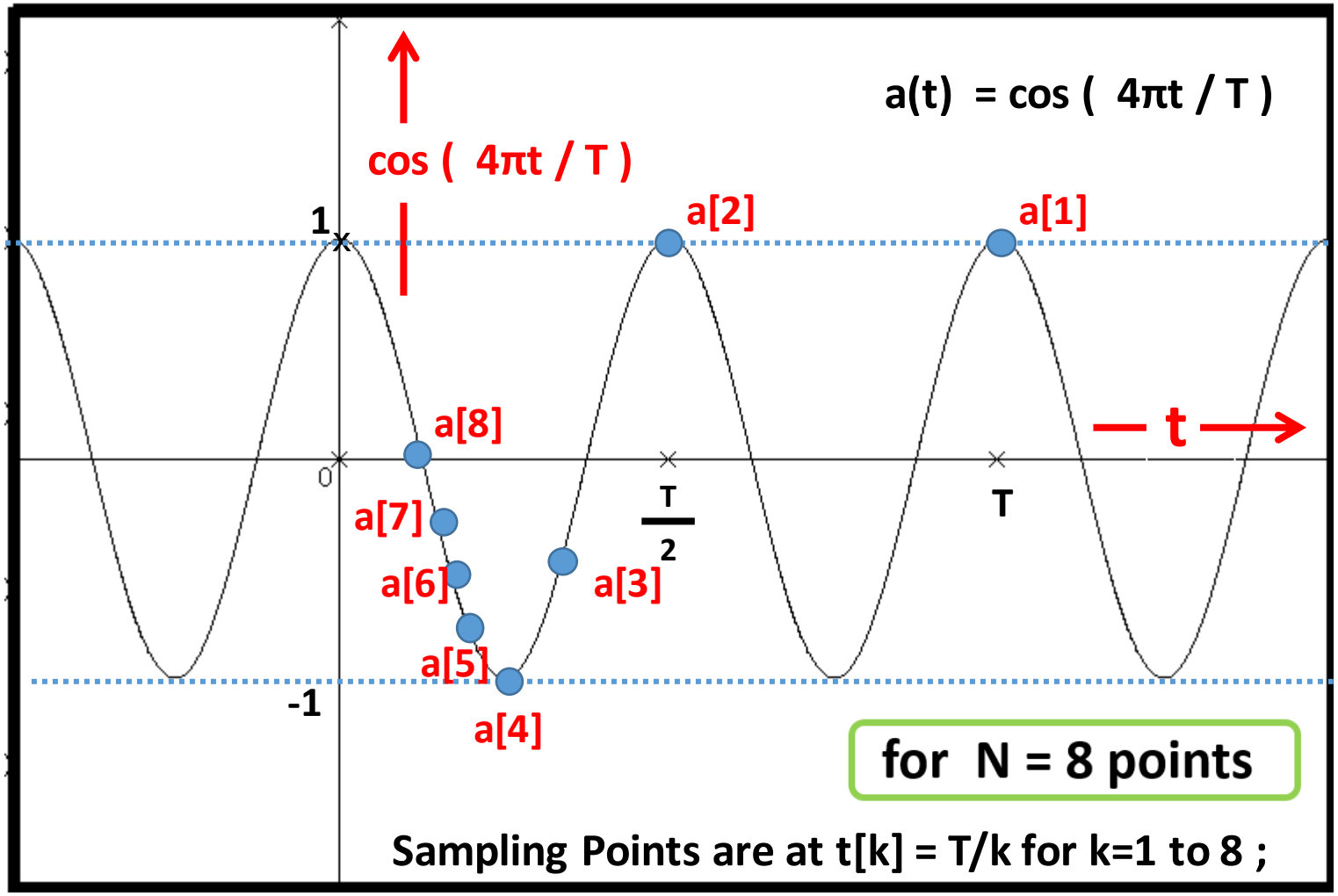
Key Words: DFT , Recursive Procedure, Digital Circuits Design, Circuit Simulation

Step(1) Define $H_m(t)$ functions

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

a[1]= 1
a[2]= 1
a[3]= - 0.5
a[4]= - 1
a[5]= - 0.809
a[6]= - 0.5
a[7]= - 0.223
a[8]= 0

A[1]= 1.032
A[2]= 1.5
A[3]= 0
A[4]= 0
A[5]= - 0.809
A[6]= - 0.5
A[7]= - 0.223
A[8]= 0

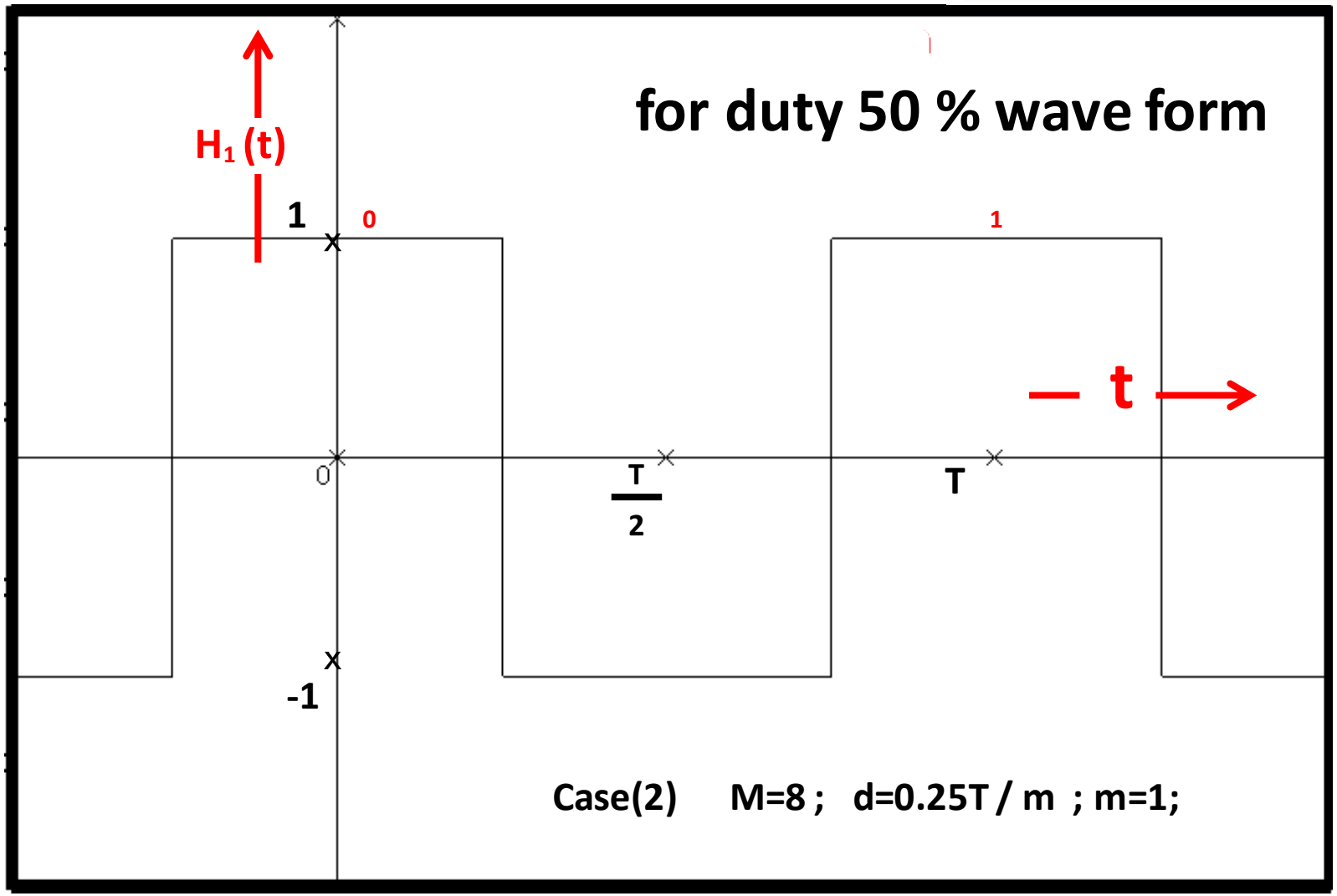


Compute $A[m] = \sum_{k=1}^{8} (1/8)\, H[m][k]\, a[k]$; Then we have $a(t) = \sum_{m=1}^{8} A[m]\, H_m(t)$;

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define $H_m(t)$ function ; m = 1;

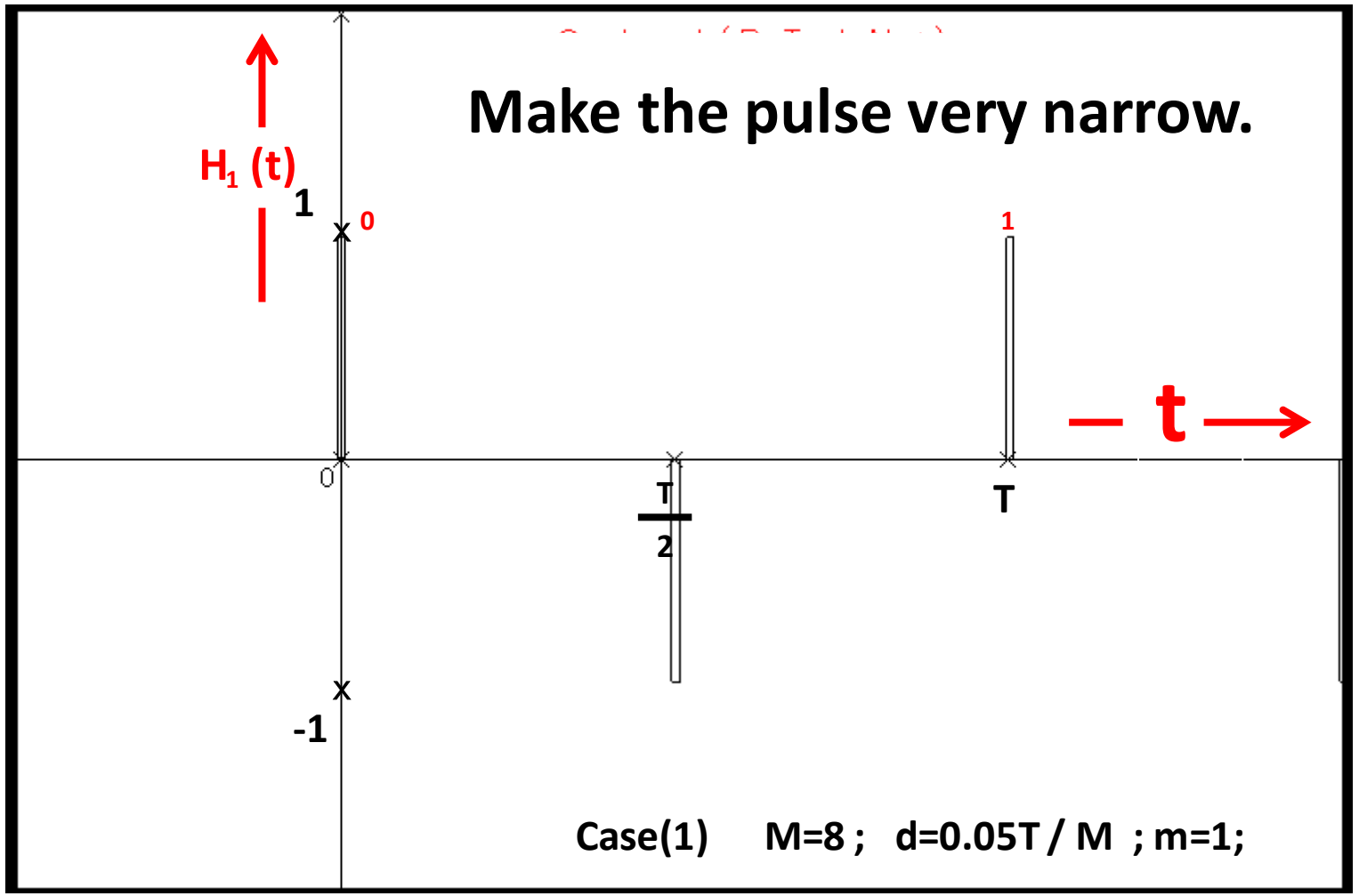
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define $H_m(t)$ function ; m = 1;

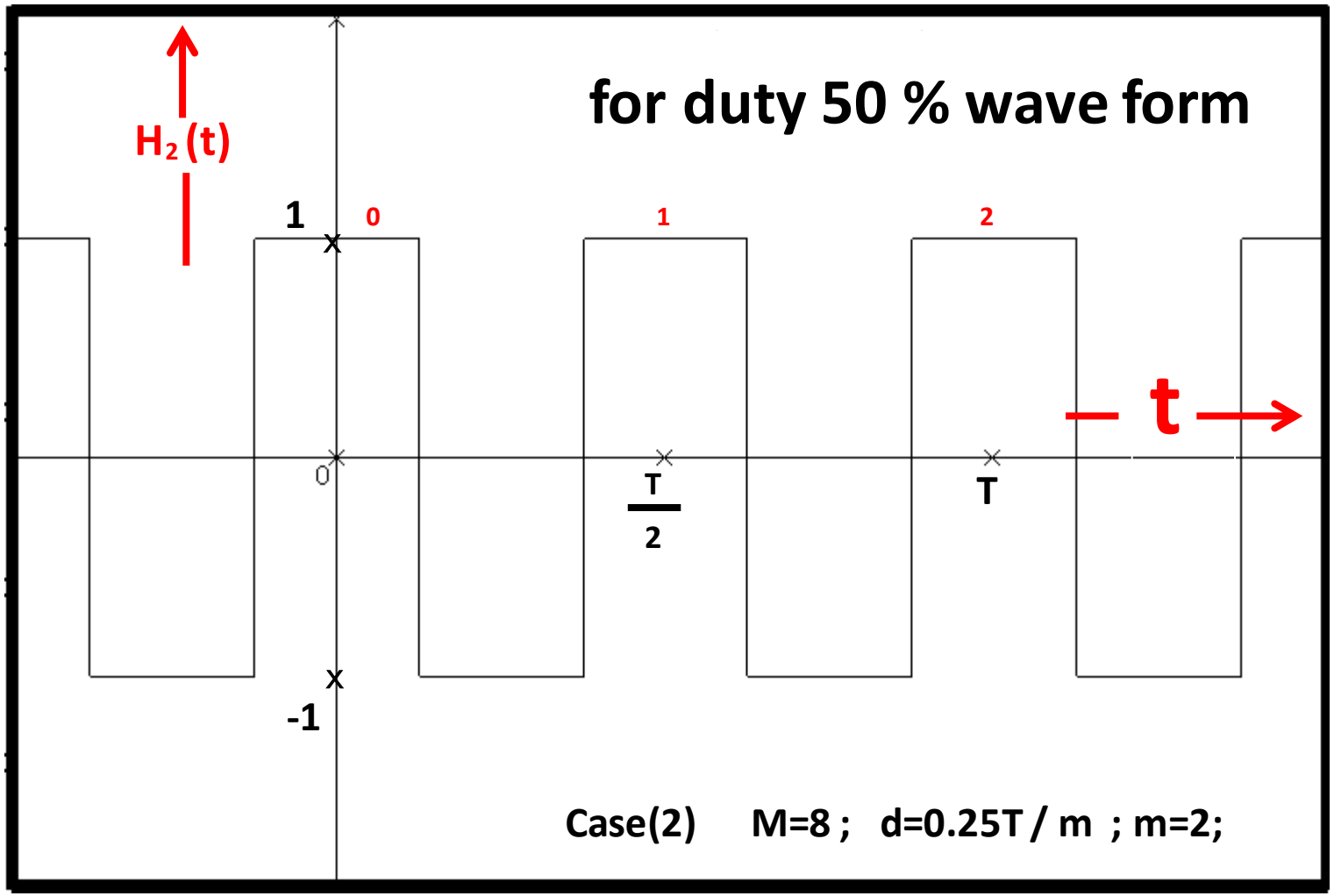
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define $H_m(t)$ function ; m = 2;

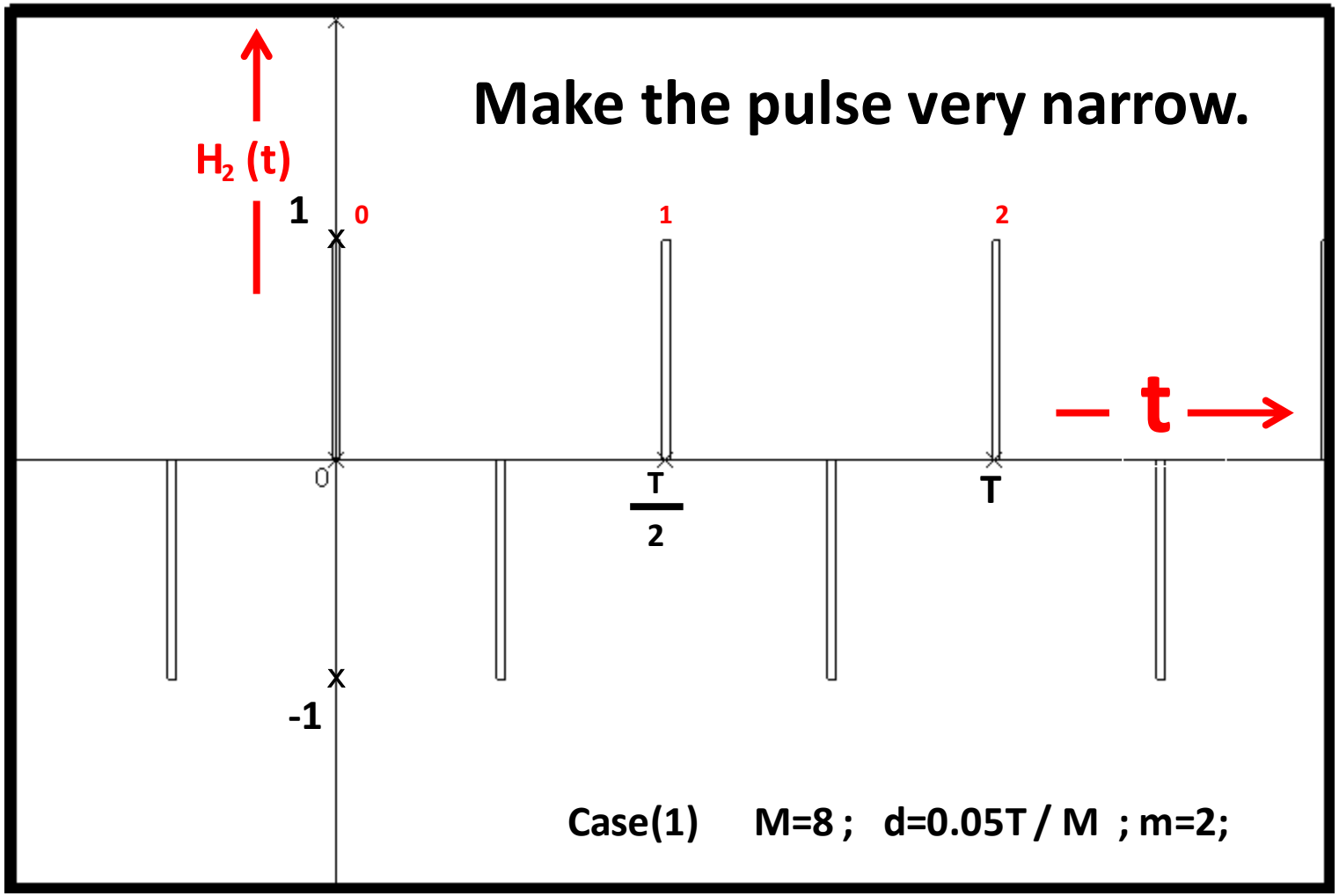
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define H_m (t) function ; m = 2;

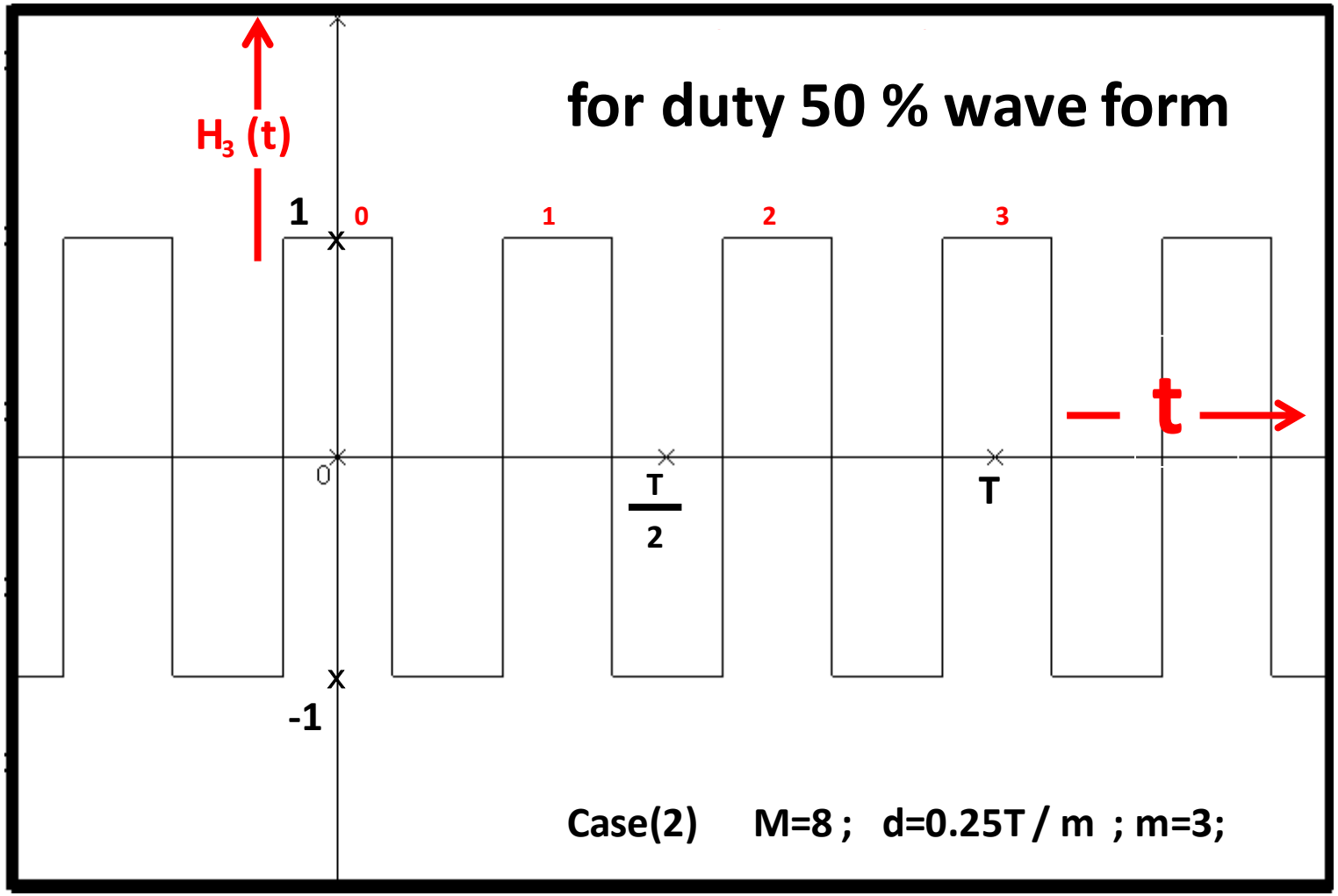
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define $H_m(t)$ function ; m = 3;

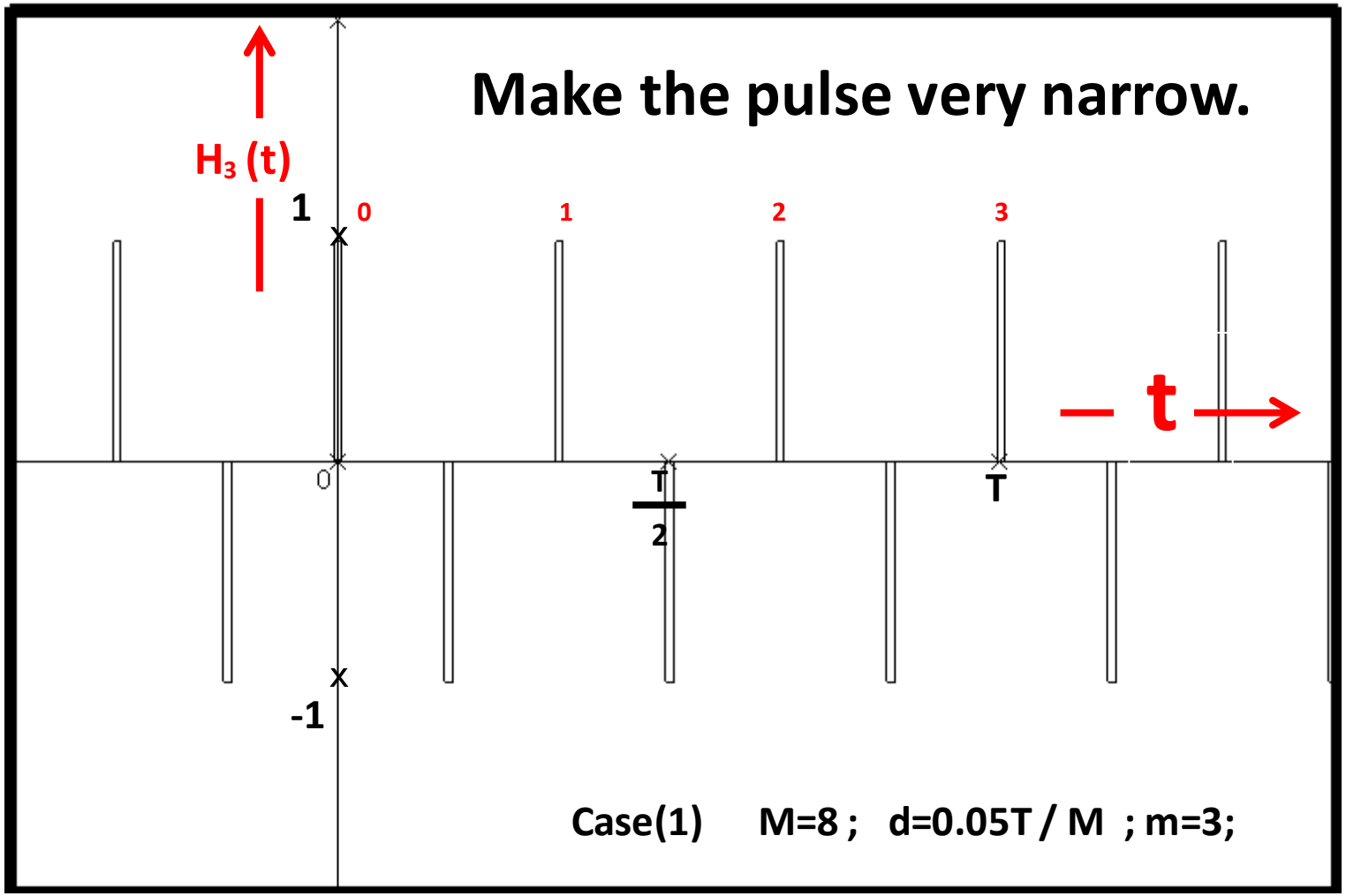
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define H_m (t) function ; m = 3;

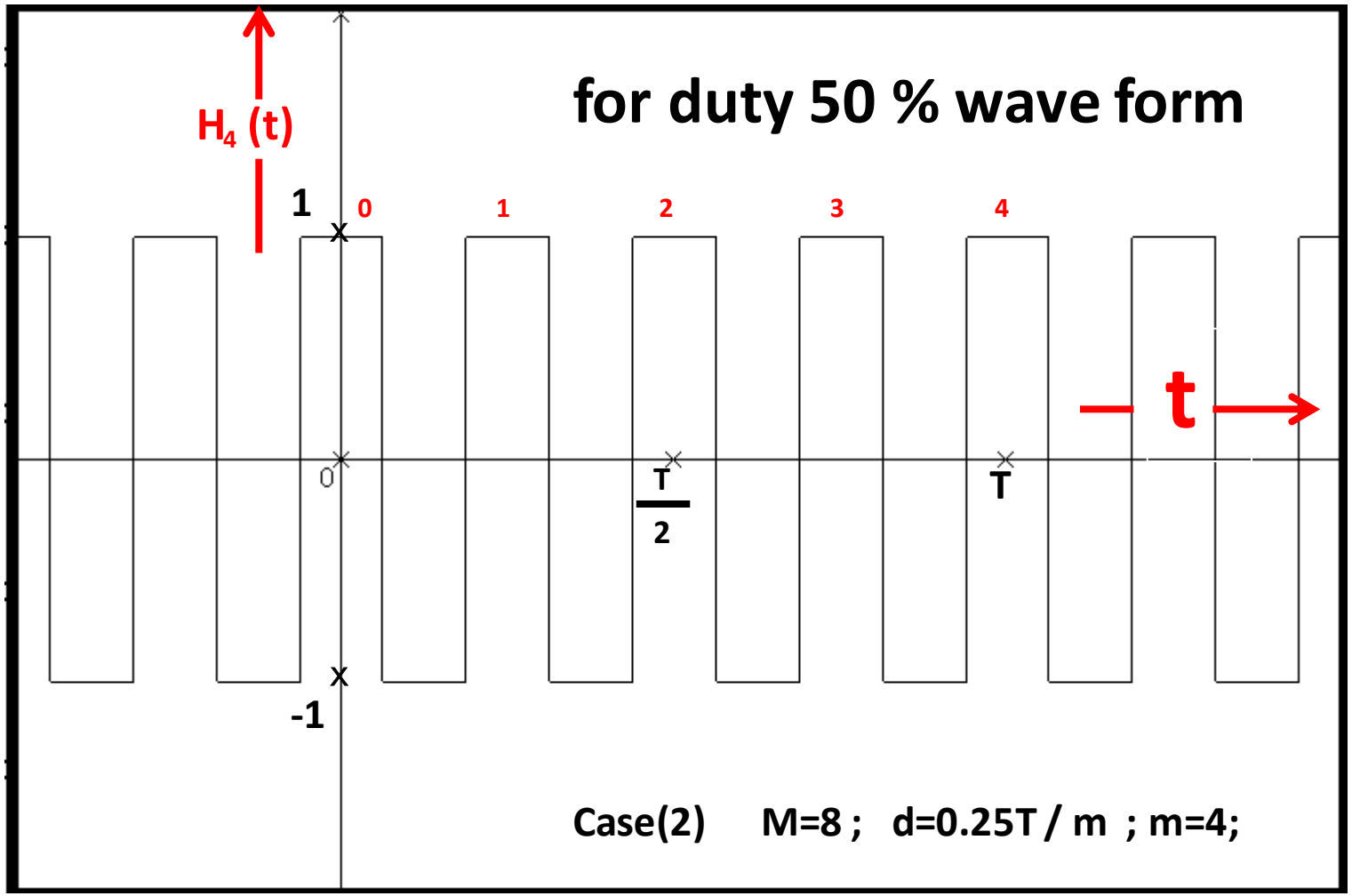
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define H_m (t) function ; m = 4;

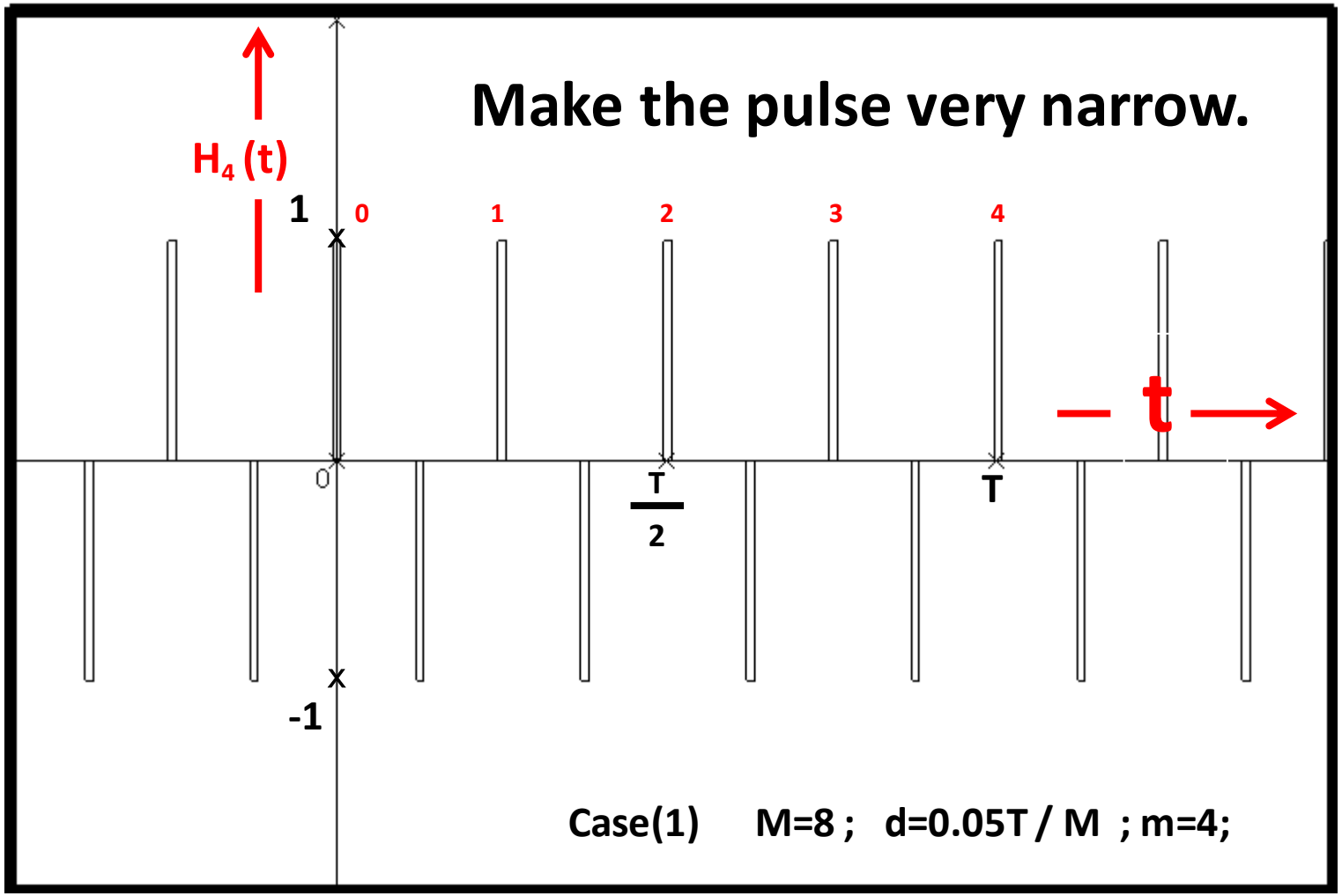
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define $H_m(t)$ function ; m = 4;

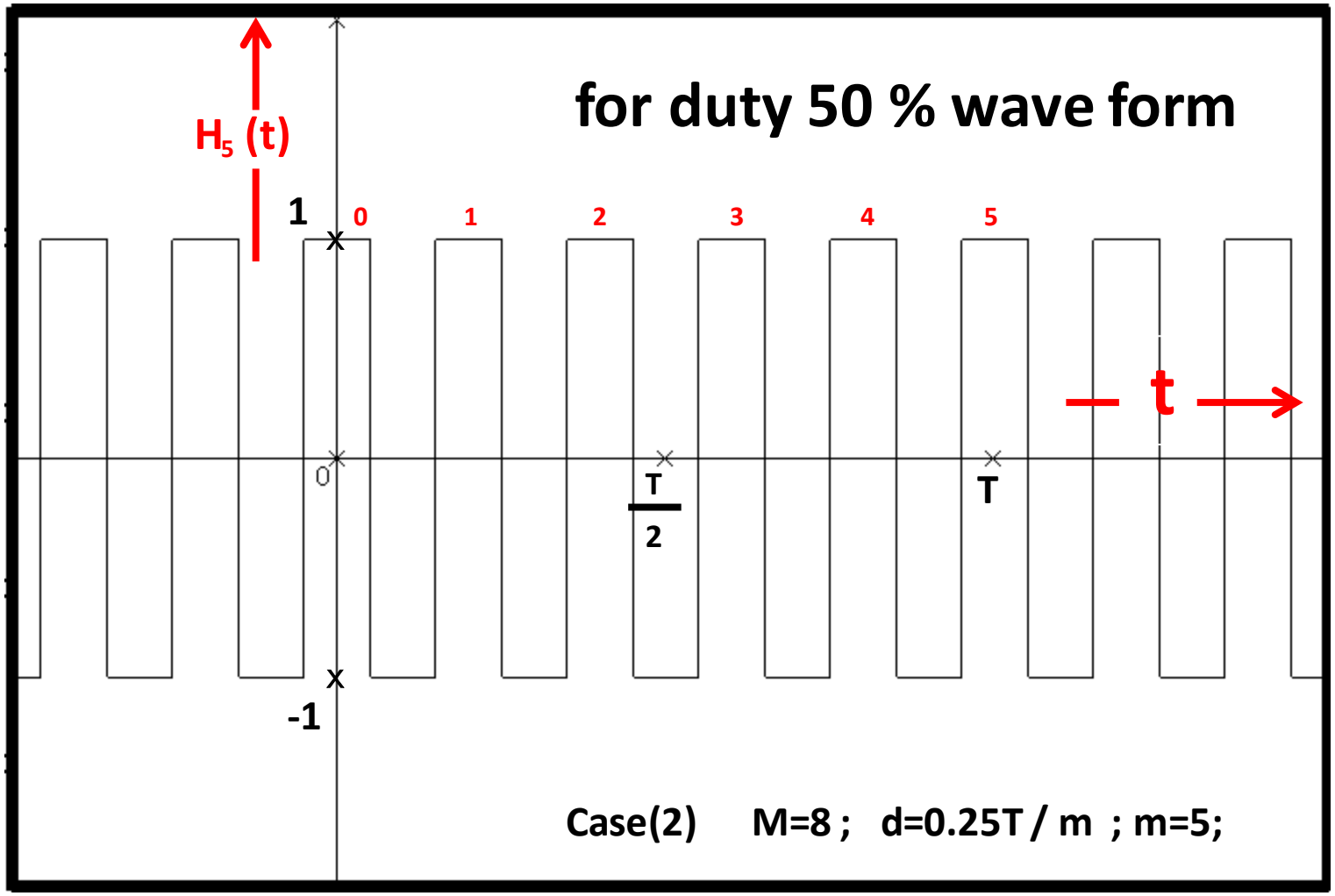
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define $H_m(t)$ function ; m = 5;

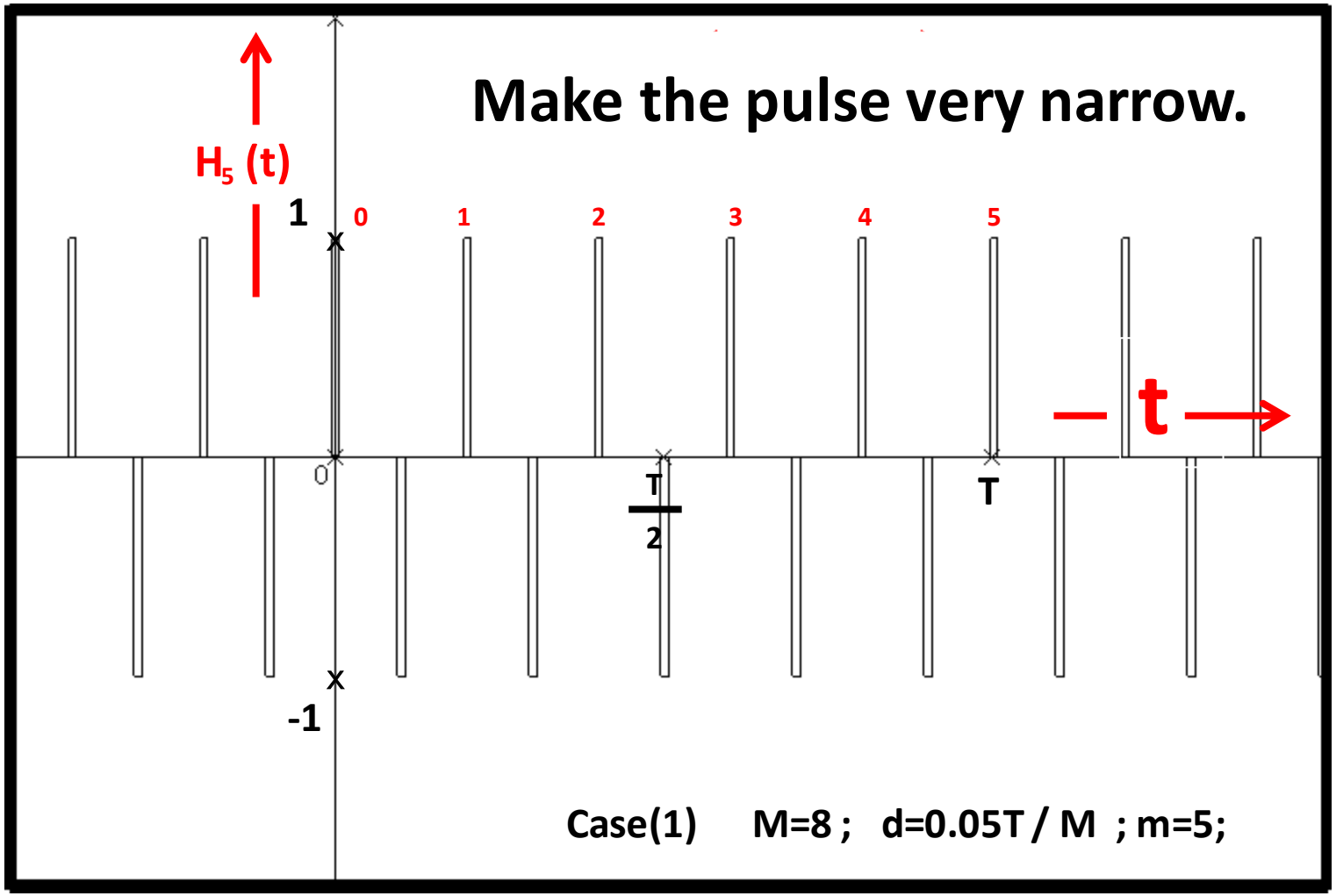
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define $H_m(t)$ function ; m = 5;

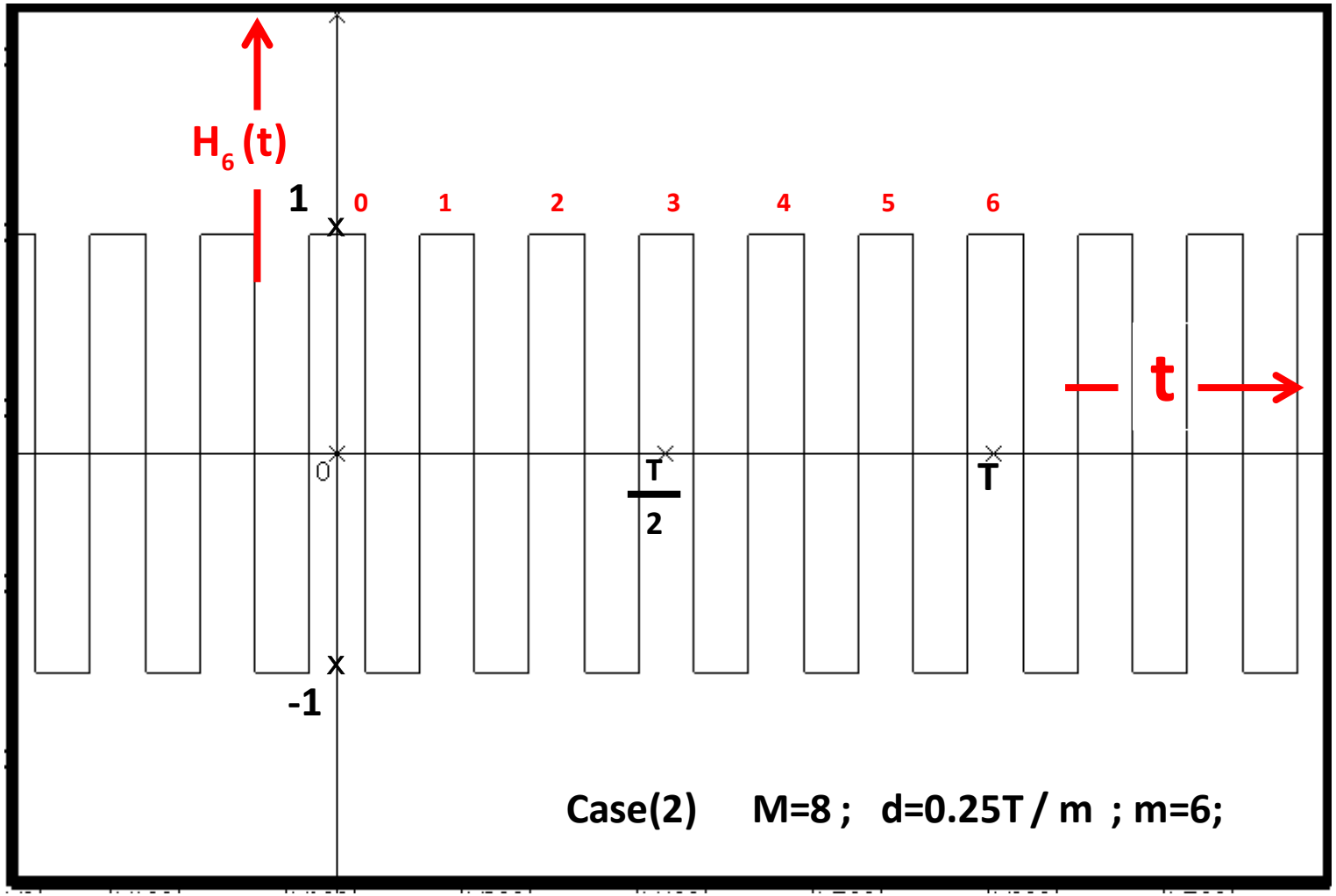
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

H_m (t) function; m = 6;

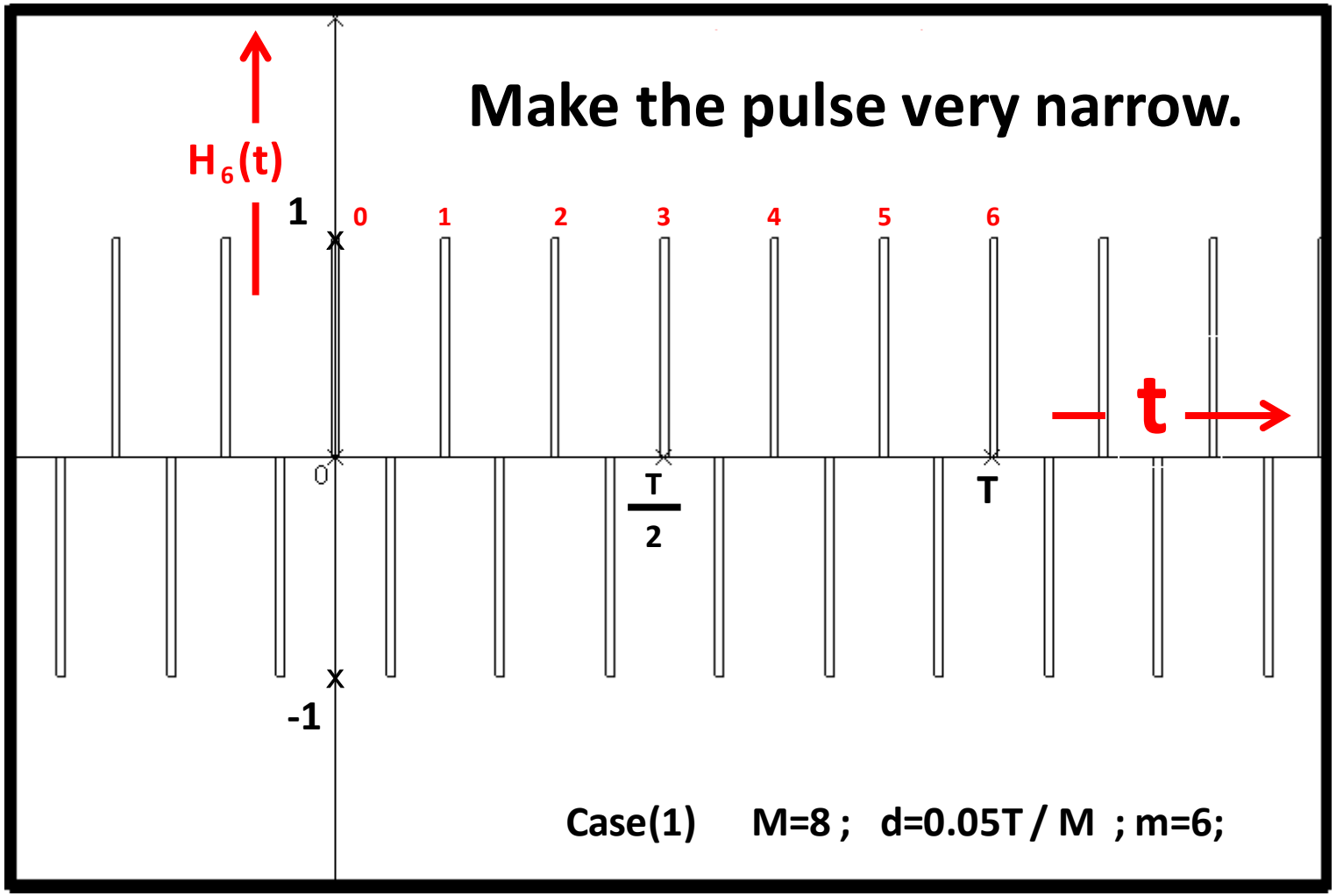
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define $H_m(t)$ function ; m = 6;

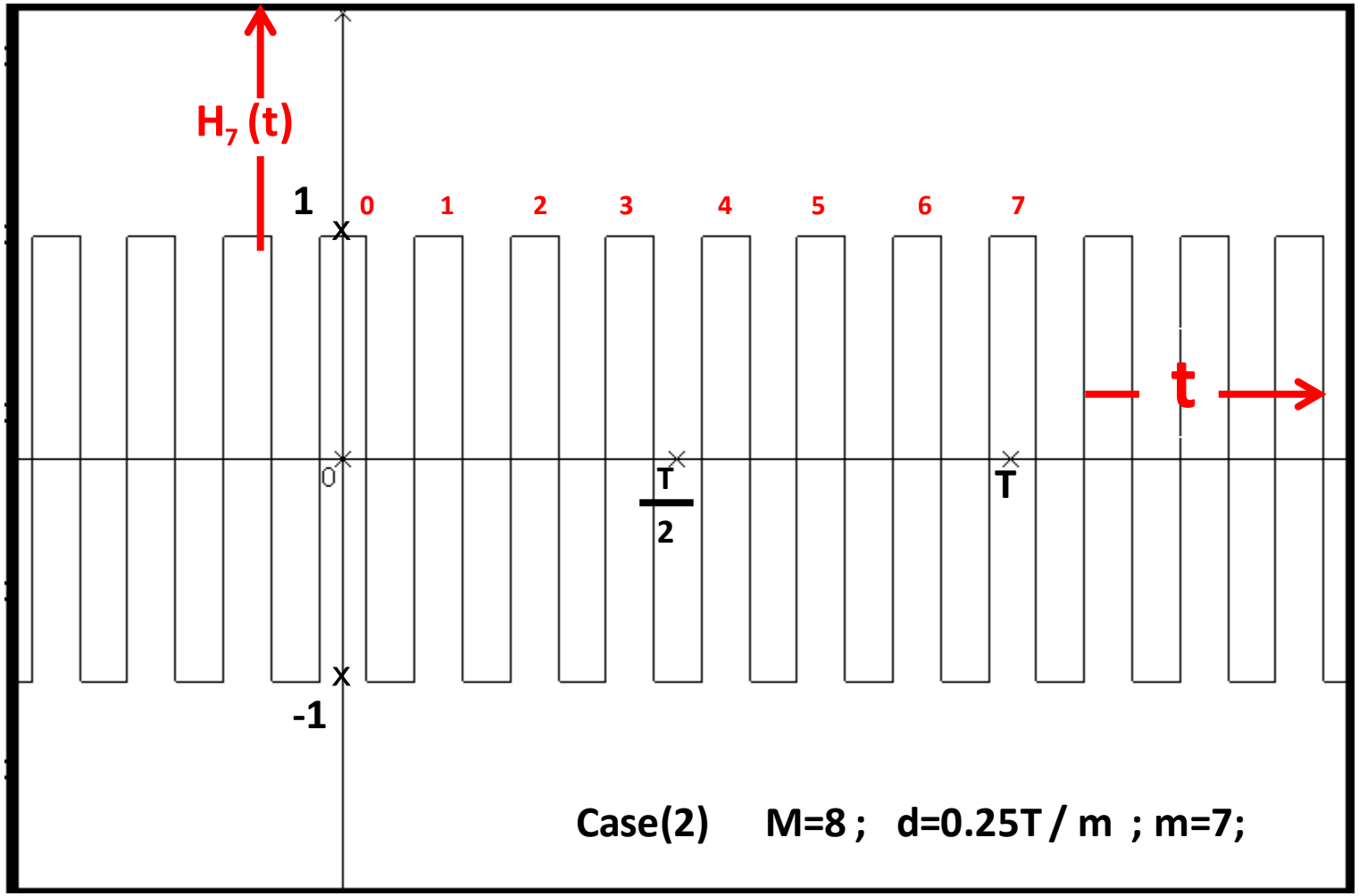
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

H_m (t) function; m = 7;

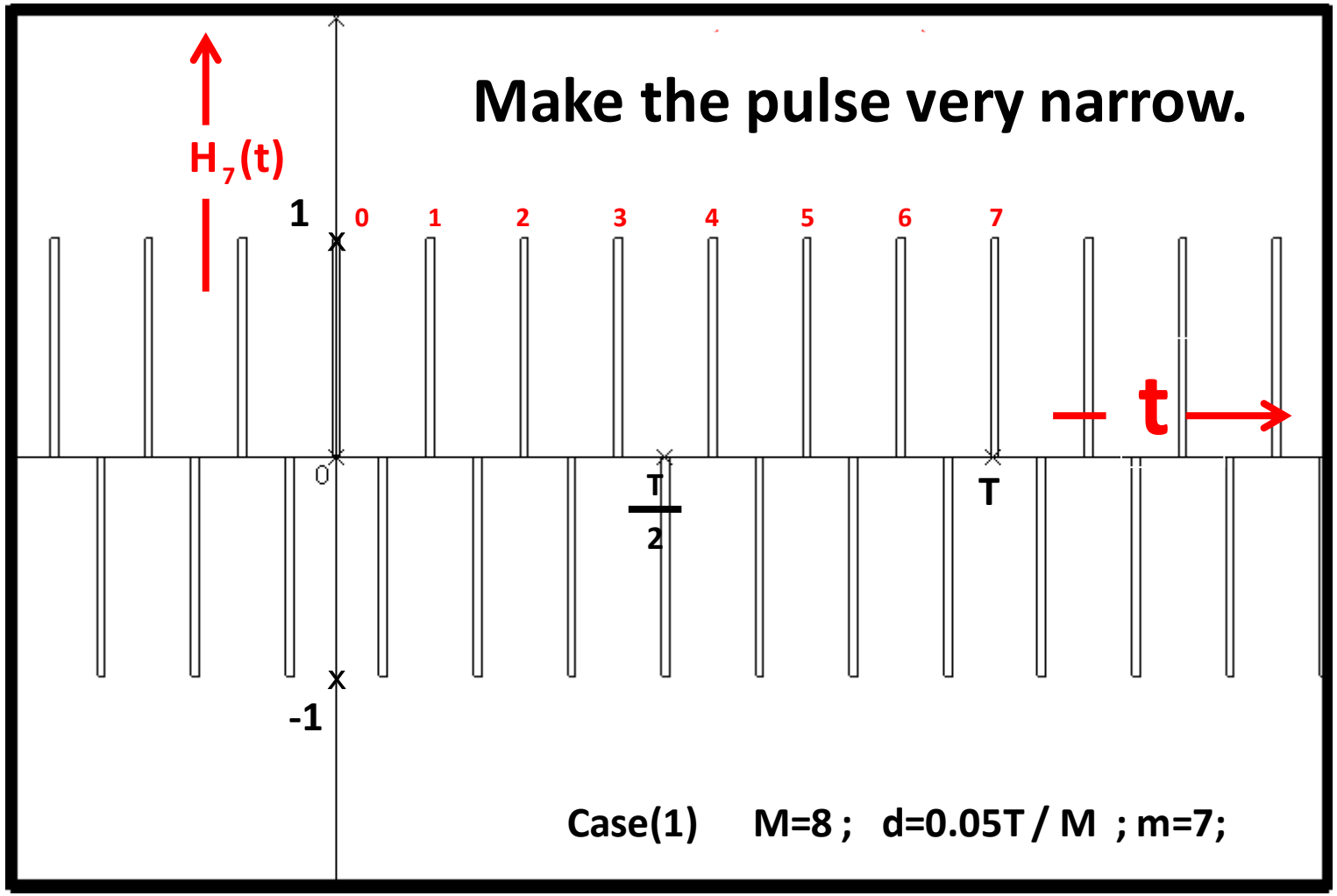
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define $H_m(t)$ function ; m = 7;

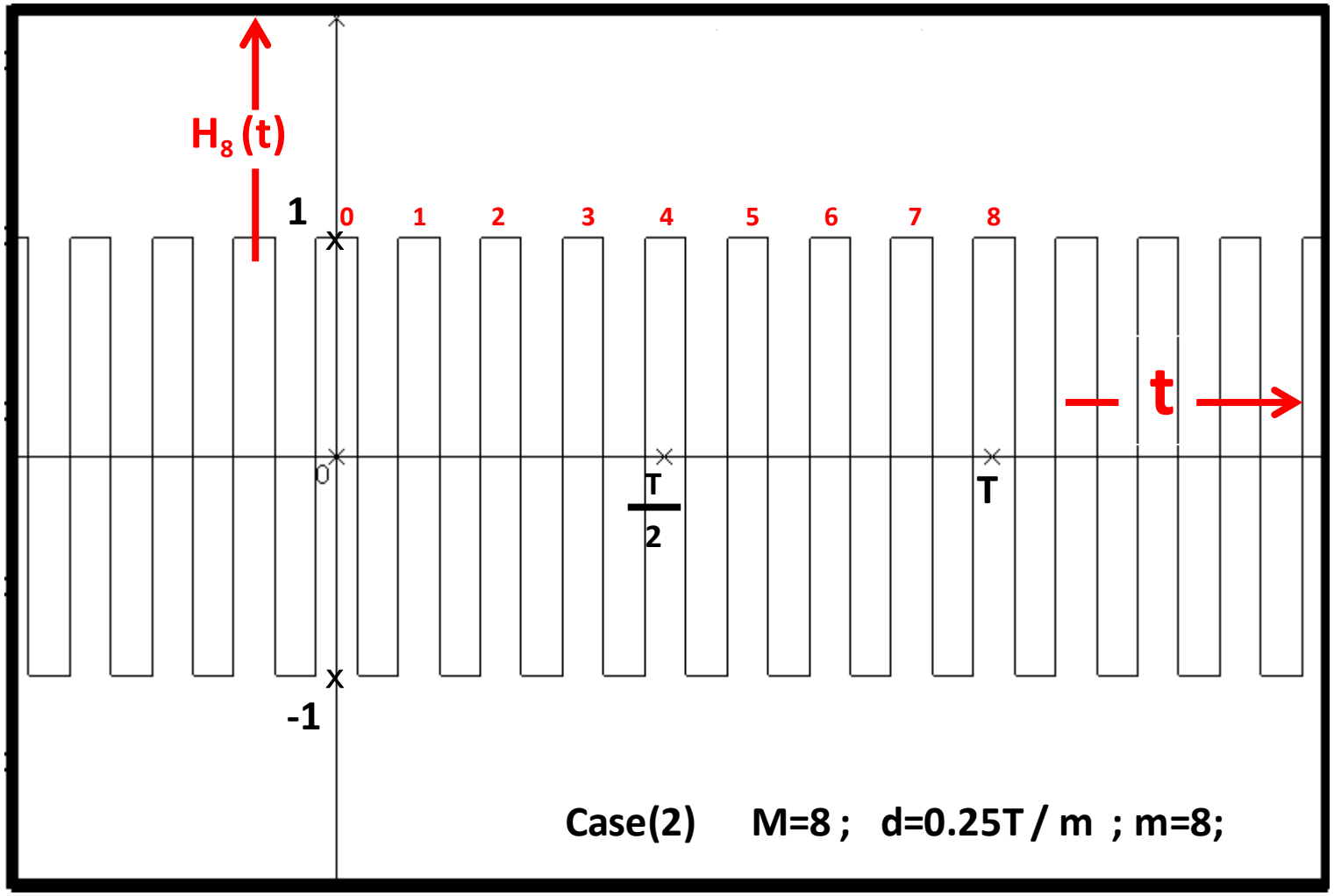
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

H_m (t) function ; m = 8;

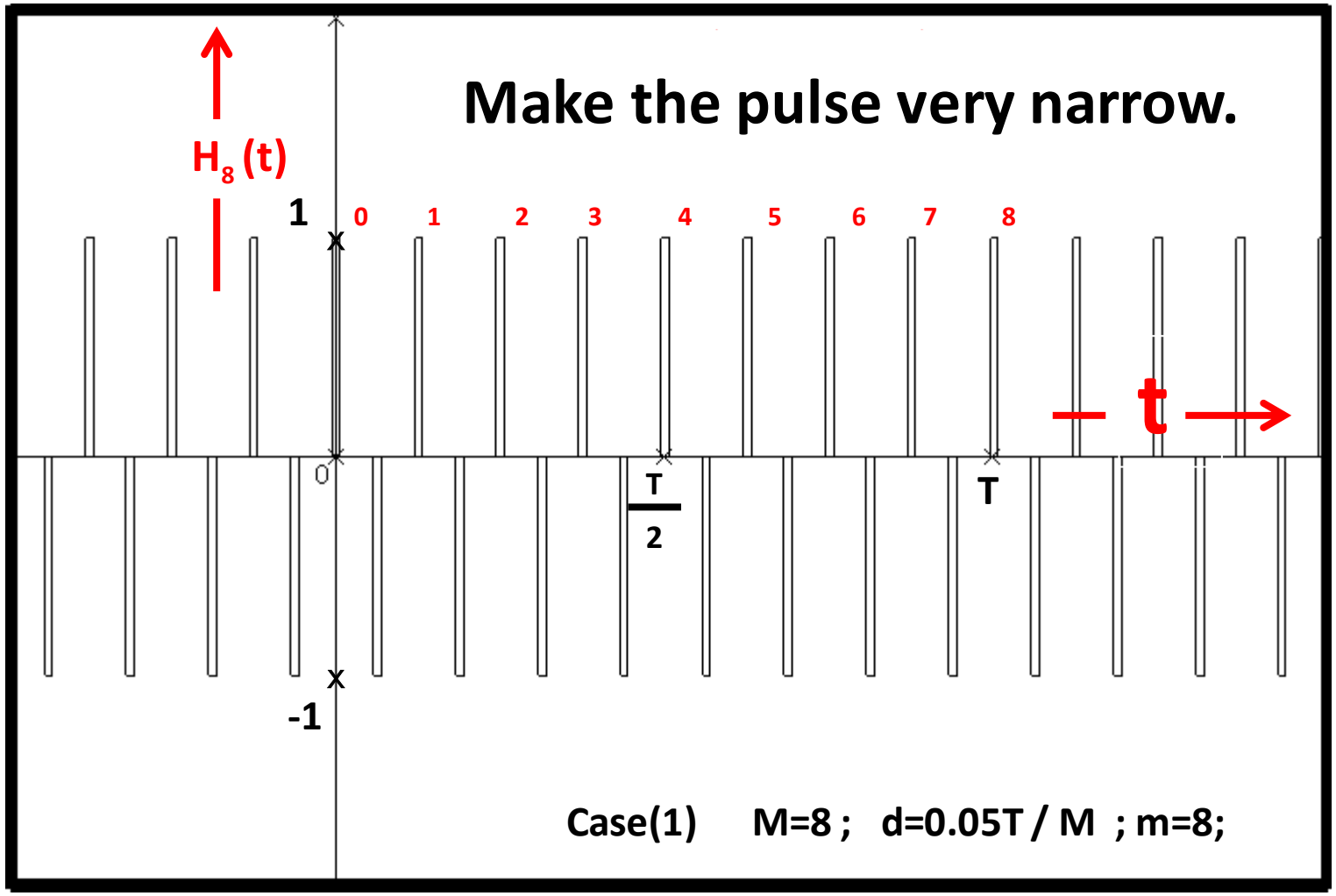
for N = 8 points



Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Define $H_m(t)$ function ; m = 8;

for N = 8 points

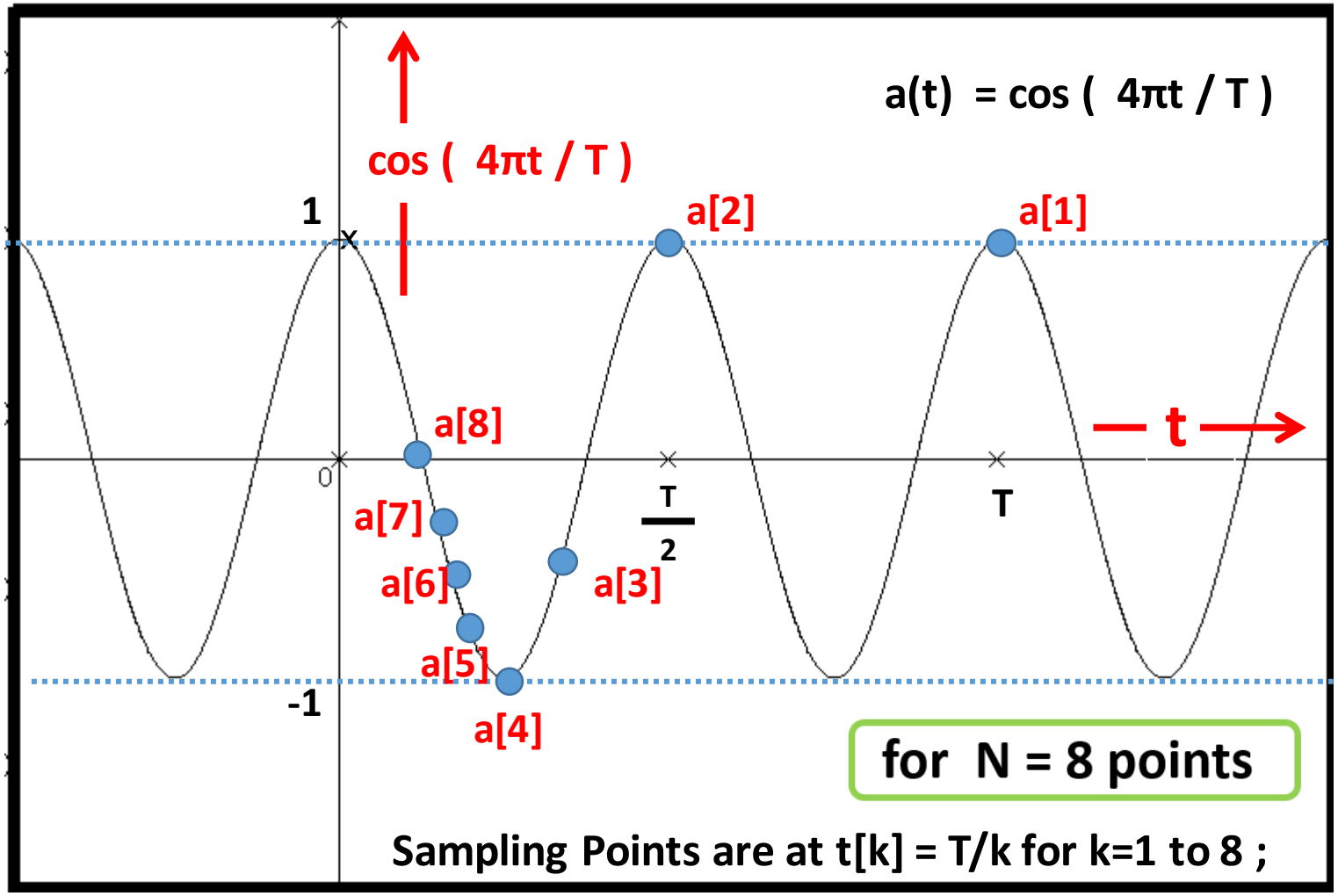


Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Step(1) Define $H_m(t)$ functions
Step(2) Define H[m][k]

a[1]= 1
a[2]= 1
a[3]= - 0.5
a[4]= - 1
a[5]= - 0.809
a[6]= - 0.5
a[7]= - 0.223
a[8]= 0

A[1]= 1.032
A[2]= 1.5
A[3]= 0
A[4]= 0
A[5]= - 0.809
A[6]= - 0.5
A[7]= - 0.223
A[8]= 0



Compute $A[m] = \sum_{k=1}^{8} (1/8)\, H[m][k]\, a[k]$; Then we have $a(t) = \sum_{m=1}^{8} A[m]\, H_k(t)$;

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

We only need the bit shifter circuits for the matrix calculations.

$$a[\ ] = H[\ ][\ ]A[\ ]; \quad \text{for } N = 1;$$

$$a[1] = [1]\,A[1]$$

$$A[\ ] = H^{-1}[\ ][\ ]\,a[\ ];$$

$$A[1] = (1/1)\,[1]\,a[1]$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

We only need the bit shifter circuits for the matrix calculations.

$$a[\ ] = H[\ ][\ ]A[\ ]; \quad \text{for } N = 2;$$

$$\begin{vmatrix} a[1] \\ a[2] \end{vmatrix} = \begin{vmatrix} 1 & 1 \\ -1 & 1 \end{vmatrix} \begin{vmatrix} A[1] \\ A[2] \end{vmatrix}$$

$$A[\ ] = H^{-1}[\ ][\ ]\, a[\ ];$$

$$\begin{vmatrix} A[1] \\ A[2] \end{vmatrix} = (1/2) \begin{vmatrix} 1 & -1 \\ 1 & 1 \end{vmatrix} \begin{vmatrix} a[1] \\ a[2] \end{vmatrix}$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

We only need the bit shifter circuits for the matrix calculations.

$$a[\ ] = H[\ ][\ ]A[\ ]; \quad \text{for } N = 3;$$

$$\begin{vmatrix} a[1] \\ a[2] \\ a[3] \end{vmatrix} = \begin{vmatrix} 1 & 1 & 1 \\ -1 & 1 & -1 \\ 0 & 0 & 1 \end{vmatrix} \begin{vmatrix} A[1] \\ A[2] \\ A[3] \end{vmatrix}$$

$$A[\ ] = H^{-1}[\ ][\ ]\, a[\ ];$$

$$\begin{vmatrix} A[1] \\ A[2] \\ A[3] \end{vmatrix} = (1/2) \begin{vmatrix} 1 & -1 & -2 \\ 1 & 1 & 0 \\ 0 & 0 & 2 \end{vmatrix} \begin{vmatrix} a[1] \\ a[2] \\ a[3] \end{vmatrix}$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

We only need the bit shifter circuits for the matrix calculations.

$$a[\ ] = H[\ ][\ ]A[\ ]; \quad \text{for } N = 4;$$

$$\begin{vmatrix} a[1] \\ a[2] \\ a[3] \\ a[4] \end{vmatrix} = \begin{vmatrix} 1 & 1 & 1 & 1 \\ -1 & 1 & -1 & -1 \\ 0 & 0 & 1 & 0 \\ 0 & -1 & 0 & 1 \end{vmatrix} \begin{vmatrix} A[1] \\ A[2] \\ A[3] \\ A[4] \end{vmatrix}$$

$$A[\ ] = H^{-1}[\ ][\ ]\, a[\ ];$$

$$\begin{vmatrix} A[1] \\ A[2] \\ A[3] \\ A[4] \end{vmatrix} = (1/4) \begin{vmatrix} 2 & -2 & -4 & 0 \\ 1 & 1 & 0 & -2 \\ 0 & 0 & 4 & 0 \\ 1 & 1 & 0 & 2 \end{vmatrix} \begin{vmatrix} a[1] \\ a[2] \\ a[3] \\ a[4] \end{vmatrix}$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

We only need the bit shifter circuits for the matrix calculations.

$$a[\ ] = H[\ ][\ ]A[\ ]; \quad \text{for } N = 5;$$

$$\begin{vmatrix} a[1] \\ a[2] \\ a[3] \\ a[4] \\ a[5] \end{vmatrix} = \begin{vmatrix} 1 & 1 & 1 & 1 & 1 \\ -1 & 1 & -1 & 1 & -1 \\ 0 & 0 & 1 & 0 & 0 \\ 0 & -1 & 0 & 1 & 0 \\ 0 & 0 & 0 & 0 & 1 \end{vmatrix} \begin{vmatrix} A[1] \\ A[2] \\ A[3] \\ A[4] \\ A[5] \end{vmatrix}$$

$$A[\ ] = H^{-1}[\ ][\ ]\, a[\ ];$$

$$\begin{vmatrix} A[1] \\ A[2] \\ A[3] \\ A[4] \\ A[5] \end{vmatrix} = (1/4) \begin{vmatrix} 2 & -2 & -4 & 0 & -4 \\ 1 & 1 & 0 & -2 & 0 \\ 0 & 0 & 4 & 0 & 0 \\ 1 & 1 & 0 & 2 & 0 \\ 0 & 0 & 0 & 0 & 4 \end{vmatrix} \begin{vmatrix} a[1] \\ a[2] \\ a[3] \\ a[4] \\ a[5] \end{vmatrix}$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

We only need the bit shifter circuits for the matrix calculations.

$$a[\ ] = H[\ ][\ ]A[\ ]; \quad \text{for } N = 6;$$

$$\begin{vmatrix} a[1] \\ a[2] \\ a[3] \\ a[4] \\ a[5] \\ a[6] \end{vmatrix} = \begin{vmatrix} 1 & 1 & 1 & 1 & 1 & 1 \\ -1 & 1 & -1 & 1 & -1 & 1 \\ 0 & 0 & 1 & 0 & 0 & 1 \\ 0 & -1 & 0 & 1 & 0 & -1 \\ 0 & 0 & 0 & 0 & 1 & 0 \\ 0 & 0 & -1 & 0 & 0 & 1 \end{vmatrix} \begin{vmatrix} A[1] \\ A[2] \\ A[3] \\ A[4] \\ A[5] \\ A[6] \end{vmatrix}$$

$$A[\ ] = H^{-1}[\ ][\ ]\, a[\ ];$$

$$\begin{vmatrix} A[1] \\ A[2] \\ A[3] \\ A[4] \\ A[5] \\ A[6] \end{vmatrix} = (1/4) \begin{vmatrix} 2 & -2 & -2 & 0 & -4 & 2 \\ 1 & 1 & -2 & -2 & 0 & -2 \\ 0 & 0 & 2 & 0 & 0 & -2 \\ 1 & 1 & 0 & 2 & 0 & 0 \\ 0 & 0 & 0 & 0 & 4 & 0 \\ 0 & 0 & 2 & 0 & 0 & 2 \end{vmatrix} \begin{vmatrix} a[1] \\ a[2] \\ a[3] \\ a[4] \\ a[5] \\ a[6] \end{vmatrix}$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

We only need the bit shifter circuits for the matrix calculations.

$$a[\ ] = H[\ ][\ ]A[\ ]; \quad \text{for } N = 7;$$

$$\begin{vmatrix} a[1] \\ a[2] \\ a[3] \\ a[4] \\ a[5] \\ a[6] \\ a[7] \end{vmatrix} = \begin{vmatrix} 1 & 1 & 1 & 1 & 1 & 1 & 1 \\ -1 & 1 & -1 & 1 & -1 & 1 & -1 \\ 0 & 0 & 1 & 0 & 0 & 1 & 0 \\ 0 & -1 & 0 & 1 & 0 & -1 & 0 \\ 0 & 0 & 0 & 0 & 1 & 0 & 0 \\ 0 & 0 & -1 & 0 & 0 & 1 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 1 \end{vmatrix} \begin{vmatrix} A[1] \\ A[2] \\ A[3] \\ A[4] \\ A[5] \\ A[6] \\ A[7] \end{vmatrix}$$

$$A[\ ] = H^{-1}[\ ][\ ]\, a[\ ];$$

$$\begin{vmatrix} A[1] \\ A[2] \\ A[3] \\ A[4] \\ A[5] \\ A[6] \\ A[7] \end{vmatrix} = (1/4) \begin{vmatrix} 2 & -2 & -2 & 0 & -4 & 2 & -4 \\ 1 & 1 & -2 & -2 & 0 & -2 & 0 \\ 0 & 0 & 2 & 0 & 0 & -2 & 0 \\ 1 & 1 & 0 & 2 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 4 & 0 & 0 \\ 0 & 0 & 2 & 0 & 0 & 2 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 4 \end{vmatrix} \begin{vmatrix} a[1] \\ a[2] \\ a[3] \\ a[4] \\ a[5] \\ a[6] \\ a[7] \end{vmatrix}$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

We only need the bit shifter circuits for the matrix calculations.

$$a[\ ] = H[\ ][\ ]A[\ ]; \quad \text{for } N = 8;$$

$$\begin{vmatrix} a[1] \\ a[2] \\ a[3] \\ a[4] \\ a[5] \\ a[6] \\ a[7] \\ a[8] \end{vmatrix} = \begin{vmatrix} 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 \\ -1 & 1 & -1 & 1 & -1 & 1 & -1 & 1 \\ 0 & 0 & 1 & 0 & 0 & 1 & 0 & 0 \\ 0 & -1 & 0 & 1 & 0 & -1 & 0 & 1 \\ 0 & 0 & 0 & 0 & 1 & 0 & 0 & 0 \\ 0 & 0 & -1 & 0 & 0 & 1 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 1 & 0 \\ 0 & 0 & 0 & -1 & 0 & 0 & 0 & 1 \end{vmatrix} \begin{vmatrix} A[1] \\ A[2] \\ A[3] \\ A[4] \\ A[5] \\ A[6] \\ A[7] \\ A[8] \end{vmatrix}$$

$$A[\ ] = H^{-1}[\ ][\ ]\, a[\ ];$$

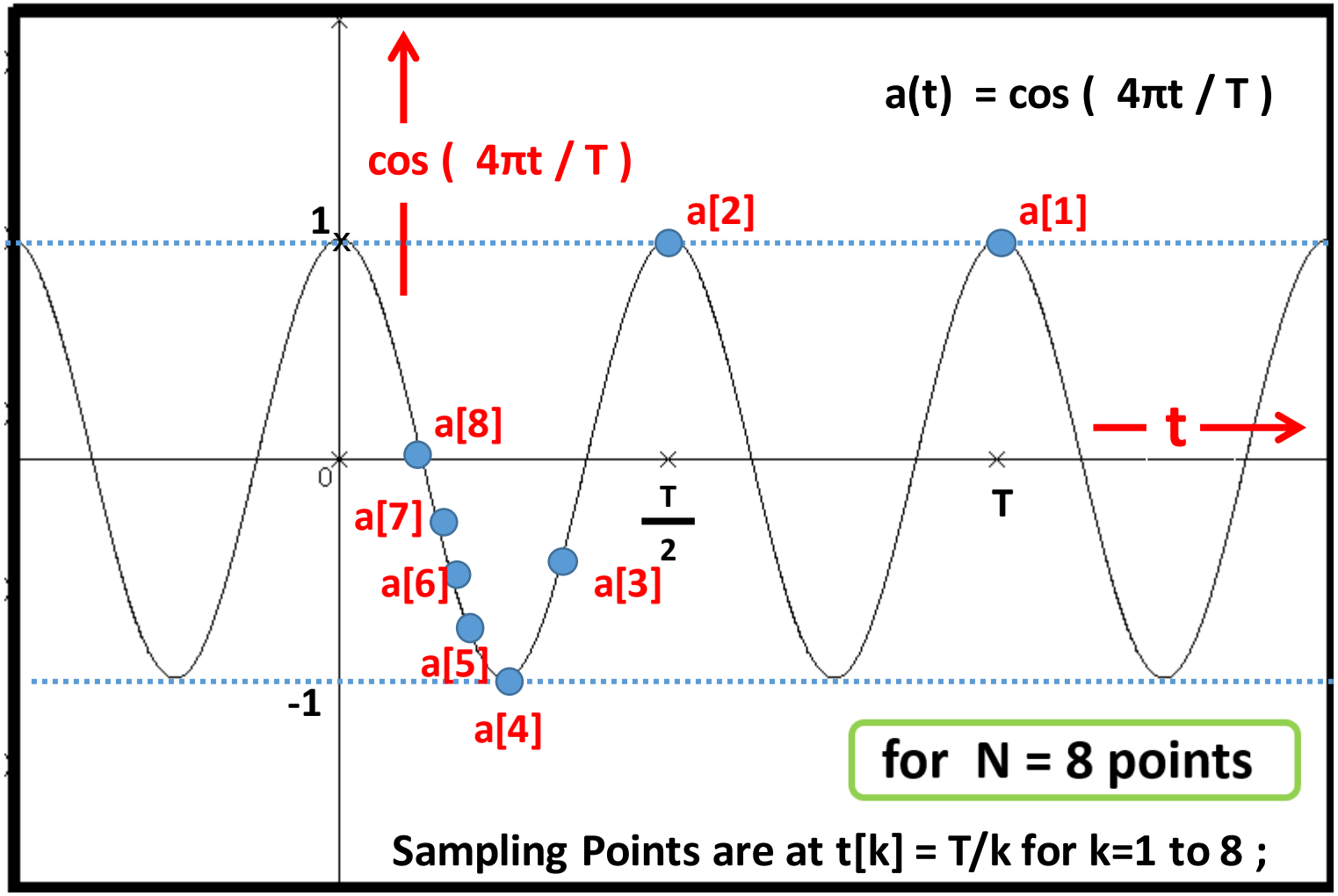
$$\begin{vmatrix} A[1] \\ A[2] \\ A[3] \\ A\ 4] \\ A[5] \\ A[6] \\ A[7] \\ A[8] \end{vmatrix} = (1/8) \begin{vmatrix} 4 & -4 & -4 & 0 & -8 & 4 & -8 & 0 \\ 2 & 2 & -4 & -4 & 0 & -4 & 0 & 0 \\ 0 & 0 & 4 & 0 & 0 & -4 & 0 & 0 \\ 1 & 1 & 0 & 2 & 0 & 0 & 0 & -4 \\ 0 & 0 & 0 & 0 & 8 & 0 & 0 & 0 \\ 0 & 0 & 4 & 0 & 0 & 4 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 8 & 0 \\ 1 & 1 & 0 & 2 & 0 & 0 & 0 & 4 \end{vmatrix} \begin{vmatrix} a[1] \\ a[2] \\ a[3] \\ a[4] \\ a[5] \\ a[6] \\ a[7] \\ a[8] \end{vmatrix}$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Step(1) Define $H_m(t)$ functions
Step(2) Define H[m][k]
Step(3) Obtain a[m]
Step(4) Obtain A[m]

a[1]= 1
a[2]= 1
a[3]= - 0.5
a[4]= - 1
a[5]= - 0.809
a[6]= - 0.5
a[7]= - 0.223
a[8]= 0

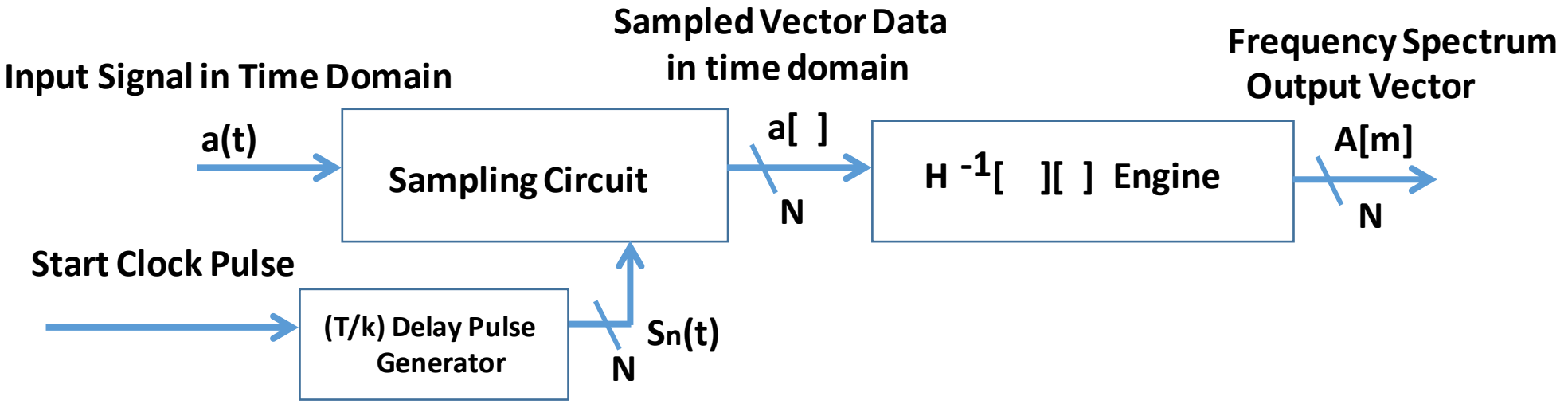
A[1]= 1.032
A[2]= 1.5
A[3]= 0
A[4]= 0
A[5]= - 0.809
A[6]= - 0.5
A[7]= - 0.223
A[8]= 0



Compute $A[m] = \sum_{k=1}^{8} (1/8)\, H[m][k]\, a[k]$; Then we have $a(t) = \sum_{m=1}^{8} A[m]\, H_m(t)$;

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Block Diagram of (T/k) Delay Pulse Generator

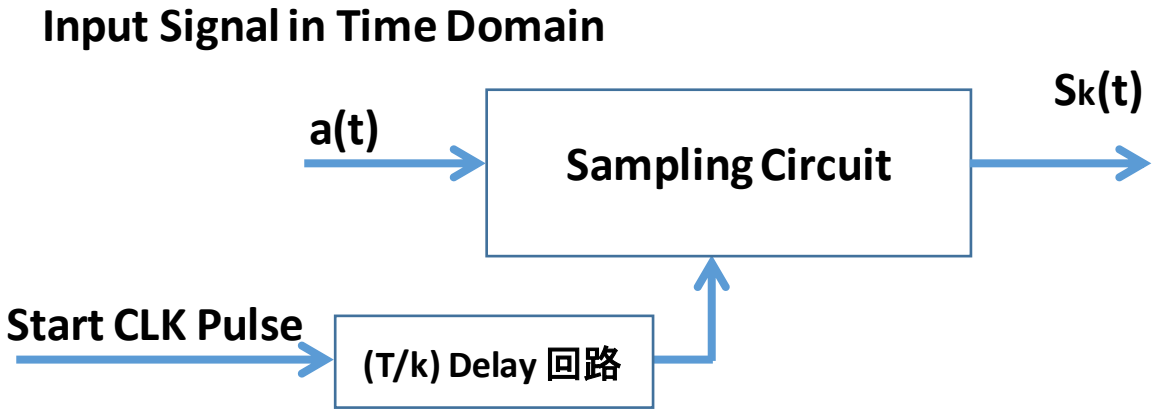


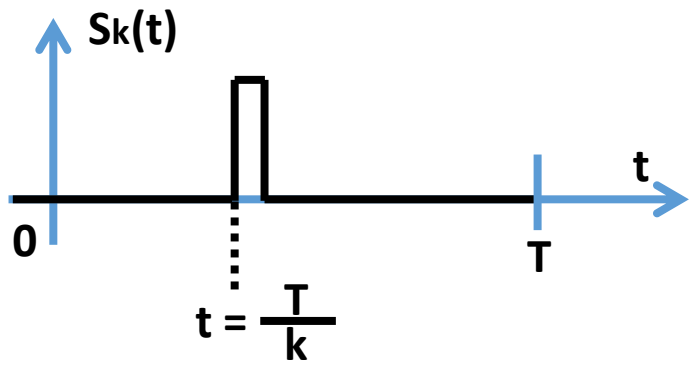
$$a[\ ] = H[\ ][\ ]A[\ ];$$

$$A[\ ] = H^{-1}[\ ][\ ]\, a[\ ];$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Block Diagram of (T/k) Delay Pulse Generator



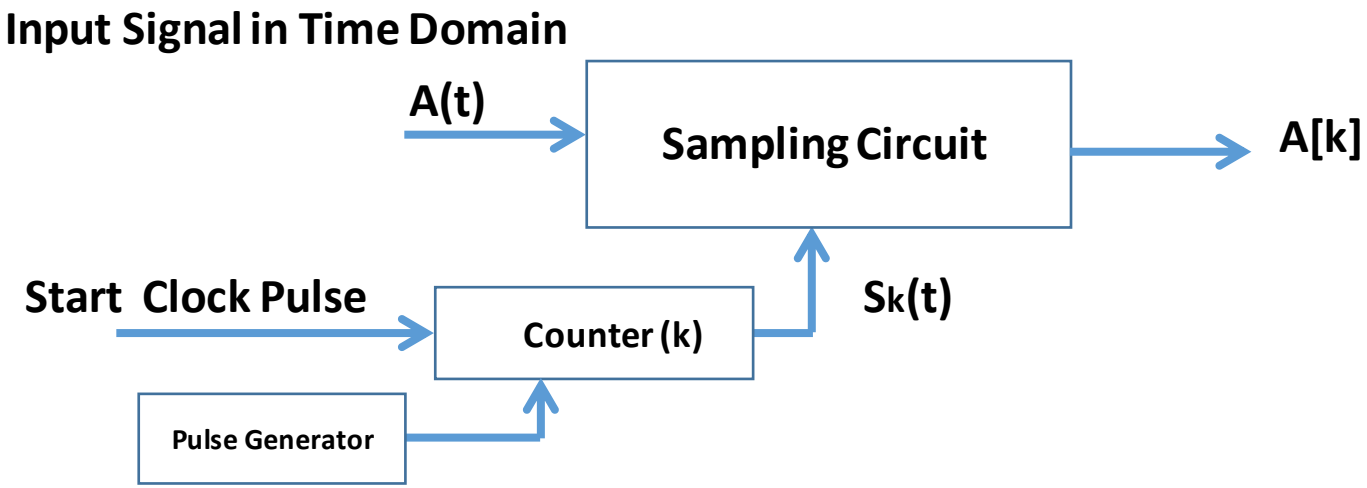


$$a[\ ] = H[\ ][\ ]A[\ ];$$

$$A[\ ] = H^{-1}[\ ][\ ]\,a[\ ];$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Block Diagram of (T/k) Delay Pulse Generator

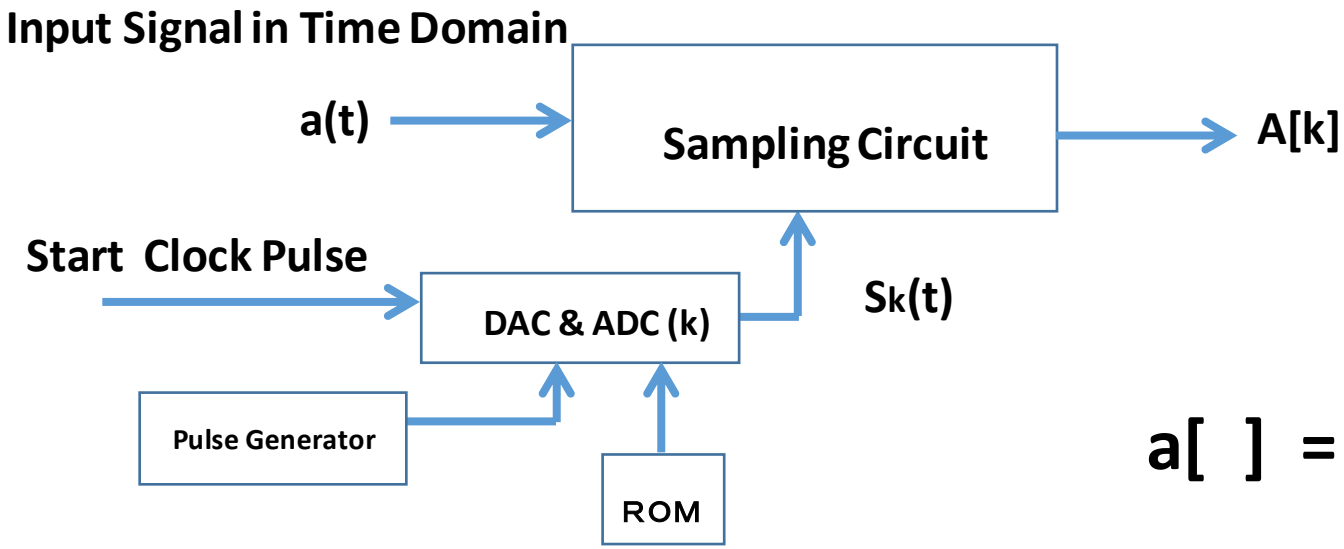


$$a[\ ] = H[\ ][\ ]A[\ ];$$

$$A[\ ] = H^{-1}[\ ][\ ]\,a[\ ];$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Block Diagram of (T/k) Delay Pulse Generator

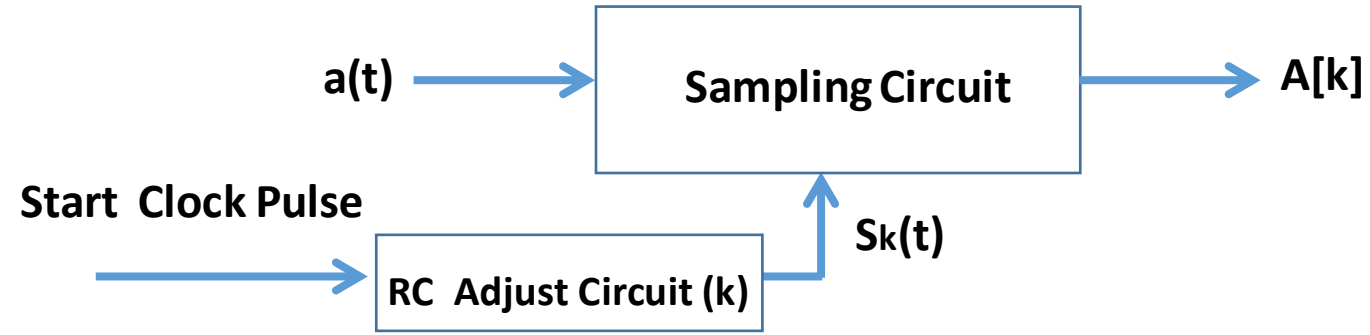


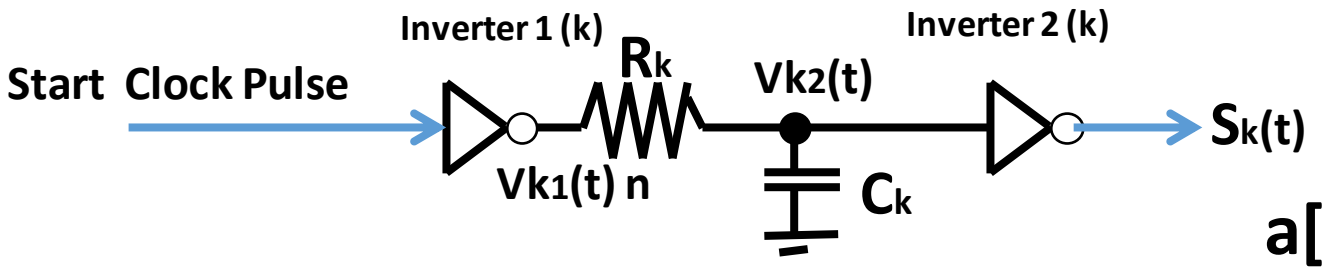
$$a[\ ] = H[\ ][\ ]A[\ ];$$

$$A[\ ] = H^{-1}[\ ][\ ]\, a[\ ];$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Block Diagram of (T/k) Delay Pulse Generator





$$a[\ ] = H[\ ][\ ]A[\ ];$$

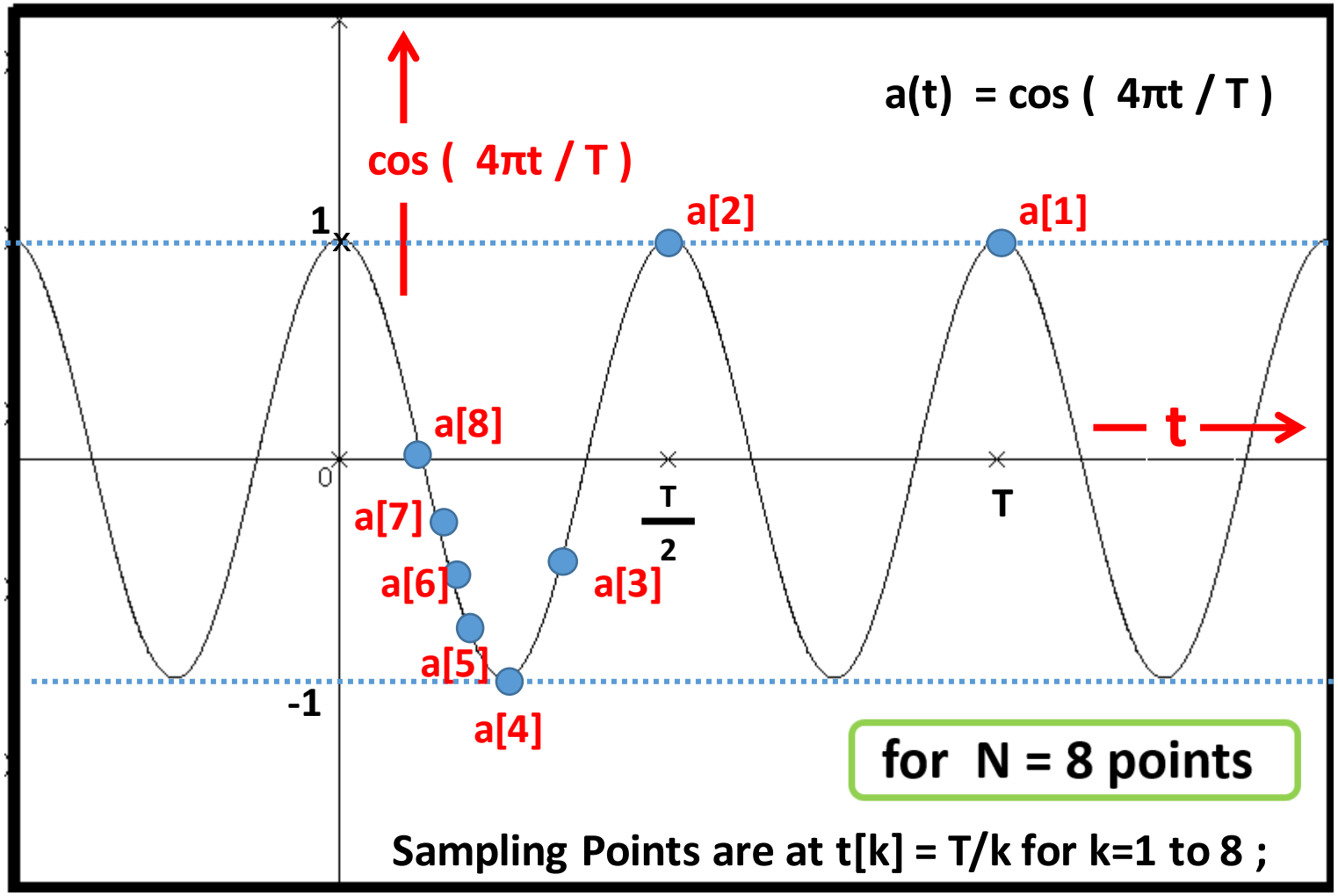
$$A[\ ] = H^{-1}[\ ][\ ]\, a[\ ];$$

Nonuniform T/k Sampling Scheme with Fast H [ ][ ] Transformation Matrix

Step(1) Define $H_m(t)$ functions
Step(2) Define H[m][k]
Step(3) Obtain a[m]
Step(4) Obtain A[m]

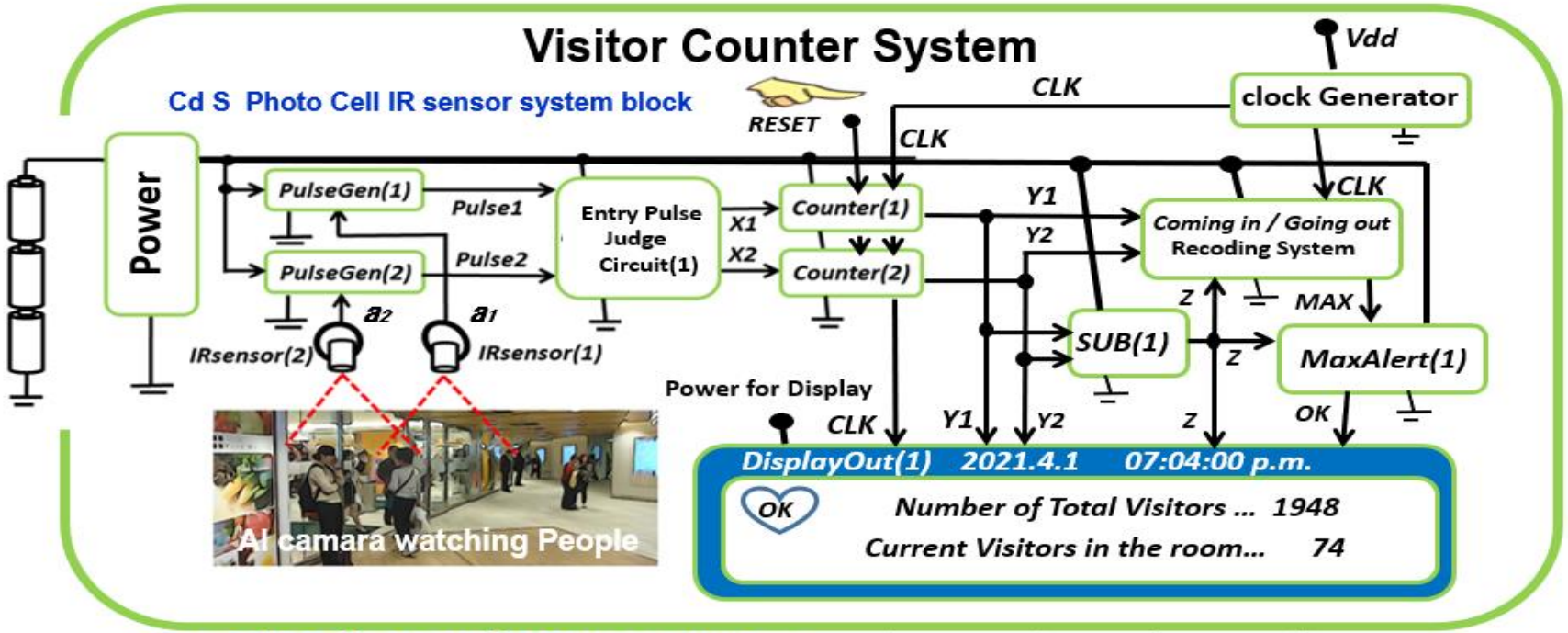
a[1]= 1
a[2]= 1
a[3]= - 0.5
a[4]= - 1
a[5]= - 0.809
a[6]= - 0.5
a[7]= - 0.223
a[8]= 0

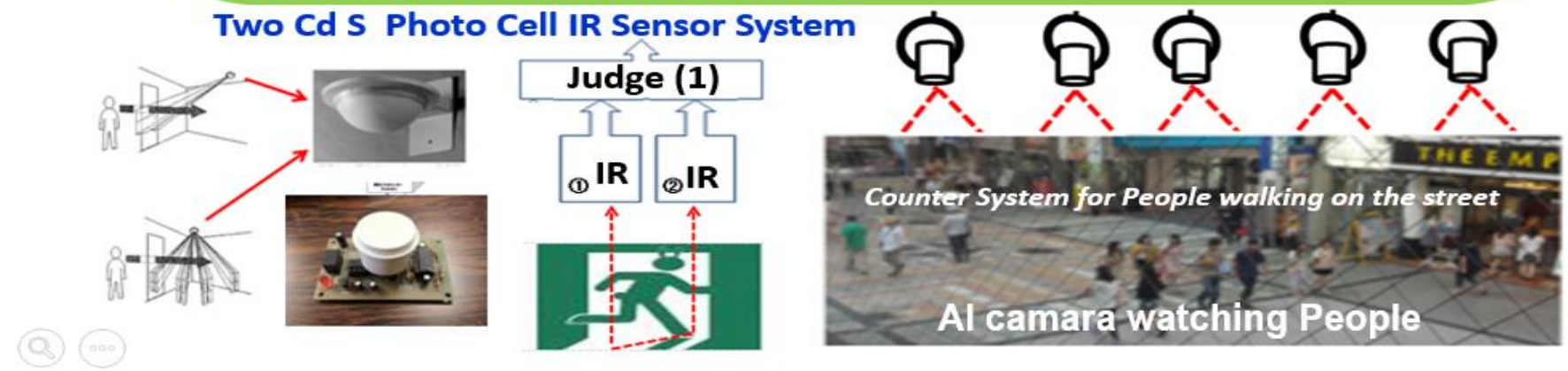
A[1]= 1.032
A[2]= 1.5
A[3]= 0
A[4]= 0
A[5]= - 0.809
A[6]= - 0.5
A[7]= - 0.223
A[8]= 0



Compute $A[m] = \sum_{k=1}^{8} (1/8)\, H[m][k]\, a[k]$; Then we have $a(t) = \sum_{m=1}^{8} A[m]\, H_m(t)$;

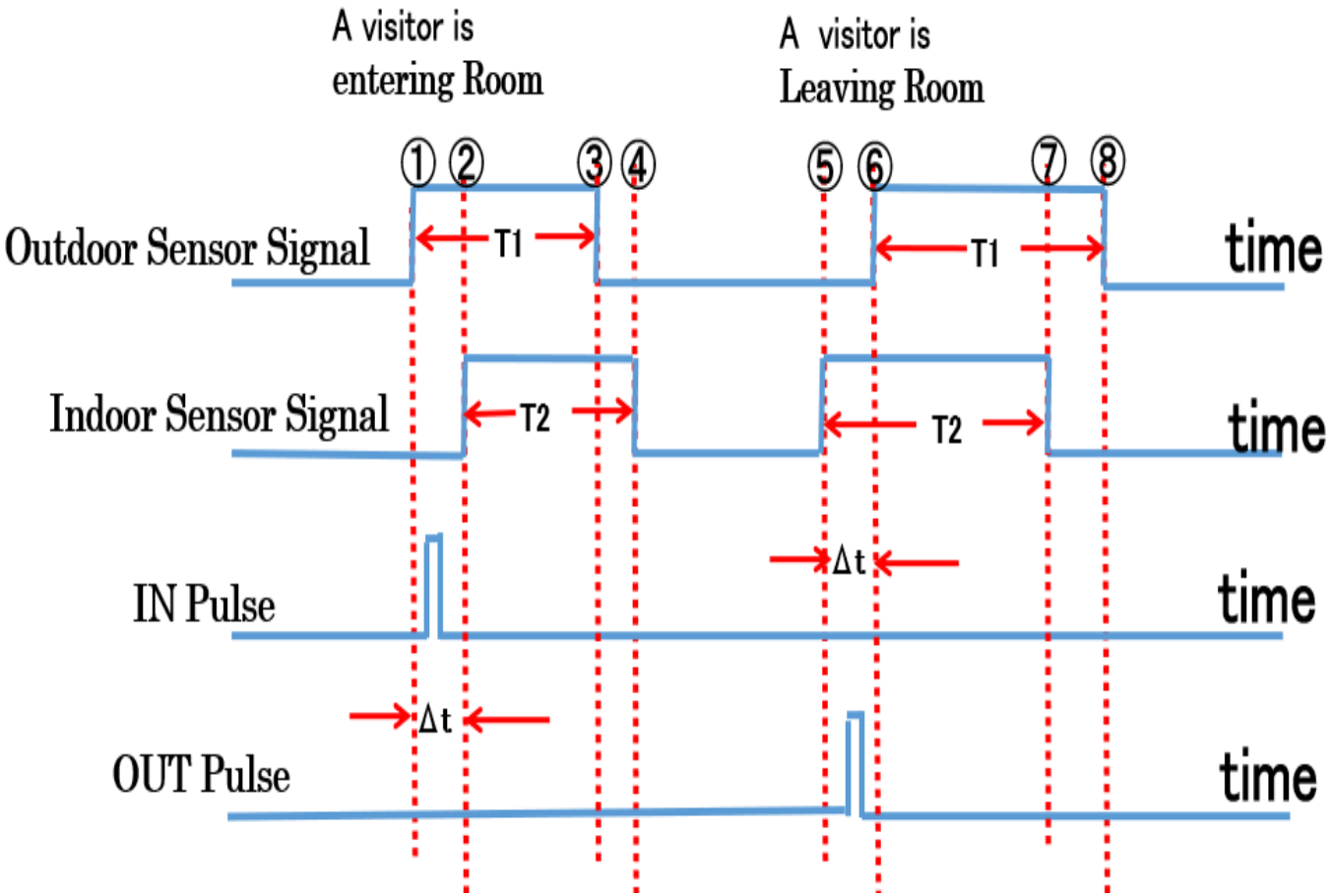
9 Artificial Intelligent Image Sensor

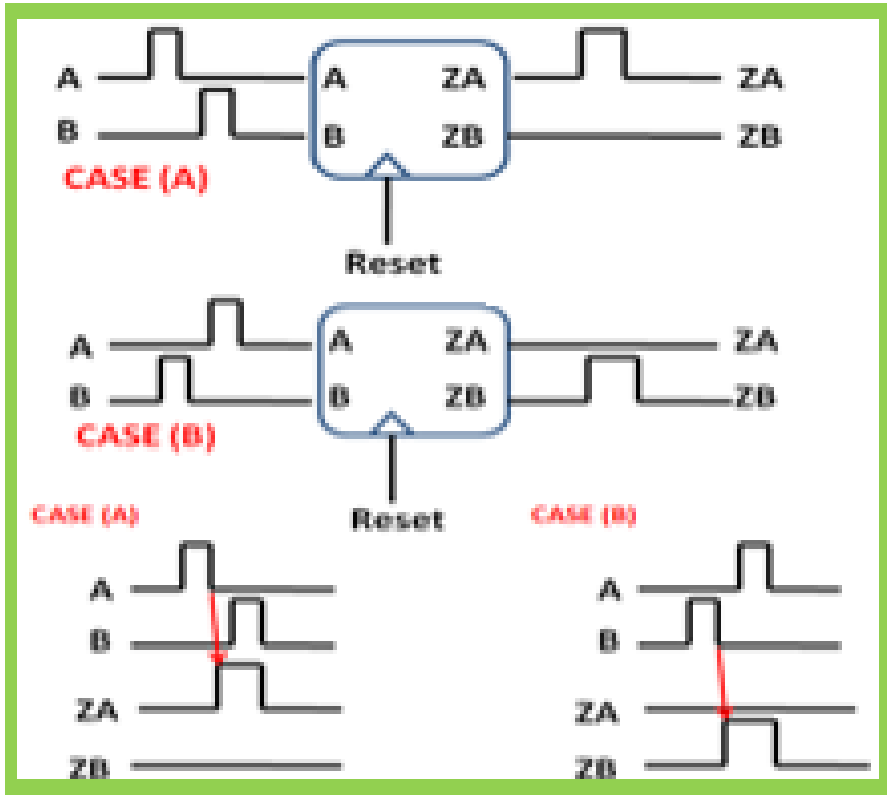




9 Artificial Intelligent Image Sensor

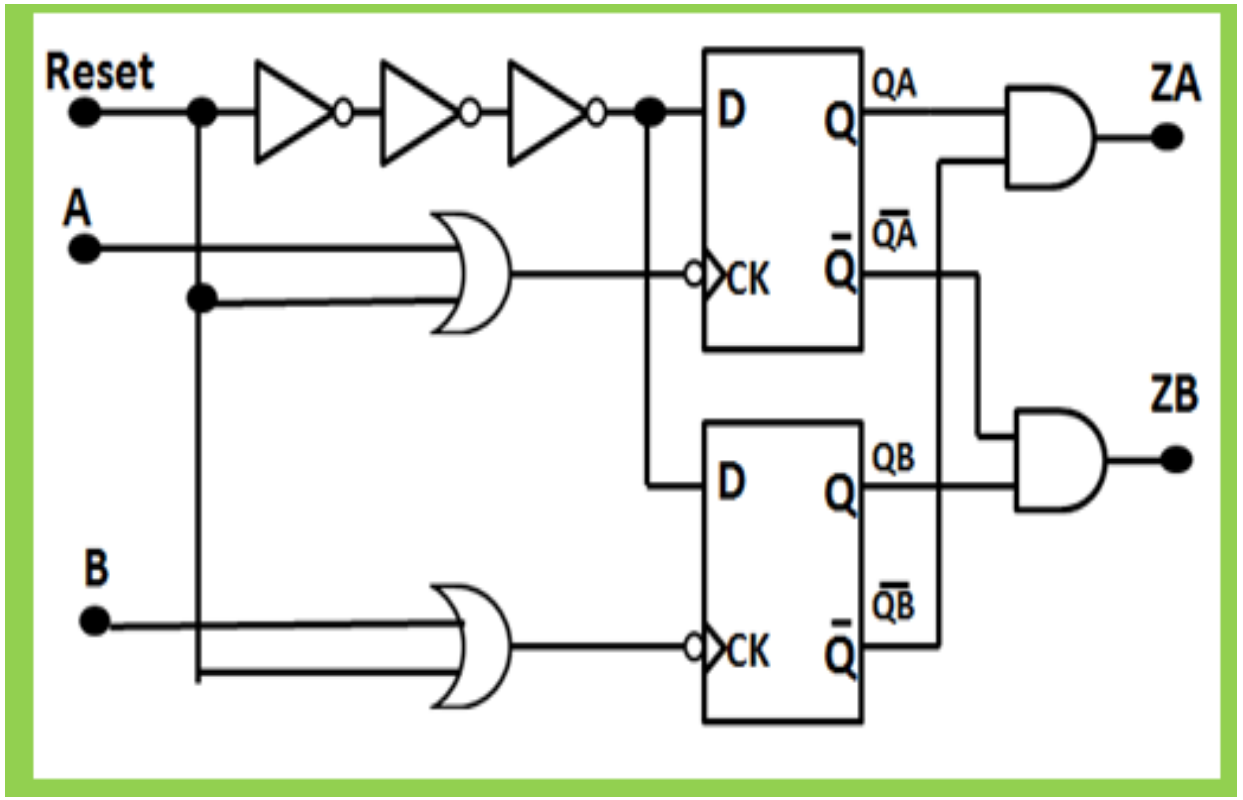
Digital Circuit Design for Visitor Counter System

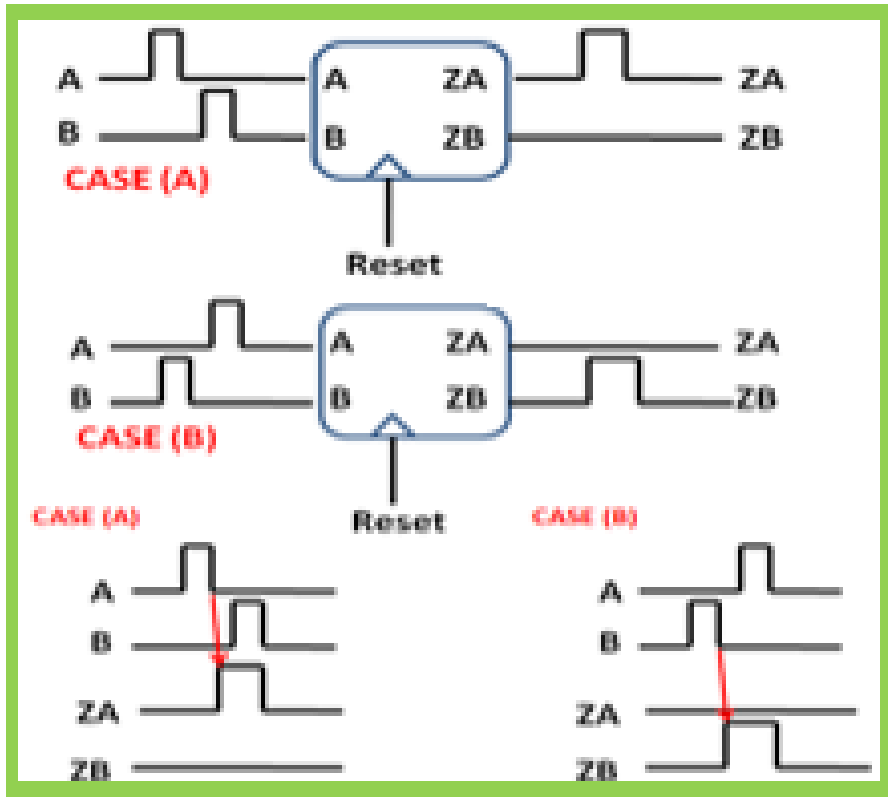




9 Artificial Intelligent Image Sensor

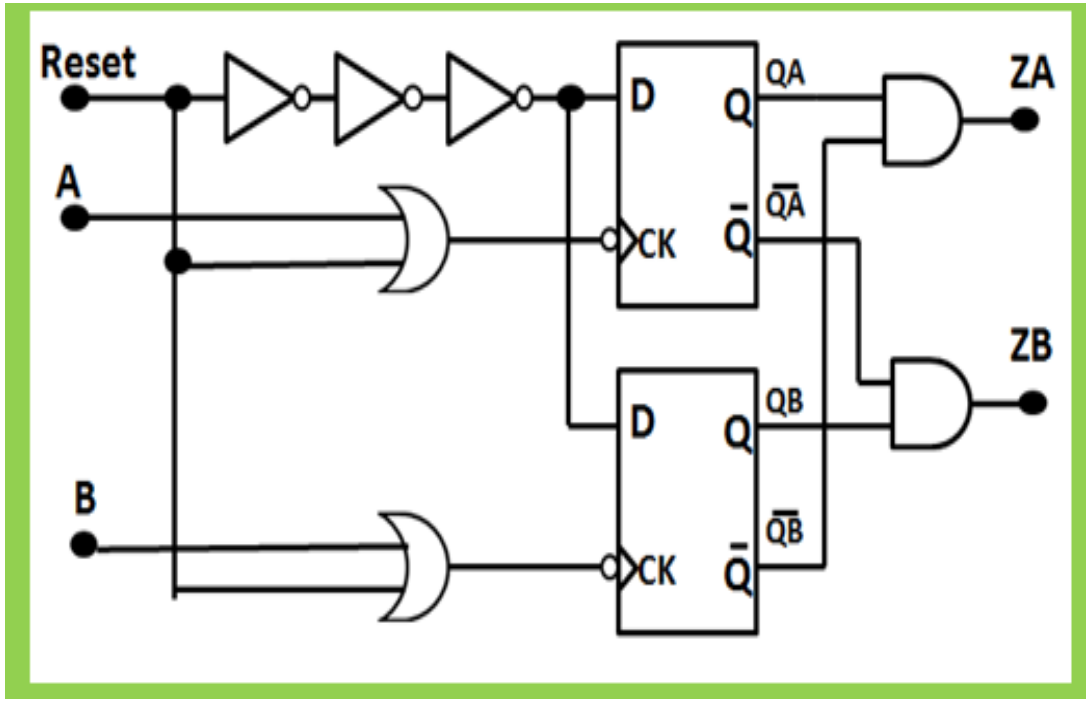
Digital Circuit Design for Visitor Counter System

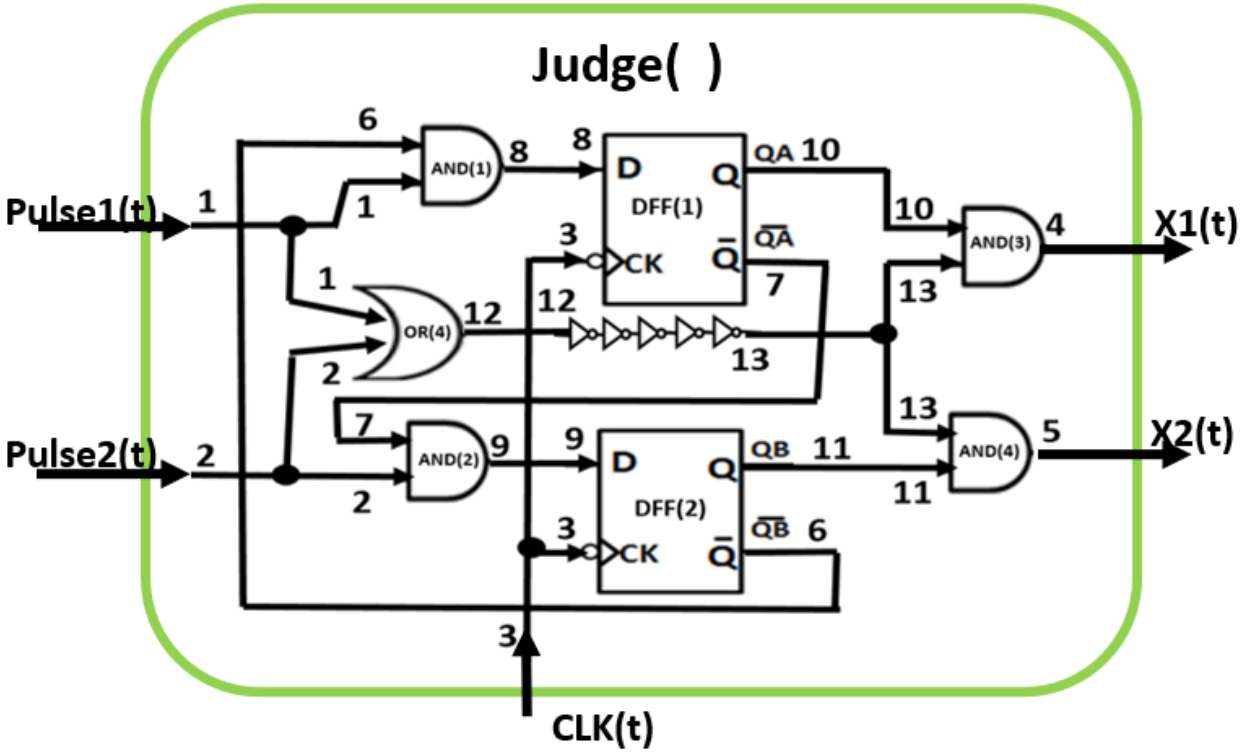




9 Artificial Intelligent Image Sensor

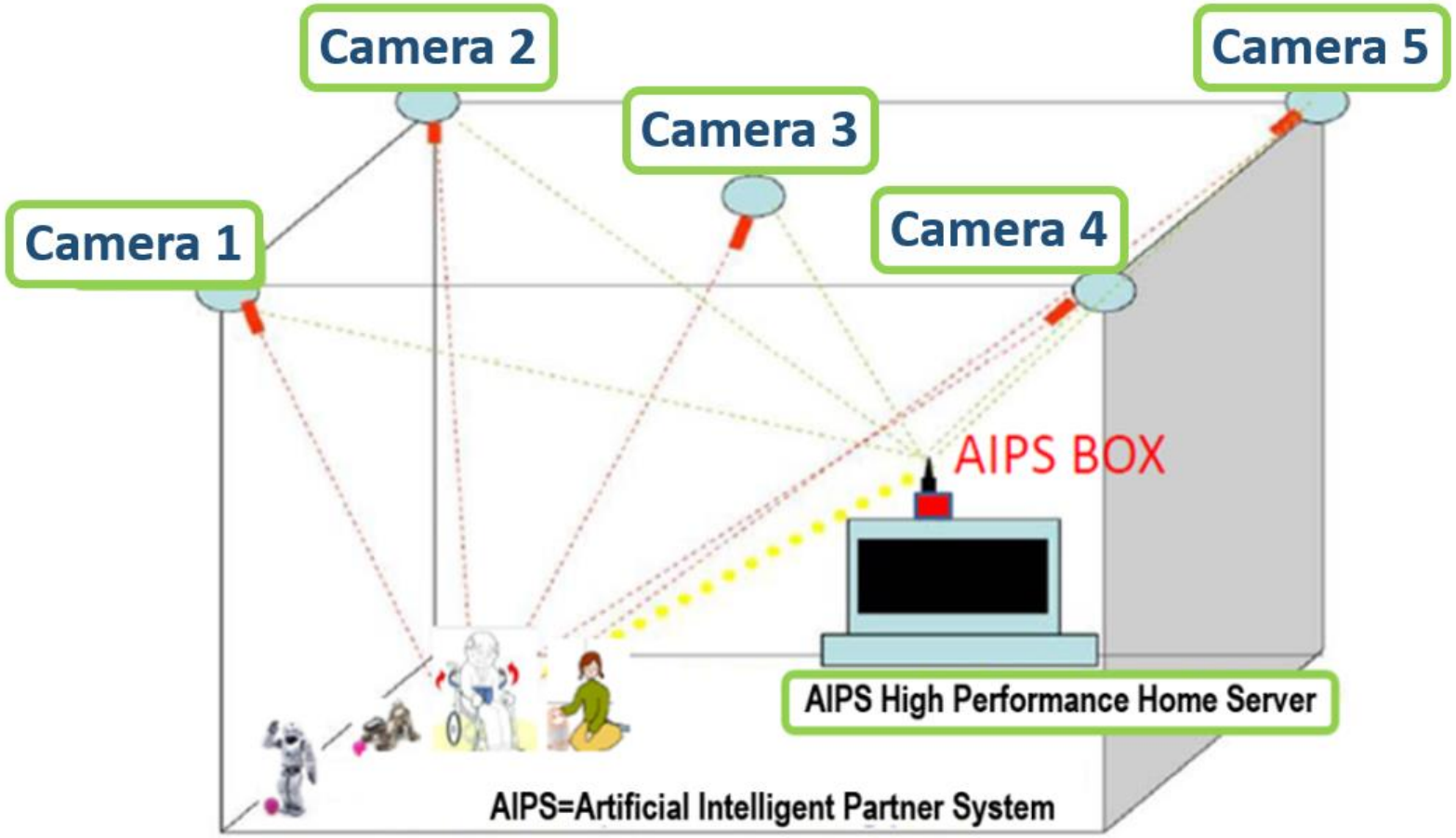
Digital Circuit Design for Visitor Counter System



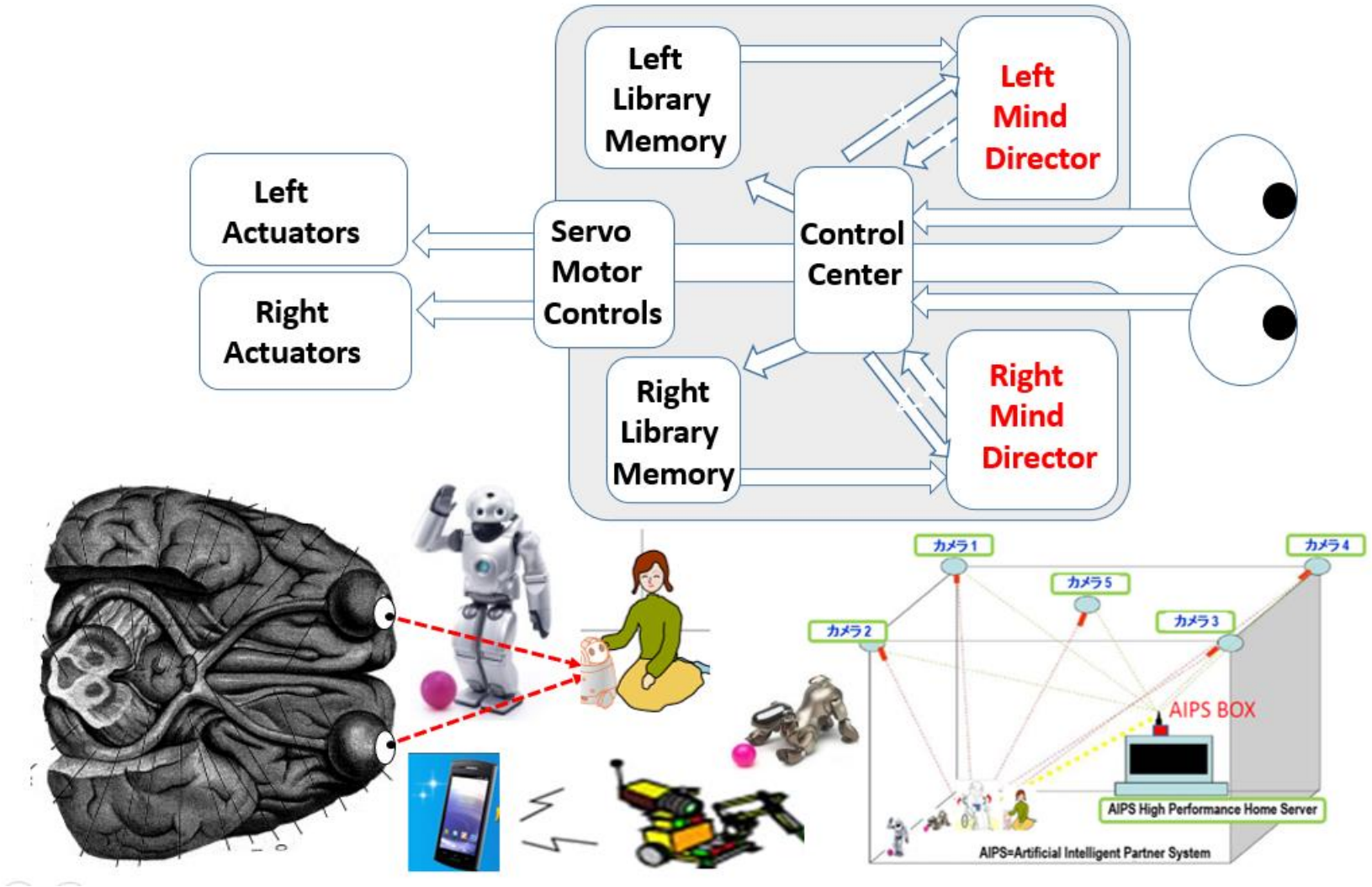


9 Artificial Intelligent Image Sensor

Digital Circuit Design for Home Care System



9 Artificial Intelligent Image Sensor



9 Artificial Intelligent Image Sensor

Artificial Intelligent Image Sensors use many dedicated real time hardware engines. To direct an image sensor pin-pointed to the right object quickly, a servomotor controlled digital feedback system is desired and being built with many tools including high performance CMOS digital circuits and clever software designs.

AIBO Model ERS-210

AIBO Model SDR-3